

## Product Preview

AFE8406

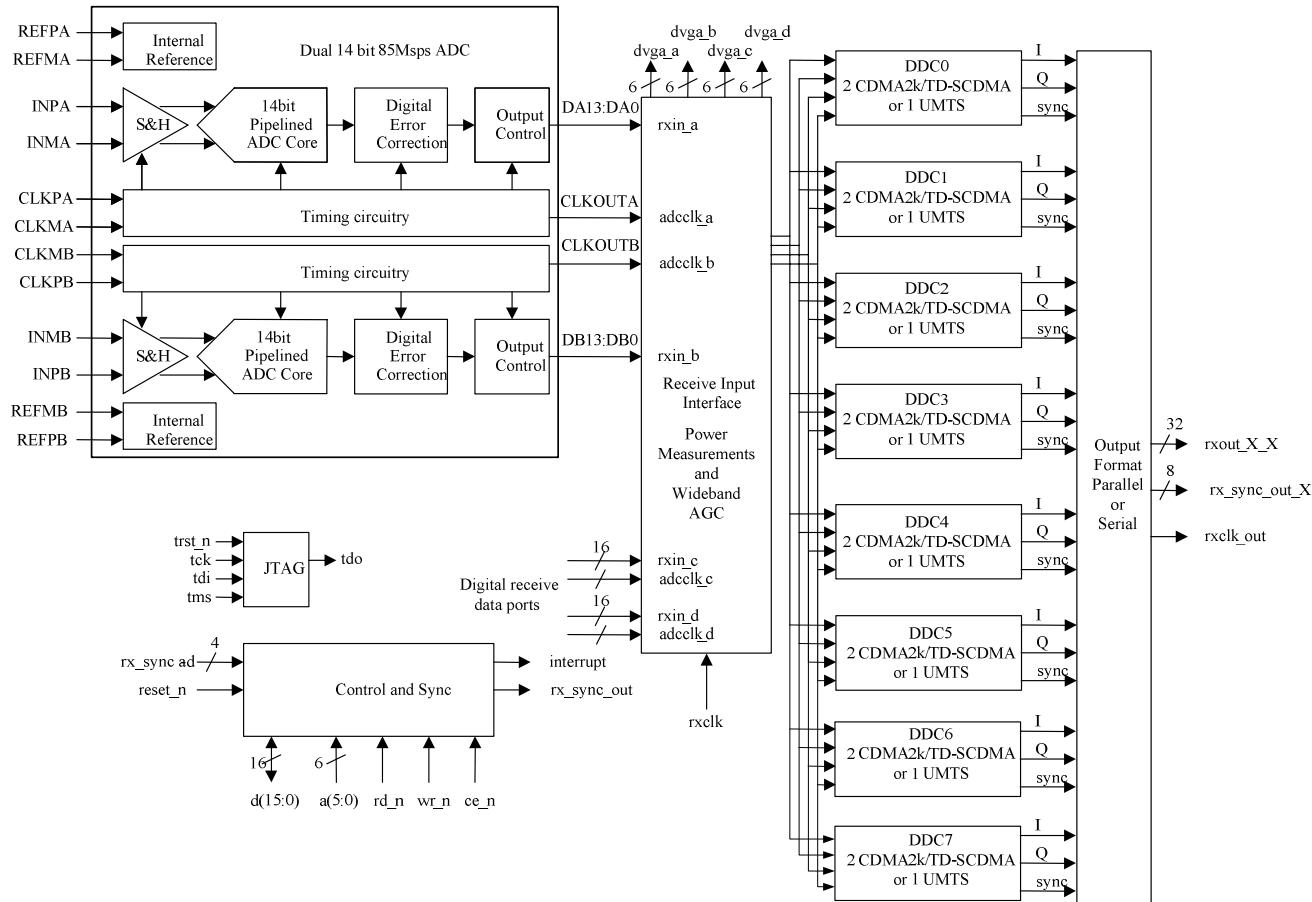
## FEATURES

- 14-bit 85 MSPS high performance dual ADC
- The dual ADC can be configured into single ADC
- At  $F_{in}=140\text{MHz}$ ,  $\text{SNR}>=68\text{dB}$ ,  $\text{SFDR}>=70\text{dBc}$
- At  $F_{in} = 70\text{MHz}$ ,  $\text{SNR}>=70\text{dB}$ ,  $\text{SFDR}>=82\text{dBc}$
- Independent clocks for ADC and DDC with build-in FIFO
- Programmable closed loop VGA control with 6-bit outputs for each ADC
- Provide Received Total Wide band Power (RTWP) measurement for the composite power across carriers with programmable time window for measurement
- 8 UMTS Digital Down Converter (DDC) channels or 16 CDMA/TD-SCDMA DDC channels with programmable 18 bit filter coefficients
- Each DDC channel includes
  - Real or complex DDC inputs
  - UMTS mode Rx Filtering: 6 stage CIC ( $m=1$  or  $2$ ), up to 40 tap CFIR, up to 64 tap PFIR
  - CDMA mode Rx Filtering: 6 stage CIC ( $m=1$  or  $2$ ), up to 64 tap CFIR, up to 64 tap PFIR
  - Each DDC channel provides individual channel specific power measurements
  - Each DDC channel has a dedicated final AGC
- Test Bus to monitor data at different stages of the DDC signal path
- 3.3V analog supplies, 1.5V digital core supply, 3.3V digital I/O supply
- 484 ball plastic BGA (23mm x 23mm) with 1.0 mm pitch
- Power dissipation: ~2.1W

## APPLICATIONS

- Wireless base station receiver
- Multi-carrier digital receiver
- UMTS (4 carriers-1 sector with diversity)
- CDMA (8 carriers-1 sector with diversity)
- TD-SCDMA (16 carriers-1 sector without diversity, 8 carriers-1-sector with diversity)
- Digital radio receivers
- Wide band receivers
- Software radios
- Wireless local loop
- Intelligent antenna systems

## Functional Block Diagram



## General Description

The AFE8406 is a multi-channel communications signal processor that provides analog to digital conversion and digital downconversion optimized for cellular base transceiver systems. The device supports UMTS, CDMA-1X and TD-SCDMA air interface cellular standards.

The AFE8406 provides up to 8 UMTS digital downconverter channels (DDC), 16 CDMA DDCs or 16 TD-SCDMA DDCs. The DDC channels are independent and operate simultaneously.

At the AFE8406 inputs, there are four input ports; two are hardwired to internal 14-bit analog-to-digital converters and two are 16-bit digital inputs. Each DDC channel can be programmed to accept data from any one of the four input ports.

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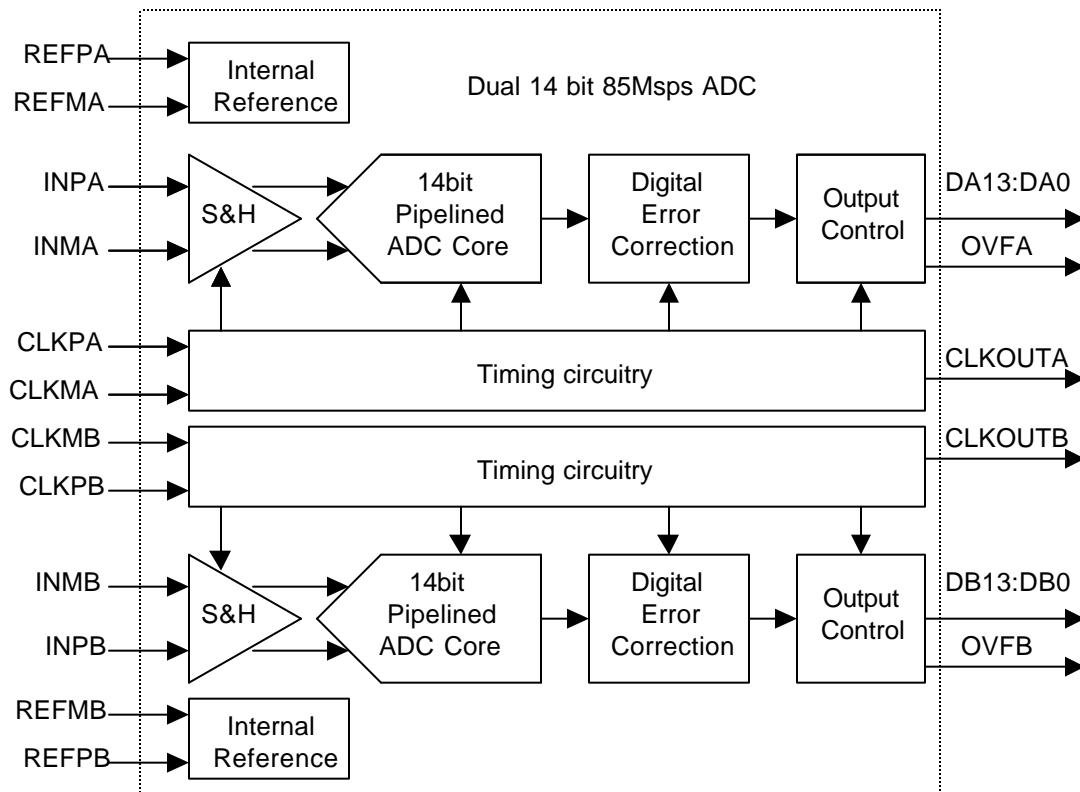
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## 1 Analog to Digital Converters

The AFE8406 includes a high performance dual channel 14bit 85MSPS Analog-to-Digital Converter. To provide a complete solution, each channel includes a high bandwidth linear sample-and-hold stage (S&H) and internal reference. An internal reference is provided, simplifying system design requirements, yet external reference can be used optionally to suit the accuracy and low drift requirements of the application.



The ADC digital output data and output clocks are connected directly to the rxin\_a and rxin\_b ports of the AFE8406 digital section. The OVFA and OVFB outputs connect directly to the AFE8406 digital section and also to package balls. The ADC outputs can be accessed through the test bus in a decimate by 32x only.

## 2 Receive Digital Signal Processing

The down conversion section of the AFE8406 consists of the receive input interface, the rx\_distribution bus, and 8 digital downconverter blocks.

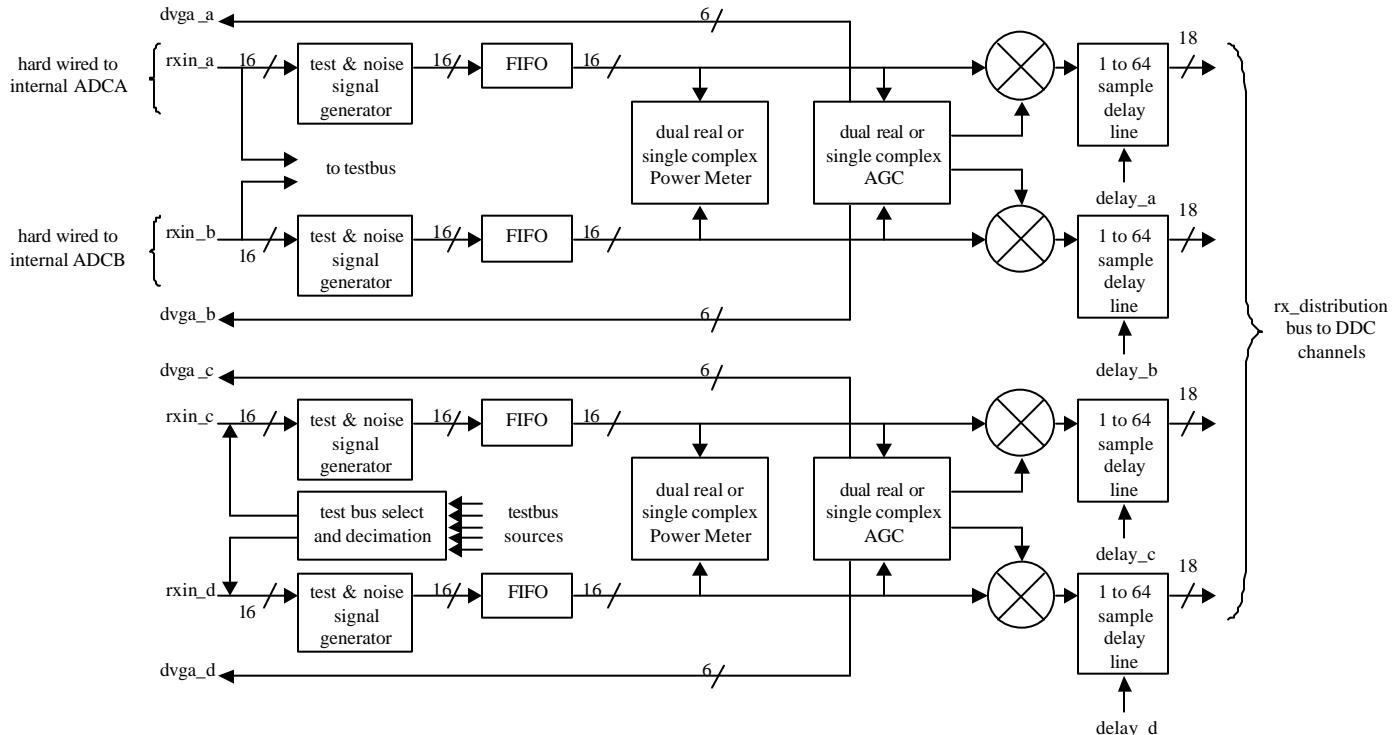
The purpose of the receive input interface is to accept signal data from four input ports (2 from the integrated 14 bit analog-to-digital converters, and 2 from the 16 bit input ports), measure the input signal power, provide control signals for external Digital Variable Gain Amplifiers (DVGAs) for controlling signal amplitude at each ADC input and to distribute the data to the DDC blocks. The input interface also has a user-controlled test generator and noise source.

The rx\_distribution bus distributes the four channels of signal data to each of the 8 DDC blocks.

Each DDC block selects one of the four channels (or 2 for complex input data) from the rx\_distribution bus and then performs downconversion tuning, programmable delay, channel filtering with decimation, power measurement, fixed gain adjust, and automatic gain control. Each DDC block can support 1 UMTS channel, 2 CDMA channels, or 2 TD-SCDMA channels. An optional mode permits stacking two DDC blocks in UMTS mode to provide double-length final pulse shaping filtering.

Tuned, filtered, and decimated signal data is output in bit serial or parallel format.

## 2.1 Receive Input Interface



The AFE8406's receive input data interface accepts data from several sources:

- Signal data from the two integrated 14-bit ADCs.
- Signal data presented at the two 16-bit digital data input ports.
- A LFSR test signal generator allows the AFE8406 to be tested using a known repetitive data sequence.

For the rxin\_c and rxin\_d input ports, signal data can be provided in binary or 2's complement form. The location of the ADC's MSB can be programmed to allow for additional AGC headroom if desired. For example, a 14-bit ADC may be connect with the MSBs aligned, or shifted down to allow the AGC additional gain range before clipping the signal.

Signal data can be accepted at rates up to rxclk in UMTS mode for either 8 normal channels or 4 double length final pulse shaping filter channels. In CDMA mode the maximum input rate is rxclk for real inputs, or rxclk/2 for complex inputs. For maximum filter performance, higher clock rates generally allow longer filters.

Complex signal data is input with I data driving one input port and Q data driving another. This means that there are only two signal data ports available when using complex input mode. The mapping of I and Q data onto the four input ports is programmable.

Signal input data is clocked into 8stage FIFOs using a matching external clock signal adcclk\_a/b/c/d. Signal data is clocked out of the FIFO from a gated rxclk (the AFE8406 receive section clock). The FIFO

allows arbitrary phase relationship between adcclk\_a/b/c/d and rxclk. The frequency relationship is mandated by the programmed configuration.

The test and noise generator can supply test sequences or add noise to the input signal data. The test sequences, when combined with the checksum generators, are useful for initial board debug or power-on self-test.

For applications that require receiver desensitization, the noise generator can add noise to user selected bits to input data stream to reduce receiver sensitivity.

The two ADC input ports, rxin\_a and rxin\_b, can be passed to the testbus control block, decimated by 32x, and routed directly to the AFE8406 testbus output pins. The key requirement of this function is to be able to verify the performance of the ADC by reconstructing the samples, while limiting the output sample rate to less than 5MHz using a 85MHz ADC sample rate.

Many other internal chip signals can be routed to the testbus for evaluation and debug purposes. When the testbus is enabled, the rxin\_c and rxin\_d ports are driven as digital outputs.

Each of the four outputs to the DDC channels includes a 1 to 64 sample delay lines.

### Programming

Variable	Description
ssel_ddc(2:0)	Selects the sync source for the DDC data input mux and mixer. This sets the sync source for <i>DDC input clock generation and synchronization for all DDC channels</i> .
offset_bin_X	Selects offset binary input when set, 2's complement input when cleared. X={a,b,c,d} <b>Note that the internal ADCs use 2's complement format, so offset_bin_A and offset_bin_B must be set.</b>
msb_pos_X(2:0)	Identifies the connection location of the ADC's MSB. Programmed values of {0..7} corresponds to msb at {rxin_x_15.. rxin_x_8}. X={a,b,c,d}

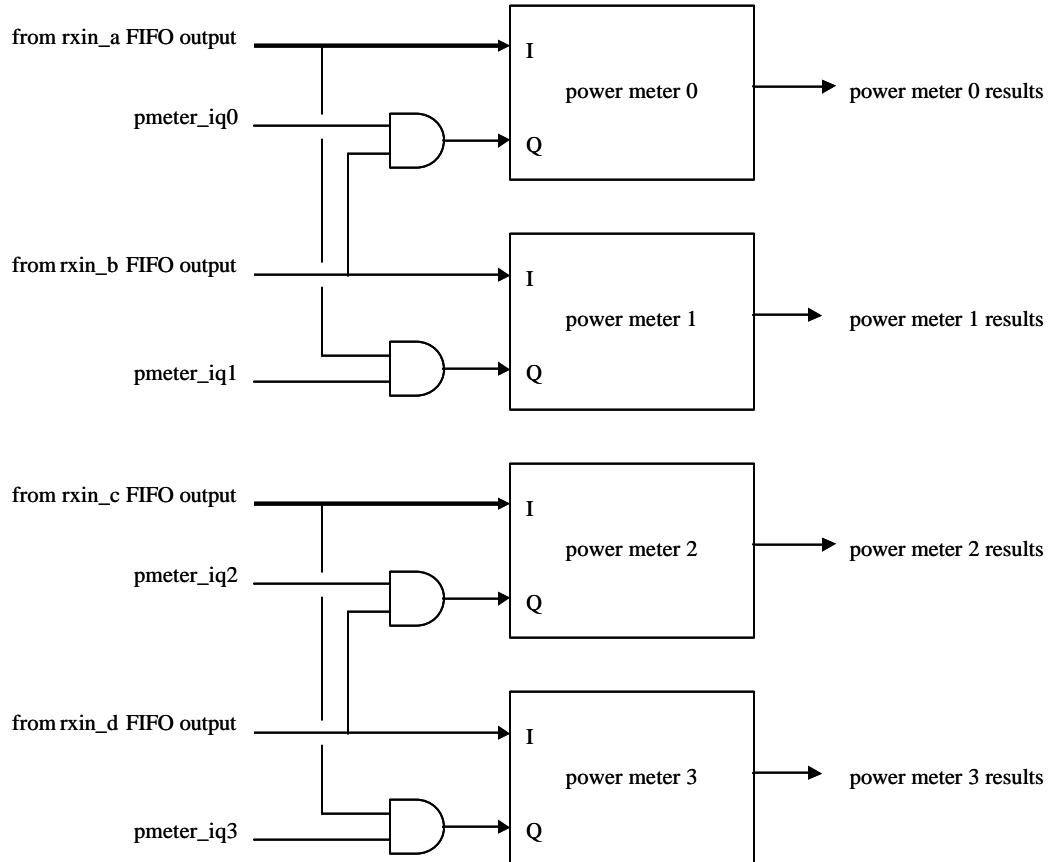
#### 2.1.1 Receive FIFO

The receive FIFO consists of an 8 stage memory and 2 counters generating the input write pointer and output read pointer. When the FIFO receives a sync signal, the input and output pointers are initialized with a write to read pointer offset of four samples. Input samples from rxin\_X (writes) are clocked with the adcclk\_X input dock rising edges, and the input pointer advances on each clock rising edge. Output samples (reads) and the output pointer are clocked with the rxclk input signal rising edges, divided by the programmed sample rate loaded into the rate\_sel(1:0) control register.

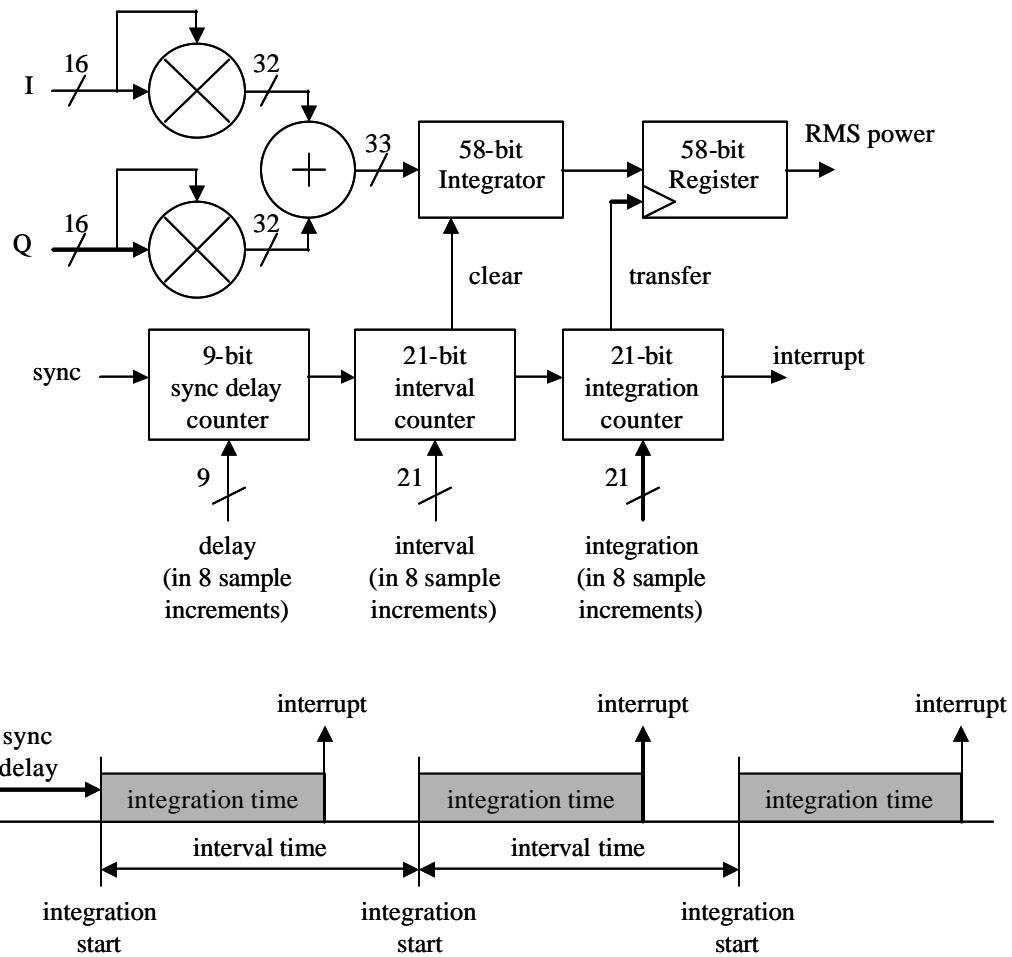
**Programming**

Variable	Description
adc_fifo_bypass	When set, bypasses the input FIFOs and input data is latched directly using the rxclk. When cleared, input data is latched using the adcclk_a/b/c/d inputs.
ssel_adc_fifo(2:0)	Selects the sync source for the FIFO state machines. This sync signal initializes the FIFO input and output pointers.
rate_sel(1:0)	This selects the FIFO input and output rate; {rxclk, rxclk/2, rxclk/4 or rxclk/8 }. For example, with rxclk at 153.6MHz, set rate_sel to 0, 1, 2 or 3 respectively for adcclk_a/b/c/d 153.6, 76.8, 38.4 or 19.2MHz. <b>MUST BE SET THE SAME AS REGISTER ch_rate_sel(1:0).</b>
adc_fifo_strap_ab	When set, the rxin_a and rxin_b FIFO input and output pointers are synchronized to support complex input signals.
adc_fifo_strap_cd	When set, the rxin_c and rxin_d FIFO input and output pointers are synchronized to support complex input signals.

### 2.1.2 Receive Input Power Meters



Four Receive Input RMS power meters are provided. For real inputs, the four power meters can be used to measure the RMS power of the combined carriers in each of the four input signals (the Q input is held at zero). For complex inputs, two power meters can be used to measure the combined complex power and two can be disabled.



Power is calculated by squaring each 16 bit I (I and Q for complex inputs) sample, summing, and then integrating the summed-squared results into a 58 bit accumulator over a programmable integration period. The integration period is programmed into the 21 bit counter, in 8 sample increments. The power read is:

$$\text{power} = [(I^2) \times (Nx8 + 1)] \quad \text{for real inputs where } N \text{ is the integration count.}$$

$$\text{power} = [(I^2 + Q^2) \times (Nx8 + 1)] \quad \text{for complex inputs where } N \text{ is the integration count.}$$

A programmable 21 bit interval counter sets the power measurement interval (how often power will be measured) in 8 sample increments. A measurement integration period is started at the beginning of each interval period.

The process begins with a sync event starting the 9 bit delay counter. After  $(8 \times \text{sync\_delay} + 2)$  samples, the integration interval is started. Integration continues until the integration count is met, at which point the 58 bit integrator results are transferred to the read only register and an interrupt is generated. A new measurement period will start at the end of the interval period.

*Note: Each of the four composite RMS power meter blocks has its own delay sync, interval, and integration period counters, as well as separate sync source registers.*

The 21-bit counters in 8 sample increments allow up to 104.8mS interval times at 160MHz clock.

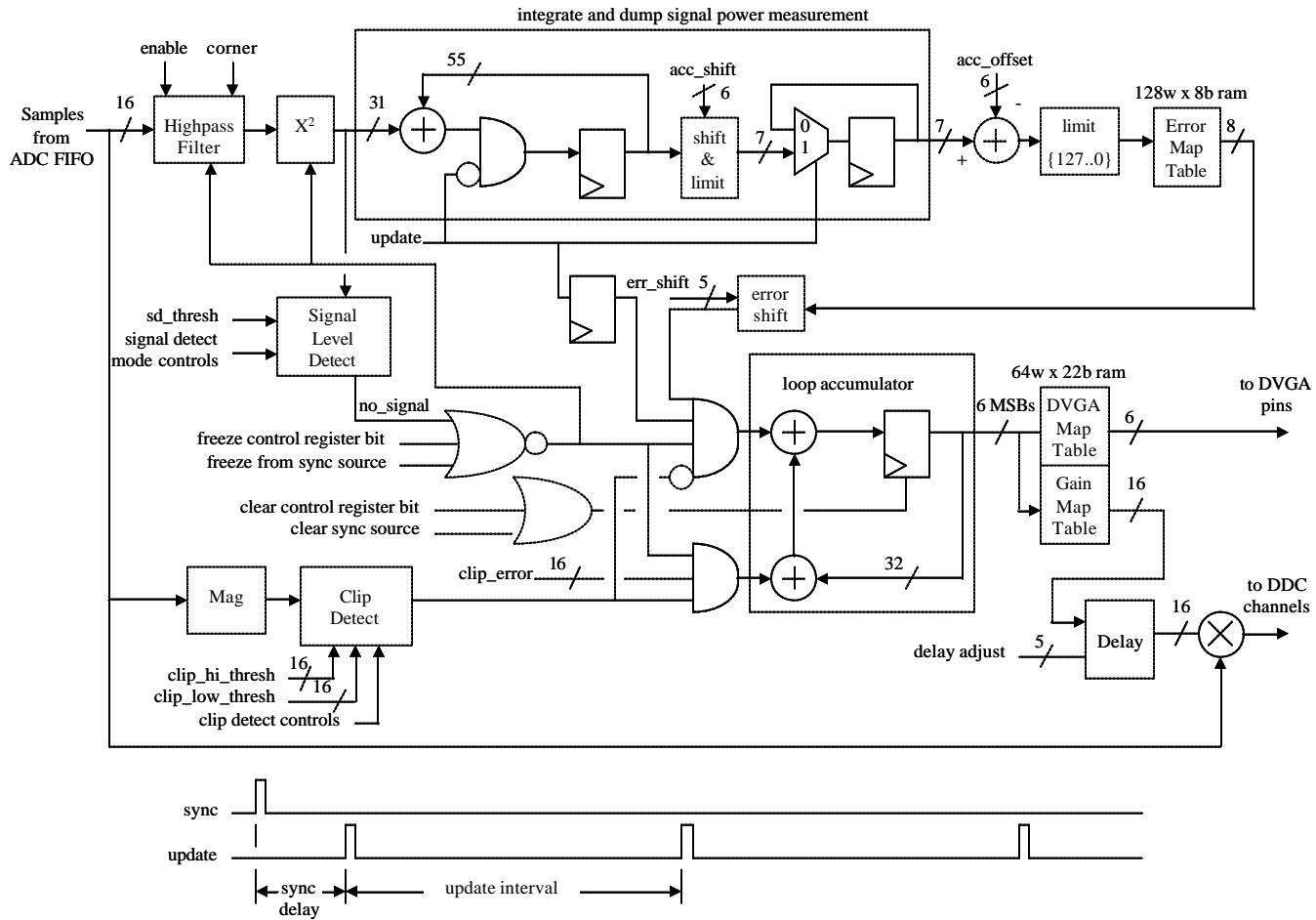
### Programming

Variable	Description
recv_pmeterX (57:0)	58 bit power measurement result. X= {0,1,2,3}.
recv_pmeterX_sqr_sum(20:0)	21 bit integration (square and sum) period. X= {0,1,2,3}.
recv_pmeterX_sync_delay(8:0)	Power meter delay sync period. X= {0,1,2,3}.
recv_pmeterX strt_intrvl(20:0)	21 bit measurement interval. X= {0,1,2,3}. <i>The strt_intrvl value must be greater than the sqr_sum value.</i>
ssel_recv_pmeter_X(2:0)	Sync source. X= {0,1,2,3}.
pmeterX_iq	selects complex power measurement input mode when set. X= {0,1,2,3}.
recv_pmeterX_ena	enables power meter when set. X= {0,1,2,3}.

### 2.1.3 Receive Input AGC (RAGC)

Input signals from the ADCs can be used to create a front end composite AGC loop when combined with a digitally controlled variable gain amplifier (DVGA) connected before the ADCs. The AGC system operates by integrating the square of the ADC samples over a programmable interval and applying a table driven error signal to a loop integrator based on the squared integration output. The error table maps the signal power to a user programmed error value. The loop integrator output is used to drive map tables to control the DVGA output pins and a gain adjustment multiplier. Fast updates can be enabled if desired, to cause the loop integrator to quickly adjust to interfering signals. The ADC input signals can also be passed through a high pass filter to remove DC offset before squaring the input.

The programmable error table, integrator mapping tables, and clip thresholds, when combined with the user programmable interval timers provide a highly flexible AGC function.



The AGC measurement interval timer is a 24-bit timer initialized by a sync after a programmable 8bit delay. During the integration interval, the squared input signal is shifted by the programmed value and accumulated. At the end of the interval time, an update pulse is generated, and the selected 7 bits of the 55-bit accumulated power is upper limit checked and transferred to the power holding register. A programmable offset is applied, and the following limit check produces a 7 bit address value for the error map table RAM. The user programmable error map table and following gain shift setting are used to determine the loop error signal to be added to the 32-bit AGC loop accumulator. The error value is only added to the loop accumulator once per update. The loop accumulator upper 6 MSBs are used as the address for the programmable DVGA map table and gain map table. The gain map table address can be delayed from 0 to 31 clock cycles to align DVGA changes to signal level changes at the output of the AGC.

The AGC includes four sources for freezing the loop and holding the loop accumulator constant. A general sync source can be used to directly control the freeze; when the selected sync source is high, the AGC will be held, and when low, the AGC will operate. A control register bit freezes the AGC in the same fashion; when the bit is set, the AGC is held, and when cleared, the AGC will operate. A signal level detector is provided that can be used to automatically freeze the AGC loop in the event of input signal loss. A programmable signal detection threshold value, number of samples below the signal detection threshold, and window timer are used to determine when no signal is present. Finally, a programmable number of PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.

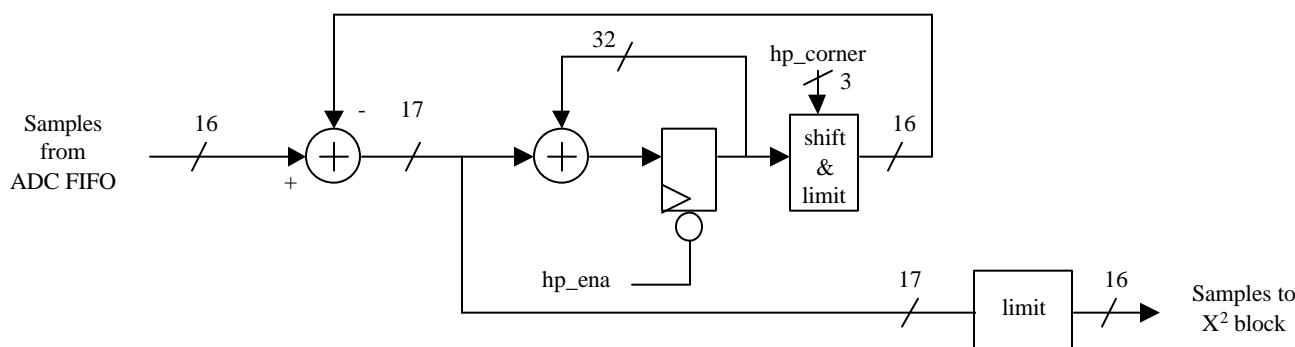
AGC updates after sync can be programmed, and the AGC will be held until the next sync event. Freeze holds the loop accumulator constant, the integrate and dump accumulator constant and the interval timer constant. When freeze is released, the interval timer will resume counting.

A sync event will always reinitialize the integrate and dump interval timer, and terminate the pending update to the loop accumulator from the current integrate and dump measurement interval. For example, if a sync event occurs during an integrate and dump interval, that interval will be terminated without updating the loop, and the integrate and dump accumulator will be cleared. After the programmed sync delay, a new interval will start.

The AGC includes a dual threshold clip detect function, using two programmable 16-bit thresholds and programmable counters. The clip detector will cause immediate loop accumulator updates while the clip event is active. The 16-bit clip error value is aligned at the MSBs of the loop accumulator. Clip events are qualified when a programmed number of samples are above the high clip threshold during the programmable clip window time. For example, a clip event can be defined as 8 samples above the clip high threshold in a 256 sample window; the clip high threshold, the number of samples above the high clip threshold and the sample window time are programmable. Once the clip event has occurred, the clip duration is controlled by the clip low threshold value, clip low samples value and clip low timer. The clip event is cleared when the number of samples below the low clip threshold exceeds the programmed value within the clip low timer window. The clip low threshold, number of clip low samples and the clip low window timer are programmable.

The AGC blocks can be paired together, rxin\_a with rxin\_b, and rxin\_c with rxin\_d, to produce a complex input AGC mode. The clip detector output from the rxin\_b/d AGCs is logically OR'ed with the rxin\_a/c clip detect outputs. The squared input function before the integrate and dump and signal level detector is replaced with a  $I^2 + Q^2$  power calculation. The accumulator MSBs from the rxin\_a/c AGCs are connected to the rxin\_c/d DVGA map table and gain map table inputs. This arrangement allows the AGCs to operate in a direct conversion receiver system by controlling the  $I^2 + Q^2$  complex signal level.

The highpass filter is a 32 bit accumulator followed by an adjustable shift to control the corner frequency, a subtractor to remove the accumulated offset and a final limiter to produce a 16 bit result. The highpass filter function is enabled by setting hp\_ena; clearing hp\_ena holds the accumulator reset.



**Programming**

Variable	Description
ragc_bypass_X	Bypasses the entire receive AGC circuit when set. X = {0,1,2,3}
hp_ena_X	enables high pass filter when set
hp_corner_X(2:0)	adjusts the corner frequency of the high pass filter
integ_interval_X(23:0)	integrate and dump signal power measurement interval in samples.
acc_shift_X(4:0)	Shift down amount following the integrate and dump accumulator.
acc_offset_X(5:0)	offset value applied to the shifted integrate and dump output.
ragc_sync_delay_X(7:0)	AGC sync delay interval, from 1 to 256 samples.
ssel_ragc_interval_X(2:0)	Sync source selection for the interval timer.
ssel_ragc_freeze_X(2:0)	Sync source selection for AGC freeze
ssel_ragc_clear_X(2:0)	Sync source selection for the AGC loop accumulator clear
ragc_freeze_X	Register bit to freeze the AGC when set
ragc_clear_X	Register bit to clear the AGC accumulator when set
ragc_update_X(7:0)	Sets the number of updates per sync event, after which no further updates will occur until the next sync event. Program to 0x00 to continually update.
sd_ena_X	enables freezing the AGC with the signal detector when set
sd_thresh_X(15:0)	signal detection threshold for AGC channel X. This 16 bit word is lined up with bits 23 down to 8 of the square output. The smallest signal level is that can be programmed is therefor 16 LSBs on the ADC input, and the largest is 4095 LSBs at the ADC input.
sd_samples_X(15:0)	the number of samples below the signal detect threshold within the signal detect sample timer window required to freeze on the AGC.
sd_timer_X(15:0)	window timer to qualify signal detection.
clip_hi_thresh_X(15:0)	clip detector high threshold
clip_lo_thresh_X(15:0)	clip detector low threshold
clip_hi_samples_X(7:0)	a clip event is detected when this number of samples above the clip high threshold within the clip high sample timer window exceeds this value.
clip_lo_samples_X(7:0)	a clip event ends when this number of samples below the clip low threshold within the clip low sample timer window exceeds this value.
clip_hi_timer_X(15:0)	window timer to qualify clip events.
clip_lo_timer_X(15:0)	window timer to determine when the clip event ends.
clip_error_X(15:0)	error signal applied to the AGC accumulator when a clip event is active. This data is MSB aligned, and therefor can cause immediate changes to the accumulator.

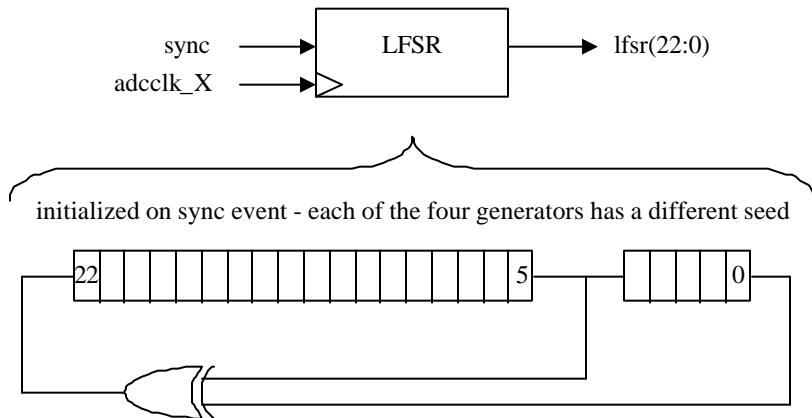
**Programming (continued)**

Variable	Description
ragc_error_map_X	128w x 8b memory holding the log to error look up table.
dvga_map_X	64w x 6b memory holding the accumulator to DVGA look up table
gain_map_X	64w x 16b memory holding the accumulator to GAIN look up table (256 decimal is unity gain)
delay_adj_X(4:0)	Delay between DVGA output updates and gain map updates to compensate for ADC pipeline delays, etc.
err_shift_X(4:0)	error map table output shift up before adding to loop accumulator
complex_01	enables complex AGC mode on inputs rxin_a and rxin_b when set
complex_23	enables complex AGC mode on inputs rxin_c and rxin_d when set
ragc_accum_X(31:0)	32-bit read only register holding the current contents of the loop accumulator.
tristate(10:7)	Tristate controls for the dvga_d/c/b/a output pins; pins are in tristate when the tristate bits are set.
ragc_mpu_ram_read	What set, the receive AGC map rams are readable via the MPU control interface. <i>The AFE8406 signal path is not operational when this bit is set, it is intended for debug purposes only.</i>

### 2.1.4 Test and Noise Signal Generator

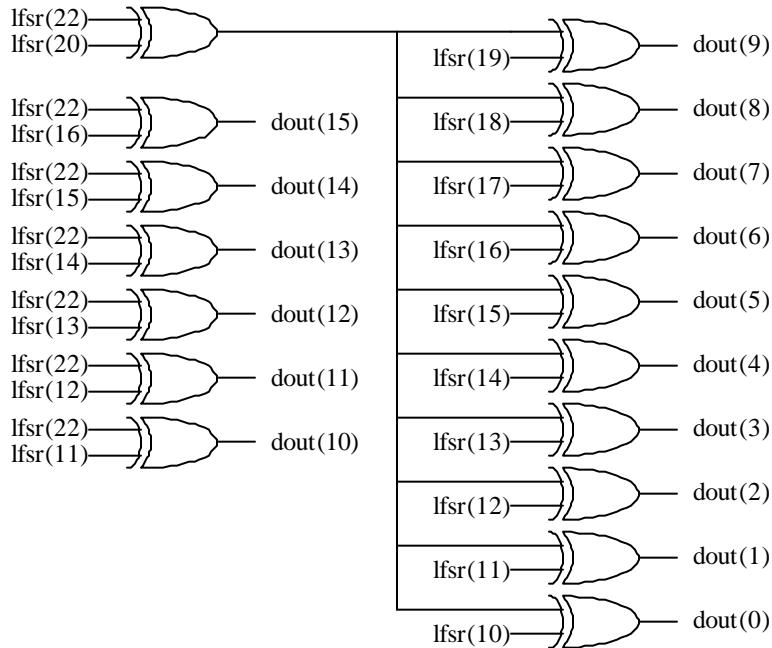
The test and noise generator can generate test signals replacing the rxin\_a/b/c/d inputs as a tool for debug, evaluation and self test. Checksum generators included in the individual DDC channels at the outputs can be used in conjunction with the noise generator and the internal sync timer block to create the built in self test function.

The test and noise signal source included in this block is a 23-bit linear feedback shift register (LFSR) with a fixed polynomial and fixed initialization state. A sync input is required to initialize the LFSR, and the sync source is connected to the ddc\_counter output signal.



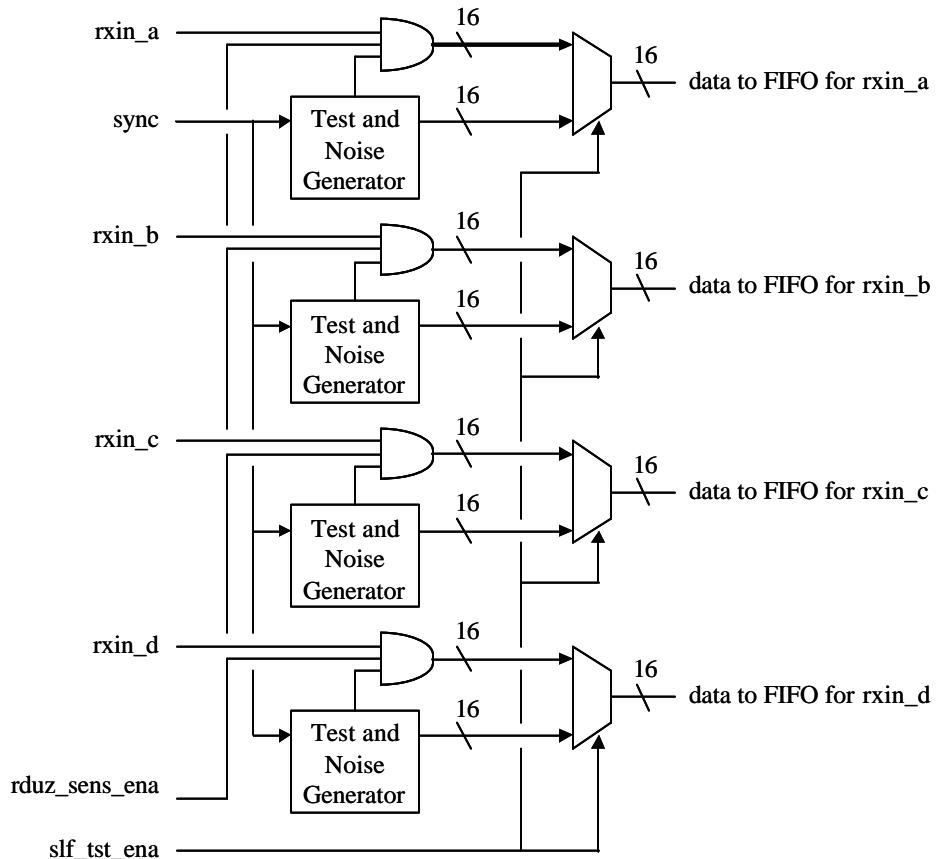
Receive Input Port	LFSR seed value, msb to lsb
rxin_a	100 0000 0000 0000 0001 0000 (0x400010)
rxin_b	010 0110 1110 0110 1100 1110 (0x26E6CE)
rxin_c	110 1110 1010 0010 1001 1000 (0x6EA298)
rxin_d	000 1011 0001 1110 1011 0111 (0x0B1EB7)

The 23-bit LFSR output signal if used to create a 16-bit "dout(15:0)" test signal using XOR combinations of the LFSR bits.

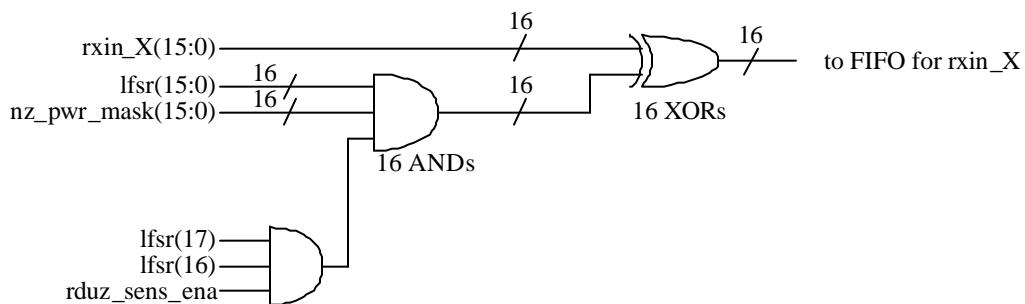


To enable the test signal generator, the slf\_tst\_ena control bit should be set. The rxin\_a/b/c/d signals will be then replaced by the four generator output streams. To use this test signal generator as a signal source for self test, the user must also set the adc\_fifo\_bypass control bit. Setting the adc\_fifo\_bypass control bit causes the adcclk\_a/b/c/d input clocks to be internally replaced with rxclk/N, where N is as programmed with the rate\_sel(1:0) control bits to {1,2,4 or 8}.

The test signal generators can also output a programmable constant value. All four test signal generators output the same programmable constant value.



The LFSR circuits can also be used to add noise to the rxin\_a/b/c/d input signals by setting the rduz\_sens\_ena control register bit. The magnitude of the noise added can be adjusted by programming the nz\_pwr\_mask(15:0) control register. In the figure below, X = {a,b,c or d}.



**Programming**

Variable	Description
slf_tst_ena	When set, the test signal generators replace the rxin_a/b/c/d input signals with internally generated psuedo random sequences. The fifo_bypass bit must be set when this bit is set.
rduz_sens_ena	Enables the LFSR, adding noise to the ADC input data when set.
nz_pwr_mask(15:0)	Selects the power of the noise added to the ADC input data.
adc_fifo_bypass	When set, the FIFO is essentially bypassed, and the adcclk_a/b/c/d clock input ports are ignored.
ddc_counter(31:0)	32 bit general purpose counter interval
ddc_counter_width(7:0)	8 bit general purpose counter timeout width pulse
ssel_ddc_counter(2:0)	Sync source selection for the general purpose counter
self_test_constant(17:0)	18-bit self test constant value applied to all 4 rxin_a/b/c/d inputs when self_test_const_ena is set.
self_test_const_ena	Enables the self test constant value for rxin_a/b/c/d

**2.1.5 Sample Delay Lines**

The four sample delay line blocks each consist of a 64 register memory and a state machine. The state machine uses a counter to control the write (input) pointer, and the programmed read offset register data to create the read (output) pointer. Programming larger read offset register values increases the effective delay at a resolution equal to the sample rate.

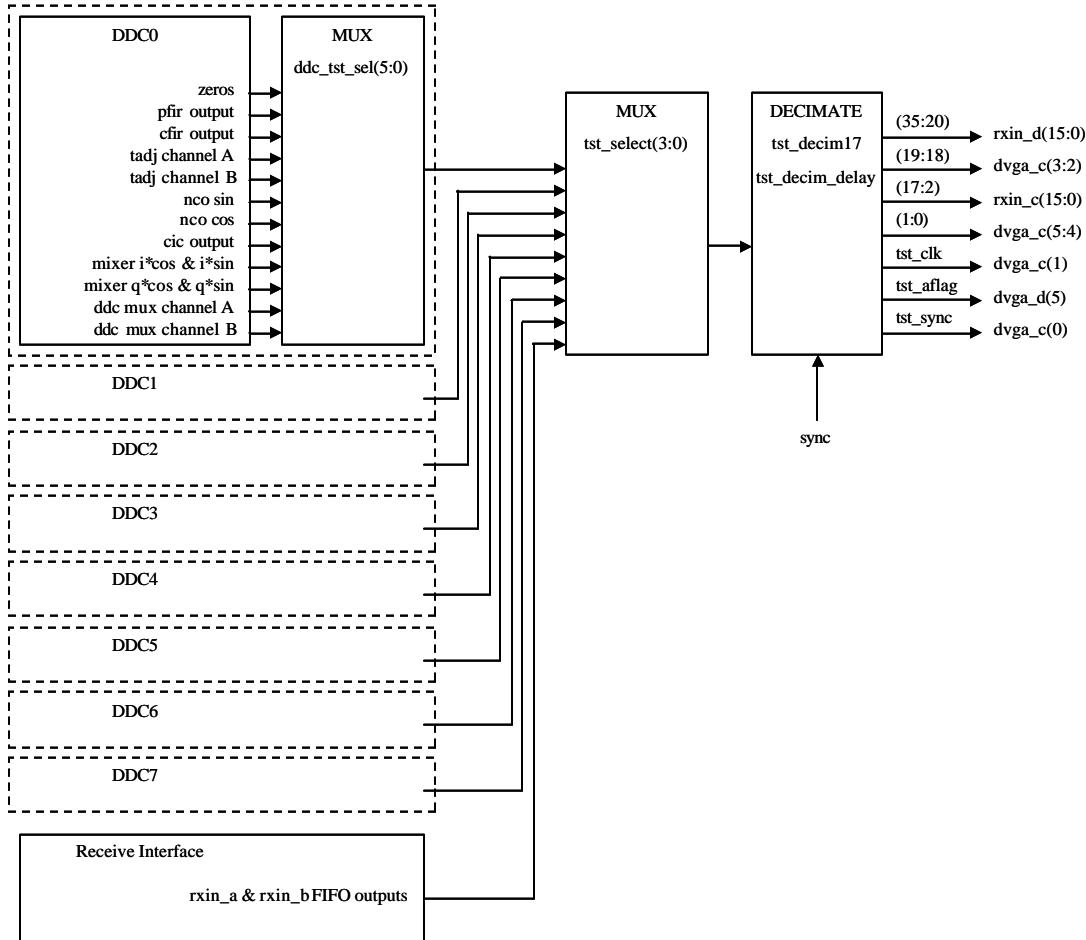
The read offset registers, delay\_line\_X, are double buffered. Writes to these registers may occur anytime, but the actual values used by the circuit will not be updated until a delay line sync event occurs.

**Programming**

Variable	Description
delay_line_X(5:0)	Read offset into the 64 element memory for each delay line. X= {0,1,2,3}.
ssel_delay_line_X(2:0)	Selects the sync source used to update the double buffered delay line register.

### 2.1.6 Test Bus

When the test bus is enabled, the rxin\_c(15:0) and rxin\_d(15:0) ports become outputs, and the dvga\_c and dvga\_d pins are combined with these pins to allow 36 bit wide signals from the DDC channels and the receive input interface to be multiplexed to this test output port. Many of these sources are decimated to reduce the output sample rates.

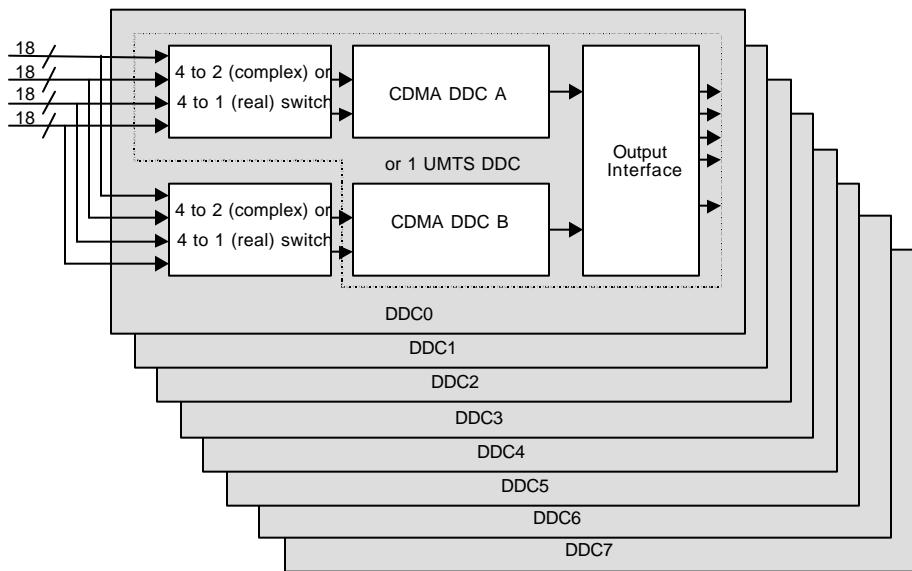


### Programming

Variable	Description
<code>ssel_tst_decim(2:0)</code>	Selects the sync source for the testbus decimator
<code>tst_decim_delay(3:0)</code>	Sets the testbus decimator delay from sync
<code>tst_decim17</code>	Not functional. Decimation is 32x regardless of setting.
<code>tst_on</code>	enables the test bus; <code>rxin_c(15:0)</code> and <code>rxin_d(15:0)</code> are changed from inputs to outputs, <code>dvga_c(5:0)</code> and <code>dvga_d(5)</code> are used as part of the test bus.
<code>tst_select(3:0)</code>	selects the source block for the testbus output; DDC0-7 or Receive Interface.
<code>ddc_tst_sel(5:0)</code>	selects the signal to be output from the DDC block
<code>tst_rate_sel(4:0)</code>	Sets the testbus output clock <code>tst_clk</code> period to $(tst_rate_sel + 1)$ rxclk cycles. When the test bus source is set to the ADC FIFO, <code>tst_rate_sel(4:0)</code> must be set to 0 for an output.
<code>tst_clk_pol</code>	Selects the polarity of the test clock output at <code>dvga_c(1)</code> when the test bus is enabled; 0 for rising edge in the center of valid data, 1 for falling edge in the center

	of valid data. <i>No effect when tst_rate_sel is "00000".</i>
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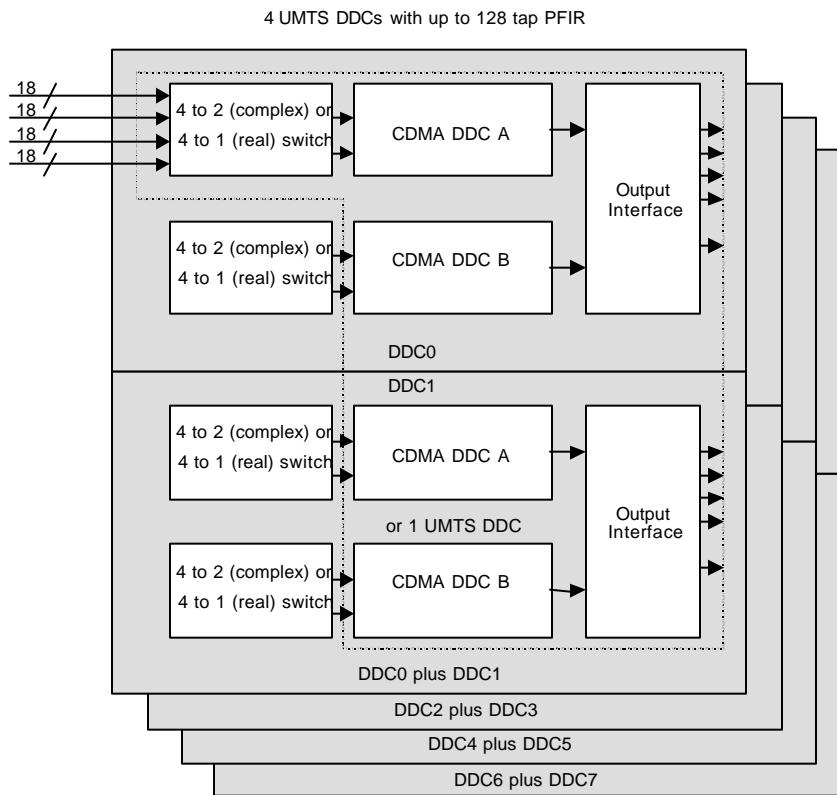
## 2.2 DDC Organization



The AFE8406 provides downconversion for up to 8 UMTS receive channels, 16 CDMA2000 receive channels or 16 TD-SCDMA receive channels. Downconversion channels are organized into 8 DDC blocks. Each individual DDC block provides 2 CDMA2000 or 2 TD-SCDMA DDC channels, A and B, or 1 UMTS channel.

Both CDMA DDC channels in a DDC block can be independently tuned, though they would likely be used as diversity pairs and tuned to the same frequency. Filter coefficients are shared between the two CDMA DDC channels within a block.

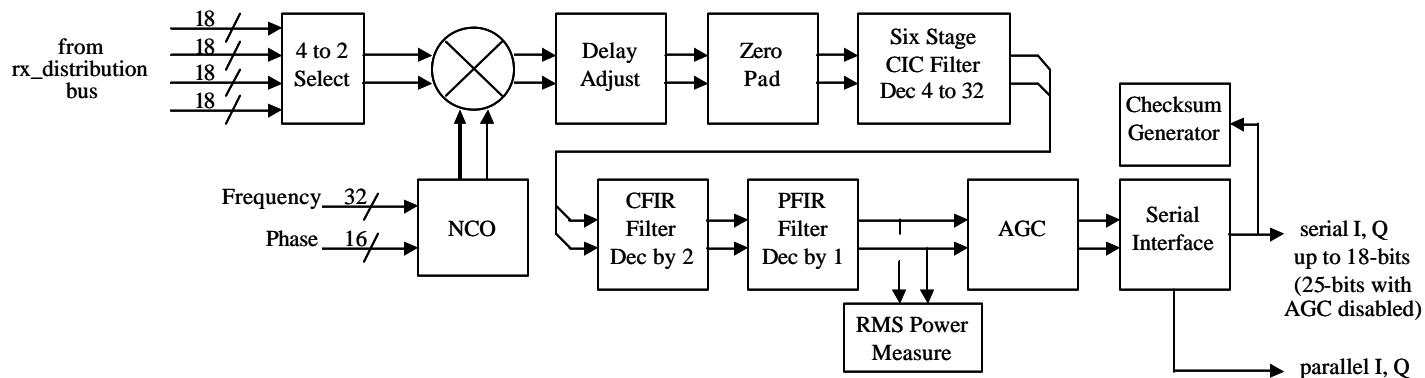
Two adjacent DDC blocks (for example, DDC0 and DDC1) can be strapped together to form a single UMTS DDC channel with double-length final pulse shaping filtering. The AFE8406 can therefore provide 4 UMTS DDC channels with double-length final PFIR filtering as shown in the following diagram.



### Programming

Variable	Description
ddc_ena	When set, turns on the DDC.
cdma_mode	When set, puts the DDC block in dual channel CDMA mode.
gbl_ddc_write	When set, all subsequent programming (writes only) for DDC0 and DDC1 is also written to DDC2/4/6 and DDC3/5/7.

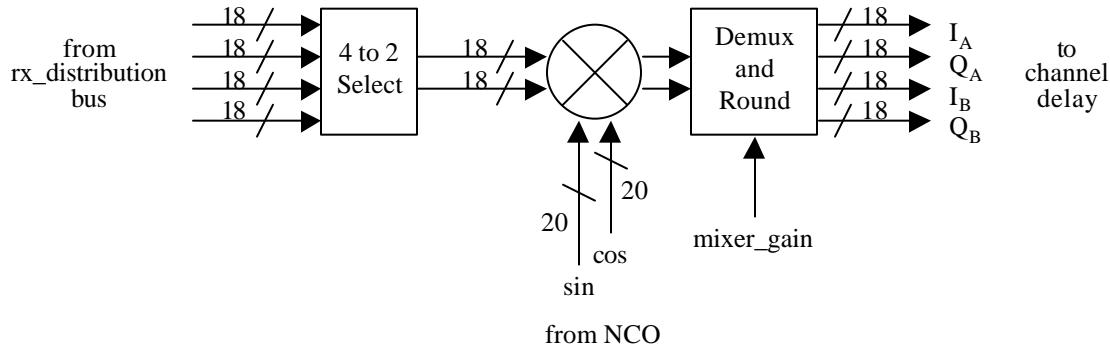
### 2.2.1 Downconverter Function Blocks



Each AFE8406 downconversion block can process two CDMA carriers or a single UMTS carrier. Signal data is selected from one of four ports for real inputs, or two of four ports for complex inputs. Data from the selected port(s) is multiplied with a complex, programmable numerically controlled oscillator (NCO) which tunes the signal of interest to baseband. The delay adjust and zero pad blocks permits adjustment of the delay in the end-to-end channel. Zero padding interpolates the signal to the rxclk rate. Filtering consists of a six stage CIC filter which decimates the tuned data by a factor from 4 to 32, a compensating FIR filter (CFIR) which decimates by a factor of two, followed by a programmable FIR filter (PFIR) which does not decimate. The output interface block can be programmed to decimate by 2 if desired.

The RMS power meter measures the power within the channel's bandwidth. The AGC automatically drives the gain and keeps the magnitude of the signal at a user-specified level. This allows fewer bits to represent the signal. The serial output interface formats and rounds the output data. Each of the above blocks is described in greater detail in the following sections.

## 2.2.2 DDC Mixer



The receive mixer translates the input (from one of the input signal sources) to baseband where subsequent filtering is performed to isolate the signal of interest. The mixer is a complex multiplier that accepts 18 bit I and 18 bit Q signal data from the receive input interface and 20 bit Sine and Cosine sequences from the NCO. The NCO generates a mixing frequency (sometimes referred to as a local oscillator, or LO) specified by the user so that the desired signal of interest is tuned to 0 Hertz.

A DDC channel can support one UMTS signal directly, or two CDMA channels at half the input rate. When in CDMA mode each channel may set independently; the path selection and the mixer tuning and phase. The mixer output produces two complex streams; one representing the signal path for the A-side DDC, the other the B-side. Each of these streams drives a channel delay and zero pad block.

The maximum input rate for UMTS is rxclk for either real or complex input data.

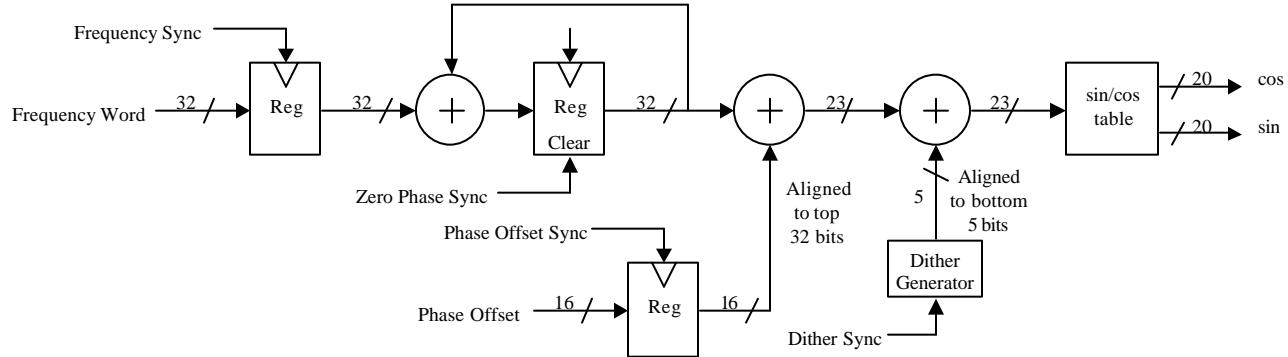
The maximum input rate in CDMA mode with real inputs is rxclk (remix\_only is set, see below).

The maximum input rate in CDMA mode with complex inputs is rxclk/2 due to sharing of multiplier resources.

## Programming

Variable	Description
ddcmux_sel_a(3:0)	Programs the I and Q complex input data routing onto two of the four input ports for stream A of CDMA DDC
ddcmux_sel_b(3:0)	Programs the I and Q complex input data routing onto two of the four input ports for stream B of CDMA DDC
remix_only	For CDMA mode only, set this bit for real input data at the rxclk rate. For complex inputs in CDMA mode, the maximum input data rate is rxclk/2, and this bit must be cleared. For CDMA mode with real inputs at the rxclk/2 rate or lower, this bit must be cleared
zero_qsample	When set, the Q samples used by the mixer are always zero. This bit should be set for real only inputs in UMTS mode, or real only inputs in CDMA mode when the input sample rate is rxclk/2 or lower.
ch_rate_sel(1:0)	Specifies the input channel data rate (rxclk, rxclk/2, rxclk/4, or rxclk/8 MSPS). <b>MUST BE SET THE SAME AS REGISTER rate_sel(1:0).</b>
mixer_gain	When asserted, adds 6dB of gain in the mixer. This gain is highly recommended.

### 2.2.3 DDC Number Controlled Oscillator (NCO)



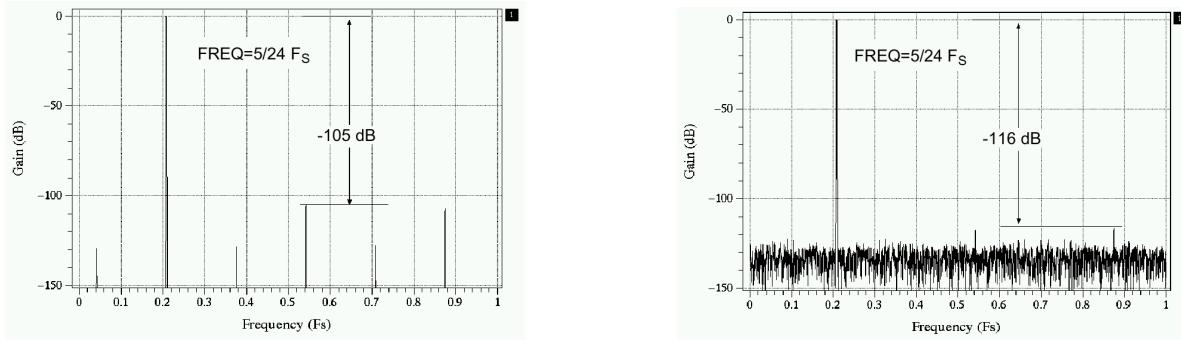
The NCO is a digital complex oscillator that is used to translate (or downconvert) an input signal of interest to baseband. The block produces programmable complex digital sinusoids by accumulating a frequency word which is programmed by the user. The output of the accumulator is a phase argument that indexes into a sin/cos ROM table which produces the complex sinusoid. A phase offset can be added prior to indexing if desired for channel calibration purposes. This will change the sin/cos phase with respect to other channels' NCOs.

A 5-bit dither generator is provided and generates a small level of digital pseudo-noise that is added to the phase argument below the bottom bits and is useful for reducing NCO spurious outputs. This dither generation is enabled by setting the dither\_ena bit; the magnitude of the dither can be reduced by setting one or both of the dither\_mask bits.

#### Dither Programming

Variable	Description
dither_ena	When set turns dither on. Clearing turns dither off.
dither_mask(1:0)	Masks the MSB and MSB-1 dither bits, respectively, when set.

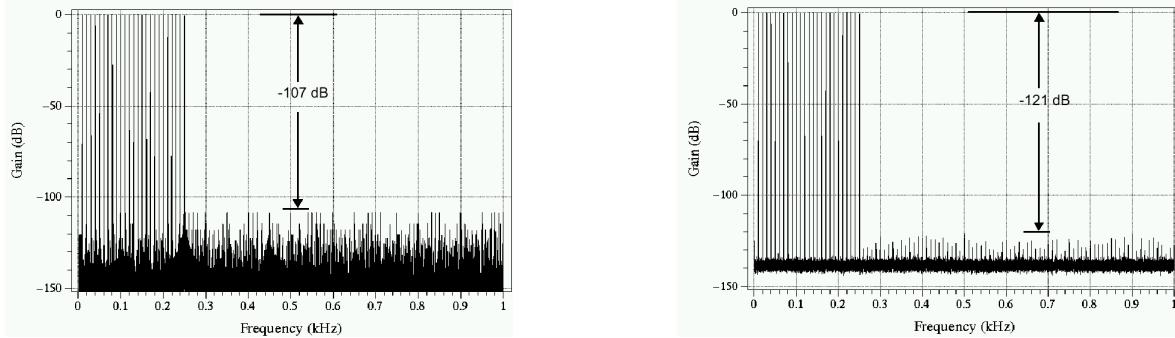
The NCO spurious levels are better than  $-115$  dBc. Added phase dither randomizes the periodic nature of the phase accumulation process and reduces low-level spurious energy. For some frequencies ( $K^*F_s/24$ ) dither is ineffective – in these cases an initial phase of 4 reduces NCO spurs. The figures below show the spur level performance of the NCO without dither, with dither, and with a phase offset value.



a) Worst case spectrum without dither

b) Spectrum with dither (tuned to same Frequency)

Figure 1. Example NCO spurs with and without dithering



a) Plot without dither or phase initialization

b) Plot with dither and phase initialization

Figure 2. NCO Peak Spur Plot

The tuning frequency is specified as a 32 bit Frequency Word and is programmed as two sequential 16 bit words over the control port. The NCO frequency resolution is simply the  $F_{\text{clk}}/2^{32}$ , where  $F_{\text{clk}}$  is the ADCCLK frequency. As an example, at an input clock rate of 61.44 MHz, the frequency step size would be approximately 14 milli-Hertz. The Frequency Word is determined by the formula:

$$\text{Frequency Word (in decimal)} = 2^{32} \times \text{Tuning Frequency} / F_{\text{clk}}$$

Note that frequency tuning words can be positive or negative valued. Specifying a positive frequency value translates negative frequencies upwards towards 0 Hertz. Specifying a negative tuning frequency translates positive frequencies downwards towards 0 Hertz.

**Programming**

Variable	Description
phase_add_a(31:0)	32 bit tuning frequency word for the A-side DDC when in CDMA mode. Also for UMTS mode.
phase_add_b(31:0)	32 bit tuning frequency word for the B-side DDC when in CDMA mode. Not used in UMTS mode.

Each of the 12 CDMA DDC channels can be loaded with unique frequency words.

The phase of the NCO's Sin/Cos output can be adjusted relative to the phase of other channel NCOs by specifying a Phase Offset. The Phase Offset is programmed as a 16 bit word, yielding a step size of about 5.5 milliDegrees. The Phase Offset Word is determined by the formula:

$$\text{Phase Offset Word} = 2^{16} \times \text{Offset\_in\_Degrees} / 360$$

or,

$$\text{Phase Offset Word} = 2^{16} \times \text{Offset\_in\_Radians} / 2\pi$$

**Programming**

Variable	Description
phase_offset_a(15:0)	16 bit phase offset word for the A-side DDC when in CDMA mode. Also for UMTS mode.
phase_offset_b(15:0)	16 bit phase offset word for the B-side DDC when in CDMA mode. Not used in UMTS mode.

Each of the 16 CDMA DDC blocks can be loaded with unique phase offset words.

Various synchronization signals are available which are used to synchronize the NCOs of all channels with respect to each other. Frequency Sync and Phase Offset Sync determine when frequency and phase offset changes occur. For example, generating a Frequency Sync after programming the two frequency words will cause the NCO (or multiple NCOs) to change frequency at that time, rather than after each of the three frequency words is programmed over the control bus. The Zero Phase Sync signal is used to force the sine and cosine oscillators to their zero phase state. Dither Sync can be used to synchronize the dither generators of multiple NCOs. The NCOs used in the transmit section are identical to what is described for the receive section. Note that there is one set of sync's provided for each DDC. When one DDC is used to process two CDMA signal the sync's are shared between them.

**Sync Programming**

Variable	Description
ssel_nco(2:0)	Sync source for NCO accumulator reset
ssel_dither(2:0)	Sync source for NCO dither reset
ssel_freq(2:0)	Sync source for NCO frequency register loading

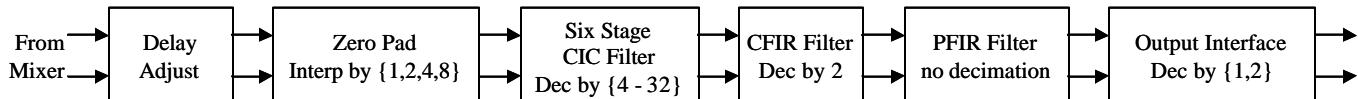
ssel_phase(2:0)	Sync source for NCO phase register loading
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### 2.2.4 DDC Filtering and Decimation

The purpose of the receive filter chain is to isolate the signal of interest (and reject all other others) that has been previously translated to baseband via the mixer and NCO. The overall decimation through the chain needs to be considered. The goal, generally, is to output the isolated signal at a rate that is twice (2X) the signal's chip rate. For UMTS this would be 7.68 MSPS and for CDMA the output rate should be 2.4576 MSPS. TD-SCDMA systems require the output rate be the chip rate of 1.28 MSPS. The output interface is programmed to decimate by 2 for the TD-SCDMA case.

Receive filtering and decimation is performed in several stages:

- Zero padding to interpolate the input sample rate (if needed) up to the rxclk rate
- High rate decimation (4 to 32) using a six stage cascade-integrate-comb filter (CIC)
- Decimate by two compensation filtering using the programmable compensating FIR filter (CFIR)
- Pulse-shape filtering via the programmable FIR filter (PFIR) with no decimation
- Output interface, serial or parallel format, with no decimation or decimate by 2

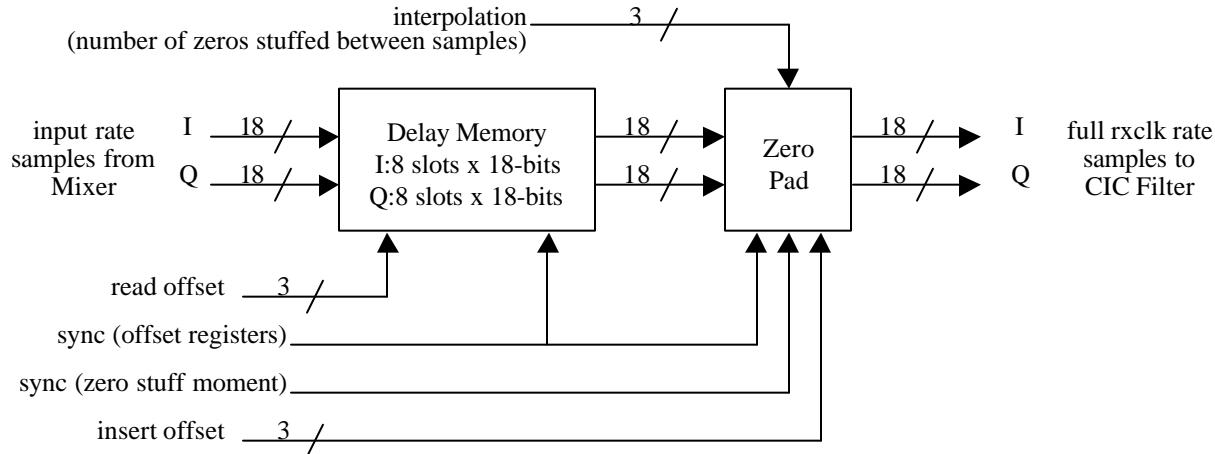


The table below contains some examples of decimation and sample rates at the output of each block for UMTS, CDMA and TD-SCDMA standards at various supported input samples. For each example, the differential ADC clocks are provided to the AFE8406 at the input sample rate and the rxclk is provided at the zero pad output rate.

	Input Sample Rate (MSPS)	Zeros Added	rxclk(MHz) and Zero Pad Output Rate (MSPS)	CIC Decimation	CIC Output Rate (MSPS)	CFIR Decimation	CFIR Output Rate (MSPS)	PFIR Decimation	PFIR Output Rate (MSPS)	Output Decimation
<b>UMTS</b>	76.80	1	153.6	10	15.36	2	7.68	1	7.68	1
<b>UMTS</b>	61.44	1	122.88	8	15.36	2	7.68	1	7.68	1
<b>CDMA</b>	78.6432	0	78.6432	16	4.9152	2	2.4576	1	2.4576	1
<b>CDMA</b>	78.6432	1	157.2864	32	4.9152	2	2.4576	1	2.4576	1
<b>CDMA</b>	61.44	1	122.88	25	4.9152	2	2.4576	1	2.4576	1
<b>TD-SCDMA</b>	81.92	0	81.92	16	5.12	2	2.56	1	2.56	2
<b>TD-SCDMA</b>	76.80	0	76.80	15	5.12	2	2.56	1	2.56	2
<b>TD-SCDMA</b>	76.80	1	153.6	30	5.12	2	2.56	1	2.56	2
<b>TD-SCDMA</b>	61.44	1	122.88	24	5.12	2	2.56	1	2.56	2

*Note: The DDC output interfaces, both serial and parallel formats, can be programmed to decimate by 2. For the TD-SCDMA examples listed above, the DDC output rate is 1.28Mps (1x chip rate).*

## 2.2.5 DDC Channel Delay Adjust and Zero Insertion



The Receive Channel Delay Adjust function is used to add programmable delays in the channel downconvert path. Adjusting channel delay can be used to compensate for analog elements external to the AFE8406 digital downconversion such as cables, splitters, analog downconverters, filters, etc.

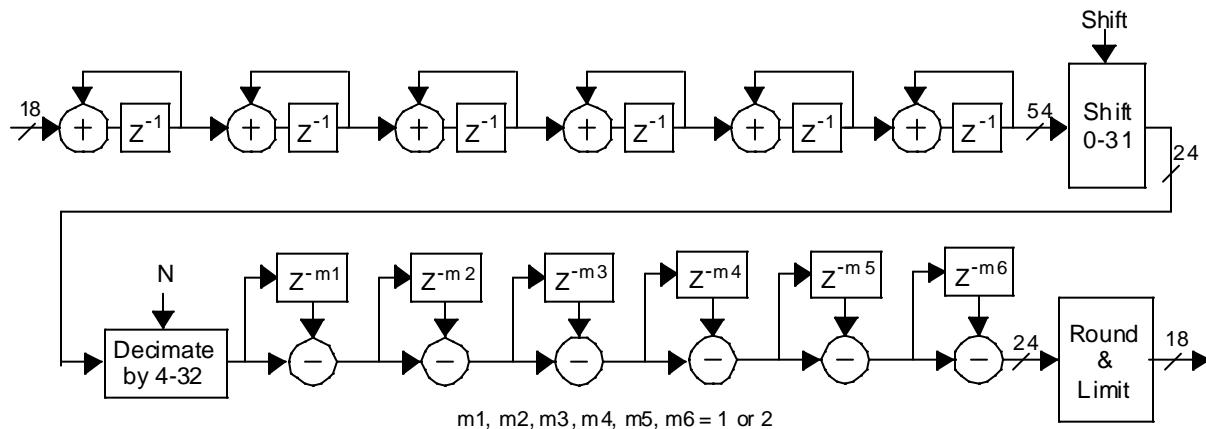
The Delay Memory block consists of an 8 register memory and a state machine. The state machine uses a counter to control the write (input) pointer, and the programmed read offset register data to create a read (output) pointer. Programming larger read offset register values increases the effective delay at a resolution equal to the input sample rate.

The Zero Pad block is used in conjunction with the Delay Memory for delay adjustments. For example, with input rates of rxclk/8, the Zero Pad block interpolates the input data to rxclk by inserting 7 zeros. The Zero Pad's sync insert offset 3-bit control specifies when the zeros are inserted relative to the Sync signal. This permits a fine adjustment at the rxclk resolution.

The read offset register, `tadf_offset_course_a/b`, and the insert offset register, `tadj_offset_fine_a/b`, are double buffered. Writes to these registers may occur anytime, but the actual values used by the circuit will not be updated until a register sync .

**Programming**

Variable	Description
tadj_offset_coarse_a(2:0)	Read offset into the 8 element memory for the UMTS or CDMA mode A channel DDC.
tadj_offset_coarse_b(2:0)	Read offset into the 8 element memory for the CDMA mode B channel DDC when in CDMA mode.
tadj_offset_fine_a(2:0)	Controls the zero pad (or stuff) insert offset (fine adjust) for the UMTS or CDMA mode A channel of the DDC.
tadj_offset_fine_b(2:0)	Controls the zero pad (or stuff) insert offset (fine adjust) for the CDMA mode B channel of the DDC when in CDMA mode.
tadj_interp(2:0)	The interpolation value (1, 2, 4, or 8). Same used for both the A and B channels when in CDMA mode. Selects the number of zeros to be inserted.
ssel_tadj_fine(2:0)	Selects the sync source for the fine time adjust zero stuff moment. Same for A and B channels when in CDMA mode.
ssel_tadj_reg(2:0)	Selects the sync source used to update the double buffer course and fine delay selection registers. Same for A and B channels when in CDMA mode.

**2.2.6 DDC CIC Filter**

The CIC filter provides the first stage of filtering and large-value decimation. The filter consists of six stages and decimates over a range from 4 to 32.

I data and Q data are handled separately with two CIC filters. In addition, when in CDMA mode (two CDMA channels processed within a single DDC), another pair of CIC filters handles the B-side channel.

The filter response is  $6^*(\text{Sin}(x)/x)$  in character where the key attribute is that the resulting response nulls reject signal aliases from decimation. A consequence of this desirable behavior is that only a small portion of the passband can be used, less than 25% generally. This means that the CIC decimation value should be chosen so that the signal exiting the CIC filter is oversampled by at least a factor of four.

The filter is equivalent to 6 stages of a FIR filter with uniform coefficients (6 combined boxcar filter stages). Each filter would be of length  $N$  if  $m=1$ , or  $2N$  if  $m=2$ .

The filter is made up of six banks of 54 bit accumulator sections followed by six banks of 24 bit subtractor sections. Each of the subtractor sections can be independently programmed with a differential delay of either one or two. A shift block follows the last integration stage and can shift the 54 bit accumulated data down by 36-rcic\_shift (a programmable factor from 0 to 31 bits).

The CIC filter exhibits a droop across its frequency response. The following CFIR filter compensates for the CIC droop with a gradually rising frequency response. It is also possible to compensate for CIC droop in the PFIR filter.

The gain of the receive CIC filter is:

$$N_{CIC}^6 * 2^{(\text{number of stages where } M=2)} * 2^{(-36+RCIC\_SHIFT)} \text{ where RCIC\_SHIFT is 0 to 31.}$$

There is no rollover protection internal to the CIC or at the final round so the user must guarantee no sample exceeds full scale prior to rounding. For practical purposes this means the CIC gain can only compensate for peak gain less than one or must be less than or equal to one. A fixed gain of +12 dB at the output of the CIC can also be programmed.

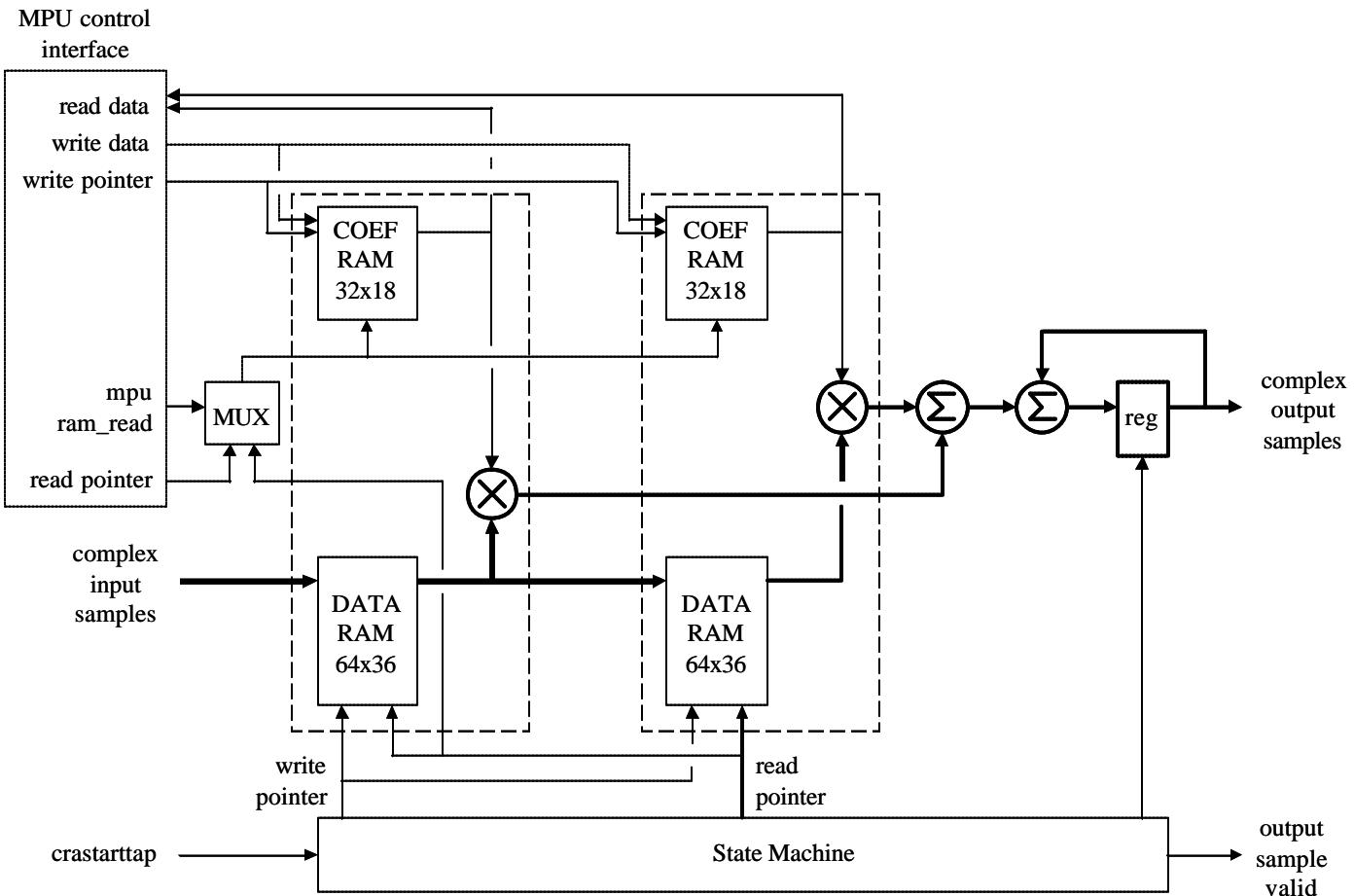
### Programming

Variable	Description
cic_decim(4:0)	The CIC decimation ratio (4 to 32). The ratio is cic_decim + 1. This ratio applies to both A and B channels of the DDC block in CDMA mode.
cic_scale_a(4:0)	The shift value for the A channel. A value of 0 is no shift, each increment in value increases the amplitude of the shifter output by a factor of 2.
cic_scale_b(4:0)	The shift value for the B channel. A value of 0 is no shift, each increment in value increases the amplitude of the shifter output by a factor of 2.
cic_gain_ddc	When asserted, adds a gain of 12 dB at the CIC output.
cic_m2_ena_a(5:0)	Sets the differential delay value M for each of the CIC subtractor stages for the UMTS or CDMA mode A channel.
cic_m2_ena_b (5:0)	Sets the differential delay value M for each of the CIC subtractor stages for the CDMA mode B channel.
cic_bypass	Bypasses the CIC filter when set, for factory use only.
ssel_cic(2:0)	Sets syncing (1 of 8 sources) for the CIC decimation moment.

#### 2.2.7 DDC Compensating FIR Filter

The receive compensating FIR filter (CFIR) decimates the output of the CIC filter by a fixed factor of two. Filter coefficient size, input data size, and output data size are 18 bits. The CFIR length can be programmed. This permits "turning off" taps and saving power if shorter filters are appropriate (the CFIR power dissipation is proportional to its length).

The filter is organized in two partial filter blocks, each containing a data RAM, a coefficient RAM and a dual multiplier, a common state machine and output accumulator.



The maximum CFIR filter length is a function of AFE8406 rxclk clock rate, output sample rate and the number of coefficient memory registers. The maximum number of taps is 64 and the minimum number is 14. Lengths between these limits can be specified in increments of 2.

Subject to the above minimum and maximum values, in the general case, the number of taps available is:

UMTS Mode:  $2 * (\text{rxclk} \div \text{output sample rate})$

CDMA Mode if cic\_decim is even (decimating by an odd number):  $2 * (\text{cic\_decim})$

CDMA Mode if cic\_decim is odd (decimating by an even number):  $2 * (\text{cic\_decim} + 1)$

Example CFIR filter lengths available based on mode and rxclk frequency:

Mode	rxclk (MHz)	CIC decimation	CFIR max length	CFIR min length	comments
UMTS	153.60	10	40	14	UMTS
UMTS	122.88	8	32	14	UMTS
CDMA	157.2864	32	64	14	CDMA2000
CDMA	122.88	25	48	14	CDMA2000
CDMA	78.6432	16	32	14	CDMA2000 low power configuration
CDMA	153.60	30	60	14	TD-SCDMA
CDMA	81.92	16	32	14	TD-SCDMA
CDMA	76.80	15	28	14	TD-SCDMA low power configuration

A single set of programmed tap values are used for both the A-side and B-side DDC channels (two CDMA channels) within a single DDC block when in CDMA mode.

After the CFIR filter performs the convolution, gain is applied at full precision, the signal is rounded, and then hard limited. A shifter at the output of the filter then scales the data by either 2e-19 or 2e-18. The gain through the filter is therefore:

$$\text{Sum(CFIR coefficients)} * 2^{-(18 \text{ or } 19)}$$

Coefficients are organized in two groups of 32 words, each 18 bits wide. For fully utilized filters, the 64 coefficients are loaded 0 through 31 into the first RAM, and 32 through 63 into the second RAM. The 16 bit MSBs and 2 bit LSBs are written into the RAMs using different page register values. Shorter filters require the coefficients be loaded into the 2 rams equally, starting from address 0.

For example, a CFIR coefficient set for a symmetric 58 tap TD-SCDMA CFIR is

taps	Coefficient	taps	Coefficient
0 = 57	-13	15 = 42	-4975
1 = 56	-20	16 = 41	-4649
2 = 55	14	17 = 40	-232
3 = 54	101	18 = 39	6581
4 = 53	184	19 = 38	11266
5 = 52	133	20 = 37	8917
6 = 51	-147	21 = 36	-1957
7 = 50	-562	22 = 35	-16736
8 = 49	-768	23 = 34	-25469
9 = 48	-364	24 = 33	-17599
10 = 47	719	25 = 32	11560
11 = 46	1905	26 = 31	56455
12 = 45	2126	27 = 30	102215
13 = 44	567	28 = 29	131071
14 = 43	-2416		

The first 29 coefficients are loaded into addresses 0 through 28 in the first coefficient RAM, and the remaining 29 are loaded into addresses 0 through 28 in the second coefficient RAM. Loading the 18 bit coefficients requires 2 writes per coefficient, one for the upper 16 bits and another for the lower 2 bits.

To program this coefficient set for the DDC2 CFIR, the following control microprocessor interface sequence would be used.

Step	Address a[5:0]	Data d[15:0]	Description
1	0x21	0x0480	<i>Page register for DDC2 CFIR Coefficient RAM 0-31, LSBs.</i>
2	0x00	0x0003	2 lower bits of coefficient 0
3	0x01	0x0000	2 lower bits of coefficient 1
4	0x02	0x0002	2 lower bits of coefficient 2
5	0x03	0x0001	2 lower bits of coefficient 3
6	0x04	0x0000	2 lower bits of coefficient 4
7	0x05	0x0001	2 lower bits of coefficient 5
8	0x06	0x0001	2 lower bits of coefficient 6
9	0x07	0x0002	2 lower bits of coefficient 7
10	0x08	0x0000	2 lower bits of coefficient 8
11	0x09	0x0000	2 lower bits of coefficient 9
12	0x0A	0x0003	2 lower bits of coefficient 10
13	0x0B	0x0001	2 lower bits of coefficient 11
14	0x0C	0x0002	2 lower bits of coefficient 12
15	0x0D	0x0003	2 lower bits of coefficient 13
16	0x0E	0x0000	2 lower bits of coefficient 14
17	0x0F	0x0001	2 lower bits of coefficient 15
18	0x10	0x0003	2 lower bits of coefficient 16
19	0x11	0x0000	2 lower bits of coefficient 17
20	0x12	0x0001	2 lower bits of coefficient 18
21	0x13	0x0002	2 lower bits of coefficient 19
22	0x14	0x0001	2 lower bits of coefficient 20
23	0x15	0x0003	2 lower bits of coefficient 21
24	0x16	0x0000	2 lower bits of coefficient 22
25	0x17	0x0003	2 lower bits of coefficient 23
26	0x18	0x0001	2 lower bits of coefficient 24
27	0x19	0x0000	2 lower bits of coefficient 25
28	0x1A	0x0003	2 lower bits of coefficient 26
29	0x1B	0x0003	2 lower bits of coefficient 27
30	0x1C	0x0003	2 lower bits of coefficient 28
31	0x1D	0x0000	2 lower bits of unused coefficient RAM location
32	0x1E	0x0000	2 lower bits of unused coefficient RAM location
33	0x1F	0x0000	2 lower bits of unused coefficient RAM location
34	0x21	0x04A0	<i>Page register for DDC2 CFIR Coefficient RAM 32-63, LSBs.</i>
35	0x00	0x0003	2 lower bits of coefficient 29
36	0x01	0x0003	2 lower bits of coefficient 30
37	0x02	0x0003	2 lower bits of coefficient 31
38	0x03	0x0000	2 lower bits of coefficient 32
39	0x04	0x0001	2 lower bits of coefficient 33
40	0x05	0x0003	2 lower bits of coefficient 34
41	0x06	0x0000	2 lower bits of coefficient 35
42	0x07	0x0003	2 lower bits of coefficient 36
43	0x08	0x0001	2 lower bits of coefficient 37
44	0x09	0x0002	2 lower bits of coefficient 38
45	0x0A	0x0001	2 lower bits of coefficient 39
46	0x0B	0x0000	2 lower bits of coefficient 40
47	0x0C	0x0003	2 lower bits of coefficient 41
48	0x0D	0x0001	2 lower bits of coefficient 42
49	0x0E	0x0000	2 lower bits of coefficient 43
50	0x0F	0x0003	2 lower bits of coefficient 44

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51	0x10	0x0002	2 lower bits of coefficient 45
52	0x11	0x0001	2 lower bits of coefficient 46
53	0x12	0x0003	2 lower bits of coefficient 47
54	0x13	0x0000	2 lower bits of coefficient 48
55	0x14	0x0000	2 lower bits of coefficient 49
56	0x15	0x0002	2 lower bits of coefficient 50
57	0x16	0x0001	2 lower bits of coefficient 51
58	0x17	0x0001	2 lower bits of coefficient 52
59	0x18	0x0000	2 lower bits of coefficient 53
60	0x19	0x0001	2 lower bits of coefficient 54
61	0x1A	0x0002	2 lower bits of coefficient 55
62	0x1B	0x0000	2 lower bits of coefficient 56
63	0x1C	0x0003	2 lower bits of coefficient 57
64	0x1D	0x0000	2 lower bits of unused coefficient RAM location
65	0x1E	0x0000	2 lower bits of unused coefficient RAM location
66	0x1F	0x0000	2 lower bits of unused coefficient RAM location
67	0x21	0x04C0	<i>Page register for DDC2 CFIR Coefficient RAM 0-31, MSBs.</i>
68	0x00	0xFFFFC	Upper 16 bits of coefficient 0
69	0x01	0xFFFFB	Upper 16 bits of coefficient 1
70	0x02	0x0003	Upper 16 bits of coefficient 2
71	0x03	0x0019	Upper 16 bits of coefficient 3
72	0x04	0x002E	Upper 16 bits of coefficient 4
73	0x05	0x0021	Upper 16 bits of coefficient 5
74	0x06	0xFFDB	Upper 16 bits of coefficient 6
75	0x07	0xFF73	Upper 16 bits of coefficient 7
76	0x08	0xFF40	Upper 16 bits of coefficient 8
77	0x09	0xFFA5	Upper 16 bits of coefficient 9
78	0x0A	0x00B3	Upper 16 bits of coefficient 10
79	0x0B	0x01DC	Upper 16 bits of coefficient 11
80	0x0C	0x0213	Upper 16 bits of coefficient 12
81	0x0D	0x008D	Upper 16 bits of coefficient 13
82	0x0E	0xFDA4	Upper 16 bits of coefficient 14
83	0x0F	0xFB24	Upper 16 bits of coefficient 15
84	0x10	0xFB75	Upper 16 bits of coefficient 16
85	0x11	0xFFC6	Upper 16 bits of coefficient 17
86	0x12	0x066D	Upper 16 bits of coefficient 18
87	0x13	0x0B00	Upper 16 bits of coefficient 19
88	0x14	0x08B5	Upper 16 bits of coefficient 20
89	0x15	0xFE16	Upper 16 bits of coefficient 21
90	0x16	0xEFA8	Upper 16 bits of coefficient 22
91	0x17	0xE720	Upper 16 bits of coefficient 23
92	0x18	0xEED0	Upper 16 bits of coefficient 24
93	0x19	0x0B4A	Upper 16 bits of coefficient 25
94	0x1A	0x3721	Upper 16 bits of coefficient 26
95	0x1B	0x63D1	Upper 16 bits of coefficient 27
96	0x1C	0x7FFF	Upper 16 bits of coefficient 28
97	0x1D	0x0000	Upper 16 bits of unused coefficient RAM location
98	0x1E	0x0000	Upper 16 bits of unused coefficient RAM location
99	0x1F	0x0000	Upper 16 bits of unused coefficient RAM location
100	0x21	0x04E0	<i>Page register for DDC2 CFIR Coefficient RAM 32-63, MSBs.</i>
101	0x00	0x7FFF	Upper 16 bits of coefficient 29
102	0x01	0x63D1	Upper 16 bits of coefficient 30
103	0x02	0x3721	Upper 16 bits of coefficient 31
104	0x03	0x0B4A	Upper 16 bits of coefficient 32
105	0x04	0xEED0	Upper 16 bits of coefficient 33

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106	0x05	0xE720	Upper 16 bits of coefficient 34
107	0x06	0xEFA8	Upper 16 bits of coefficient 35
108	0x07	0xFE16	Upper 16 bits of coefficient 36
109	0x08	0x08B5	Upper 16 bits of coefficient 37
110	0x09	0x0B00	Upper 16 bits of coefficient 38
111	0x0A	0x066D	Upper 16 bits of coefficient 39
112	0x0B	0xFFC6	Upper 16 bits of coefficient 40
113	0x0C	0xFB75	Upper 16 bits of coefficient 41
114	0x0D	0xFB24	Upper 16 bits of coefficient 42
115	0x0E	0xFDA4	Upper 16 bits of coefficient 43
116	0x0F	0x008D	Upper 16 bits of coefficient 44
117	0x10	0x0213	Upper 16 bits of coefficient 45
118	0x11	0x01DC	Upper 16 bits of coefficient 46
119	0x12	0x00B3	Upper 16 bits of coefficient 47
120	0x13	0xFFA5	Upper 16 bits of coefficient 48
121	0x14	0xFF40	Upper 16 bits of coefficient 49
122	0x15	0xFF73	Upper 16 bits of coefficient 50
123	0x16	0xFFDB	Upper 16 bits of coefficient 51
124	0x17	0x0021	Upper 16 bits of coefficient 52
125	0x18	0x002E	Upper 16 bits of coefficient 53
126	0x19	0x0019	Upper 16 bits of coefficient 54
127	0x1A	0x0003	Upper 16 bits of coefficient 55
128	0x1B	0xFFFFB	Upper 16 bits of coefficient 56
129	0x1C	0xFFFFC	Upper 16 bits of coefficient 57
130	0x1D	0x0000	Upper 16 bits of unused coefficient RAM location
131	0x1E	0x0000	Upper 16 bits of unused coefficient RAM location
132	0x1F	0x0000	Upper 16 bits of unused coefficient RAM location
133	0x21	0x0500	<i>Page register for DDC2 control registers 0-31</i>
134	0x00	0x8EE0	DDC2 FIR_MODE register; cdma_mode enabled, 60 tap PFIR, 58 tap CFIR
135	0x01	0x2000	DDC2 PFIR gain = sum(taps)*2^-18 and CFIR gain = sum(taps)*2^-19

### Programming

Variable	Description
crastarttap_cfir(4:0)	Number of DDC CFIR filter taps is $2^*(\text{crastarttap} + 1)$
mpu_ram_read	What set, the PFIR and CFIR coefficient rams are readable via the MPU control interface. <i>The AFE8406 signal path is not operational when this bit is set, it is intended for debug purposes only.</i>
cfir_gain	$0 = 2^{-19}, 1 = 2^{-18}$

The CFIR filter's 18 bit coefficients are loaded in two 32 word memories.

**Note:** CFIR filter coefficients are shared between A and B channels of a DDC block in CDMA mode.

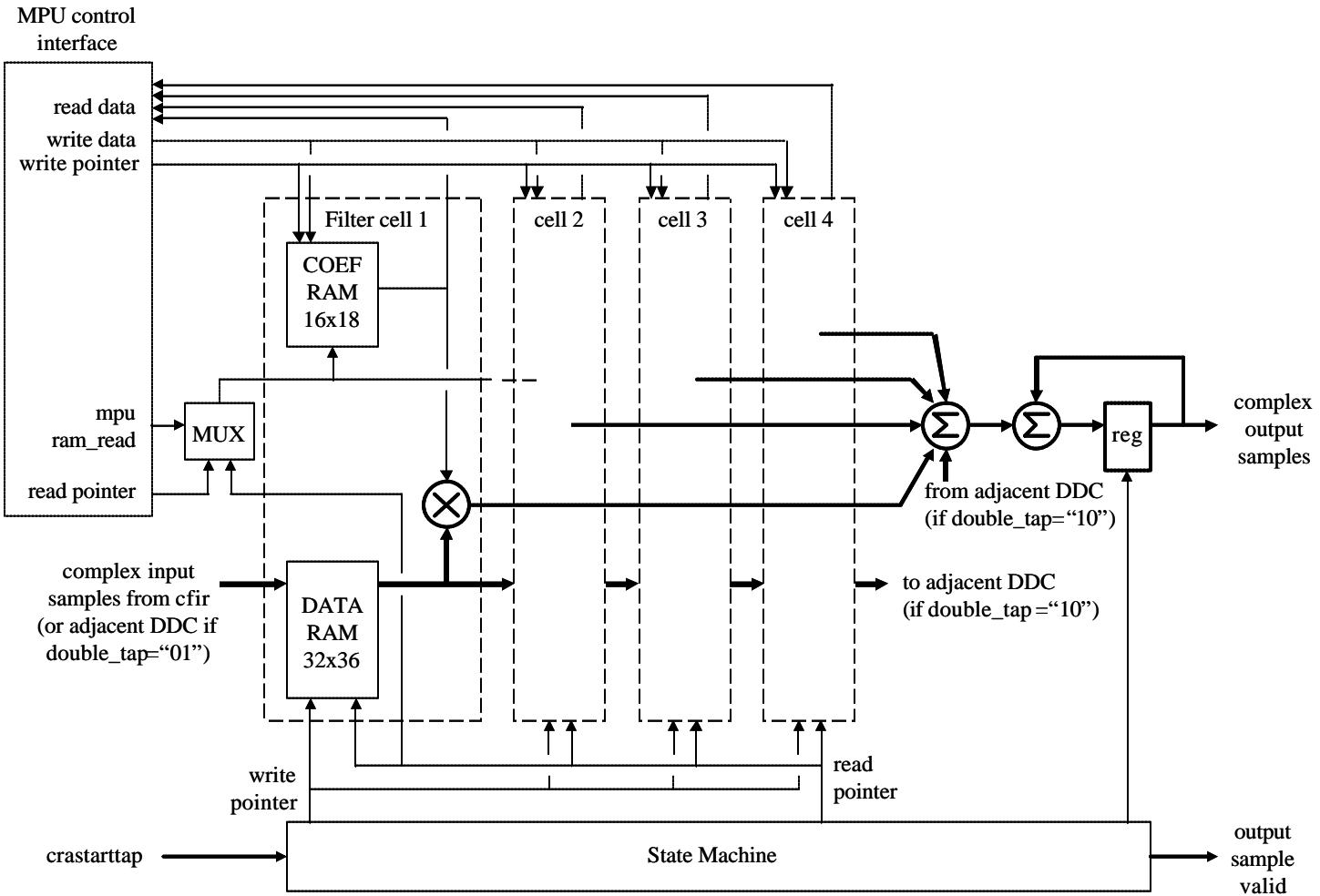
### 2.2.8 DDC Programmable FIR Filter

The receive programmable FIR filter (PFIR) provides final pulse shaping of the baseband signal data. It does not perform any decimation. Filter coefficient size, input, and output data size is 18 bits. A special strapped mode can be employed for UMTS where two adjacent DDCs (2k & 2k+1, k=0 to 3) can be

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combined to yield a filter with twice the number of coefficients. This means the AFE8406 can support 4 UMTS DDC channels with double-length filter coefficients (up to 128 taps).

The filter is organized in four partial filter blocks, each containing a data RAM, a coefficient RAM and a dual multiplier, a common state machine and output accumulator.



The PFIR length is programmable. This permits turning off taps and saving power if short filters are appropriate. The filter's output data can be shifted over a range of 0 to 7 bits where it is then rounded and hard limited to 18 bits. The shift range results in a gain that ranges from 2e-19 to 2e-12.

The gain of the PFIR block is:  $\text{sum(coefficients)} * 2^{\text{shift}}$ , where shift ranges from 12 to 19.

The maximum PFIR filter length is a function of AFE8406 clock rate and output sample rate and is limited by the number of coefficient memory registers. The maximum number of taps is 64 and the minimum number is 32 (for both CDMA and UMTS). Lengths between these limits can be specified in increments of 4. For strapped UMTS with double length filters, the range of taps available is 64 to 128 in increments of 8

Subject to the above minimum and maximum values, the number of maximum taps available is:

UMTS Mode:  $4 * (\text{rxclk} \div \text{output sample rate})$

Strapped UMTS Mode:  $8 * (\text{rxclk} \div \text{output sample rate})$

CDMA Mode:  $2 * (\text{rxclk} \div \text{output sample rate})$

PFIR coefficients and gain shift values are shared between both A and B CDMA channels in a DDC block.

Example PFIR filter lengths available based on mode and rxclk frequency:

Mode	rxclk (MHz)	CIC decimation	PFIR max length	PFIR min length	comments
UMTS	153.60	10	64	32	UMTS, 1 to 8 DDC channels
UMTS	122.88	8	64	32	UMTS, 1 to 8 DDC channels
UMTS	153.60	10	128	64	Strapped UMTS double length PFIR configuration; 1 to 4 DDC channels.
UMTS	122.88	8	128	64	Strapped UMTS double length PFIR configuration; 1 to 4 DDC channels.
CDMA	157.2864	32	64	32	CDMA2000
CDMA	122.88	25	64	32	CDMA2000
CDMA	78.6432	16	64	32	CDMA2000 low power configuration
CDMA	153.60	30	64	32	TD-SCDMA
CDMA	81.92	16	64	32	TD-SCDMA
CDMA	76.80	15	60	32	TD-SCDMA low power configuration

Coefficients are organized in four groups of 16 words, each 18 bits wide. For fully utilized filters, the 64 coefficients are loaded 0 through 31 into the first and second RAMs, and 32 through 63 into the third and fourth RAMs. The 16 bit MSBs and 2 bit LSBs are written into the RAMs using different page register values. Shorter filters require the coefficients be loaded into the 4 rams equally, starting from address 0 and address 16.

For example, a PFIR coefficient set for a symmetric 60 tap TD-SCDMA PFIR is

taps	Coefficient	taps	Coefficient
0 = 59	-2	15 = 44	420
1 = 58	1	16 = 43	-331
2 = 57	4	17 = 42	-319
3 = 56	-8	18 = 41	744
4 = 55	-2	19 = 40	-440
5 = 54	21	20 = 39	-1005
6 = 53	-13	21 = 38	2389
7 = 52	-28	22 = 37	514
8 = 51	46	23 = 36	-6182
9 = 50	1	24 = 35	1845
10 = 49	-85	25 = 34	12959
11 = 48	96	26 = 33	-8691
12 = 47	82	27 = 32	-27246
13 = 46	-266	28 = 31	34166
14 = 45	38	29 = 30	131071

The first 15 coefficients are loaded into addresses 0 through 14 in the first coefficient RAM, the second group of 15 are loaded into addresses 16 through 30 corresponding to the second coefficient RAM, the third group of 15 are loaded into the third coefficient ram at addresses 0 through 14, and the fourth group of 15 are loaded into addresses 16 through 30 in the fourth coefficient RAM. Loading the 18 bit coefficients requires 2 writes per coefficient, one for the upper 16 bits and another for the lower 2 bits.

To program this coefficient set for the DDC2 PFIR, the following control microprocessor interface sequence would be used.

Step	Address a[5:0]	Data d[15:0]	Description
1	0x21	0x0400	<i>Page register for DDC2 PFIR Coefficient RAMs 0-15 and 16-31, LSBs.</i>
2	0x00	0x0002	2 lower bits of coefficient 0
3	0x01	0x0001	2 lower bits of coefficient 1
4	0x02	0x0000	2 lower bits of coefficient 2
5	0x03	0x0000	2 lower bits of coefficient 3
6	0x04	0x0002	2 lower bits of coefficient 4
7	0x05	0x0001	2 lower bits of coefficient 5
8	0x06	0x0003	2 lower bits of coefficient 6
9	0x07	0x0000	2 lower bits of coefficient 7
10	0x08	0x0002	2 lower bits of coefficient 8
11	0x09	0x0001	2 lower bits of coefficient 9
12	0x0A	0x0003	2 lower bits of coefficient 10
13	0x0B	0x0000	2 lower bits of coefficient 11
14	0x0C	0x0002	2 lower bits of coefficient 12
15	0x0D	0x0002	2 lower bits of coefficient 13
16	0x0E	0x0002	2 lower bits of coefficient 14
17	0x0F	0x0000	2 lower bits of unused coefficient RAM location
18	0x10	0x0000	2 lower bits of coefficient 15
19	0x11	0x0001	2 lower bits of coefficient 16
20	0x12	0x0001	2 lower bits of coefficient 17
21	0x13	0x0000	2 lower bits of coefficient 18
22	0x14	0x0000	2 lower bits of coefficient 19
23	0x15	0x0003	2 lower bits of coefficient 20
24	0x16	0x0001	2 lower bits of coefficient 21
25	0x17	0x0002	2 lower bits of coefficient 22
26	0x18	0x0002	2 lower bits of coefficient 23
27	0x19	0x0001	2 lower bits of coefficient 24
28	0x1A	0x0003	2 lower bits of coefficient 25
29	0x1B	0x0001	2 lower bits of coefficient 26
30	0x1C	0x0002	2 lower bits of coefficient 27
31	0x1D	0x0002	2 lower bits of coefficient 28
32	0x1E	0x0003	2 lower bits of coefficient 29
33	0x1F	0x0000	2 lower bits of unused coefficient RAM location
34	0x21	0x0420	<i>Page register for DDC2 PFIR Coefficient RAMs 32-47 and 48-63, LSBs.</i>
35	0x00	0x0003	2 lower bits of coefficient 30
36	0x01	0x0002	2 lower bits of coefficient 31
37	0x02	0x0002	2 lower bits of coefficient 32
38	0x03	0x0001	2 lower bits of coefficient 33
39	0x04	0x0003	2 lower bits of coefficient 34
40	0x05	0x0001	2 lower bits of coefficient 35
41	0x06	0x0002	2 lower bits of coefficient 36
42	0x07	0x0002	2 lower bits of coefficient 37
43	0x08	0x0001	2 lower bits of coefficient 38

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44	0x09	0x0003	2 lower bits of coefficient 39
45	0x0A	0x0000	2 lower bits of coefficient 40
46	0x0B	0x0000	2 lower bits of coefficient 41
47	0x0C	0x0001	2 lower bits of coefficient 42
48	0x0D	0x0001	2 lower bits of coefficient 43
49	0x0E	0x0000	2 lower bits of coefficient 44
50	0x0F	0x0000	2 lower bits of unused coefficient RAM location
51	0x10	0x0002	2 lower bits of coefficient 45
52	0x11	0x0002	2 lower bits of coefficient 46
53	0x12	0x0002	2 lower bits of coefficient 47
54	0x13	0x0000	2 lower bits of coefficient 48
55	0x14	0x0003	2 lower bits of coefficient 49
56	0x15	0x0001	2 lower bits of coefficient 50
57	0x16	0x0002	2 lower bits of coefficient 51
58	0x17	0x0000	2 lower bits of coefficient 52
59	0x18	0x0003	2 lower bits of coefficient 53
60	0x19	0x0001	2 lower bits of coefficient 54
61	0x1A	0x0002	2 lower bits of coefficient 55
62	0x1B	0x0000	2 lower bits of coefficient 56
63	0x1C	0x0000	2 lower bits of coefficient 57
64	0x1D	0x0001	2 lower bits of coefficient 58
65	0x1E	0x0002	2 lower bits of coefficient 59
66	0x1F	0x0000	2 lower bits of unused coefficient RAM location
67	0x21	0x0440	<i>Page register for DDC2 PFIR Coefficient RAMs 0-15 and 16-31, MSBs.</i>
68	0x00	0xFFFF	Upper 16 bits of coefficient 0
69	0x01	0x0000	Upper 16 bits of coefficient 1
70	0x02	0x0001	Upper 16 bits of coefficient 2
71	0x03	0xFFFFE	Upper 16 bits of coefficient 3
72	0x04	0xFFFF	Upper 16 bits of coefficient 4
73	0x05	0x0005	Upper 16 bits of coefficient 5
74	0x06	0xFFFFC	Upper 16 bits of coefficient 6
75	0x07	0xFFFF9	Upper 16 bits of coefficient 7
76	0x08	0x000B	Upper 16 bits of coefficient 8
77	0x09	0x0000	Upper 16 bits of coefficient 9
78	0x0A	0xFFEA	Upper 16 bits of coefficient 10
79	0x0B	0x0018	Upper 16 bits of coefficient 11
80	0x0C	0x0014	Upper 16 bits of coefficient 12
81	0x0D	0xFFBD	Upper 16 bits of coefficient 13
82	0x0E	0x0009	Upper 16 bits of coefficient 14
83	0x0F	0x0000	Upper 16 bits of unused coefficient RAM location
84	0x10	0x0069	Upper 16 bits of coefficient 15
85	0x11	0xFFAD	Upper 16 bits of coefficient 16
86	0x12	0xFFB0	Upper 16 bits of coefficient 17
87	0x13	0x00BA	Upper 16 bits of coefficient 18
88	0x14	0xFF92	Upper 16 bits of coefficient 19
89	0x15	0xFF04	Upper 16 bits of coefficient 20
90	0x16	0x0255	Upper 16 bits of coefficient 21
91	0x17	0x0080	Upper 16 bits of coefficient 22
92	0x18	0xF9F6	Upper 16 bits of coefficient 23
93	0x19	0x01CD	Upper 16 bits of coefficient 24
94	0x1A	0x0CA7	Upper 16 bits of coefficient 25
95	0x1B	0xF783	Upper 16 bits of coefficient 26
96	0x1C	0xE564	Upper 16 bits of coefficient 27
97	0x1D	0x215D	Upper 16 bits of coefficient 28
98	0x1E	0x7FFF	Upper 16 bits of coefficient 29

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99	0x1F	0x0000	Upper 16 bits of unused coefficient RAM location
100	0x21	0x0460	<i>Page register for DDC2 PFIR Coefficient RAMs 32-47 and 48-63, MSBs.</i>
101	0x00	0x7FFF	Upper 16 bits of coefficient 30
102	0x01	0x215D	Upper 16 bits of coefficient 31
103	0x02	0xE564	Upper 16 bits of coefficient 32
104	0x03	0xF783	Upper 16 bits of coefficient 33
105	0x04	0x0CA7	Upper 16 bits of coefficient 34
106	0x05	0x01CD	Upper 16 bits of coefficient 35
107	0x06	0xF9F6	Upper 16 bits of coefficient 36
108	0x07	0x0080	Upper 16 bits of coefficient 37
109	0x08	0x0255	Upper 16 bits of coefficient 38
110	0x09	0xFF04	Upper 16 bits of coefficient 39
111	0x0A	0xFF92	Upper 16 bits of coefficient 40
112	0x0B	0x00BA	Upper 16 bits of coefficient 41
113	0x0C	0xFFB0	Upper 16 bits of coefficient 42
114	0x0D	0xFFAD	Upper 16 bits of coefficient 43
115	0x0E	0x0069	Upper 16 bits of coefficient 44
116	0x0F	0x008D	Upper 16 bits of unused coefficient RAM location
117	0x10	0x0009	Upper 16 bits of coefficient 45
118	0x11	0xFFBD	Upper 16 bits of coefficient 46
119	0x12	0x0014	Upper 16 bits of coefficient 47
120	0x13	0x0018	Upper 16 bits of coefficient 48
121	0x14	0xFFEA	Upper 16 bits of coefficient 49
122	0x15	0x0000	Upper 16 bits of coefficient 50
123	0x16	0x000B	Upper 16 bits of coefficient 51
124	0x17	0xFFFF9	Upper 16 bits of coefficient 52
125	0x18	0xFFFFC	Upper 16 bits of coefficient 53
126	0x19	0x0005	Upper 16 bits of coefficient 54
127	0x1A	0xFFFF	Upper 16 bits of coefficient 55
128	0x1B	0xFFFFE	Upper 16 bits of coefficient 56
129	0x1C	0x0001	Upper 16 bits of coefficient 57
130	0x1D	0x0000	Upper 16 bits of coefficient 58
131	0x1E	0xFFFF	Upper 16 bits of coefficient 59
132	0x1F	0x0000	Upper 16 bits of unused coefficient RAM location
133	0x21	0x0500	<i>Page register for DDC2 control registers 0-31</i>
134	0x00	0x8EE0	DDC2 FIR_MODE register; cdma_mode enabled, 60 tap PFIR, 58 tap CFIR
135	0x01	0x2000	DDC2 PFIR gain = sum(taps)*2^18 and CFIR gain = sum(taps)*2^19

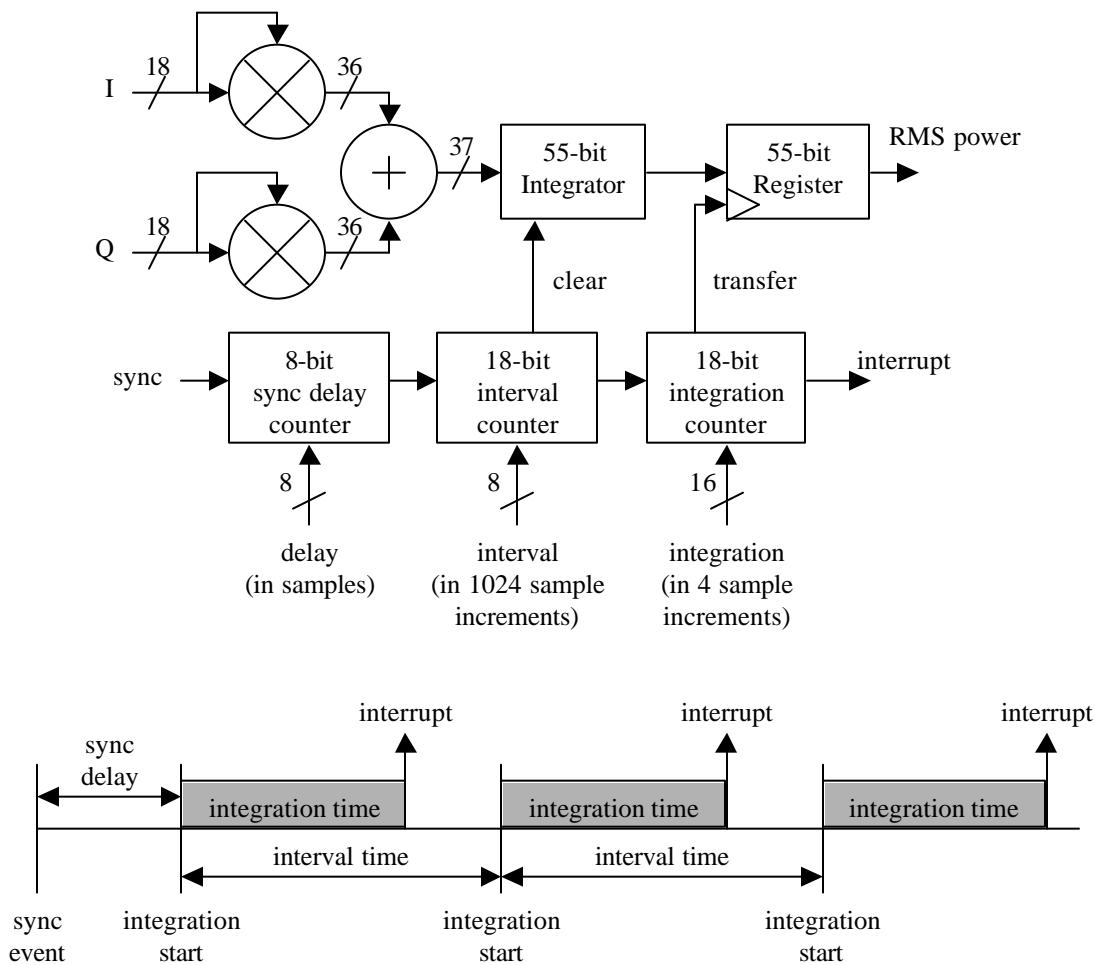
**Programming**

Variable	Description
crastarttap_pfir(4:0)	Number of DDC PFIR filter taps is 4*(crastarttap+1) For double length PFIR the number of taps is 8*(crastarttap+1)
cdma_mode	When set, puts the CFIR & PFIR blocks in CDMA mode.
mpu_ram_read	When set, the PFIR and CFIR coefficient rams are readable via the MPU control interface. <i>The AFE8406 signal path is not operational when this bit is set, it is intended for debug purposes only.</i>
pfir_gain(2:0)	Sets the gain of the PFIR filter. The range is from $2e^{-19}$ to $2e^{-12}$ , "000" = $2e^{-19}$ and "111" = $2e^{-12}$
double_tap(1:0)	When set, puts two adjacent DDC (2k & 2k+1, k=0 to 3) in double length (from 64 to 128 tap) UMTS mode.  Set to "00" for normal mode.  In double tap mode, data out of the last PFIR ram in the main DDC (DDC0, DDC2, DDC4 or DDC6) is sent to the adjacent secondary DDC (DDC1, DDC3, DDC5 or DDC7) PFIR as input thus forming a 128-tap delay line. Data received from the adjacent PFIR summers is added into the Main DDC's PFIR sum to form the final output.  When using double tap mode, set double_tap to "10" for the main DDC, and to "01" for the secondary DDC.  When in double tap mode, the first half of the coefficients should be loaded into the main DDC (DDC0, DDC2, DDC4 or DDC6), the remaining coefficients are loaded into the secondary DDC (DDC1, DDC3, DDC5 or DDC7).  <u><i>In double tap mode, the main DDC must be turned on (ddc_ena=1), and the secondary DDC must be turned off (ddc_ena=0).</i></u>

The PFIR filter's 18 bit coefficients are loaded in four 16 word memories.

**Note:** PFIR filter coefficients are shared between A and B channels of a DDC block when in CDMA mode.

## 2.2.9 DDC RMS Power Meter



Each DDC channel includes an RMS power meter which is used to measure the total power within the channel pass band.

The power meter samples the I and Q data stream after the PFIR filter. Both 18 bit I and Q data are squared, summed, and then integrated over a period determined by a programmable counter. The integration time is a 16 bit word which is programmed into the 18 bit counter.

There is a programmable 18 bit interval timer which sets the interval over which power measurements are made. The timer counts in increments of 1024 samples. This allows the user to select intervals from 1 x 1024 samples up to 256 x 1024 samples. For UMTS systems with sample rate rate at 7.68MHz, the power meter interval range is from 133uS to 34.1mS. For a CDMA system with the sample rate at 2.4576MHz, the power meter interval range is 417uS to 107mS.

The power measurement process starts with a sync event. The integration will start at sync event + 3 chips + sync\_delay. The 8 bit delay register permits delays from 1 to 256 samples after sync. The integration will continue until the integration count is met. At that point, the result in the 55 bit accumulator is transferred to the read holding register and an interrupt is generated indicating the power value is ready to read. The interval counter continues until the programmed interval count is reached. When reached, the integration counter and the interval counter start over again. Each time the integration count is reached, the 55 result bits are again transferred to the read register overwriting the previous value and an interrupt is generated signifying the data is ready to be read. Failure to read the data timely will result in overwriting the previous interval measurement.

Sync starts the process. Whenever a sync is received, all the counters are reset to zero no matter what the status.

For UMTS, I and Q are calculated and the integrated power is read. When in CDMA mode the power is calculated for both the A ( Signal ) path and the B ( Diversity) signal. As a result, there are two 55-bit words representing the Signal and Diversity when in CDMA mode.

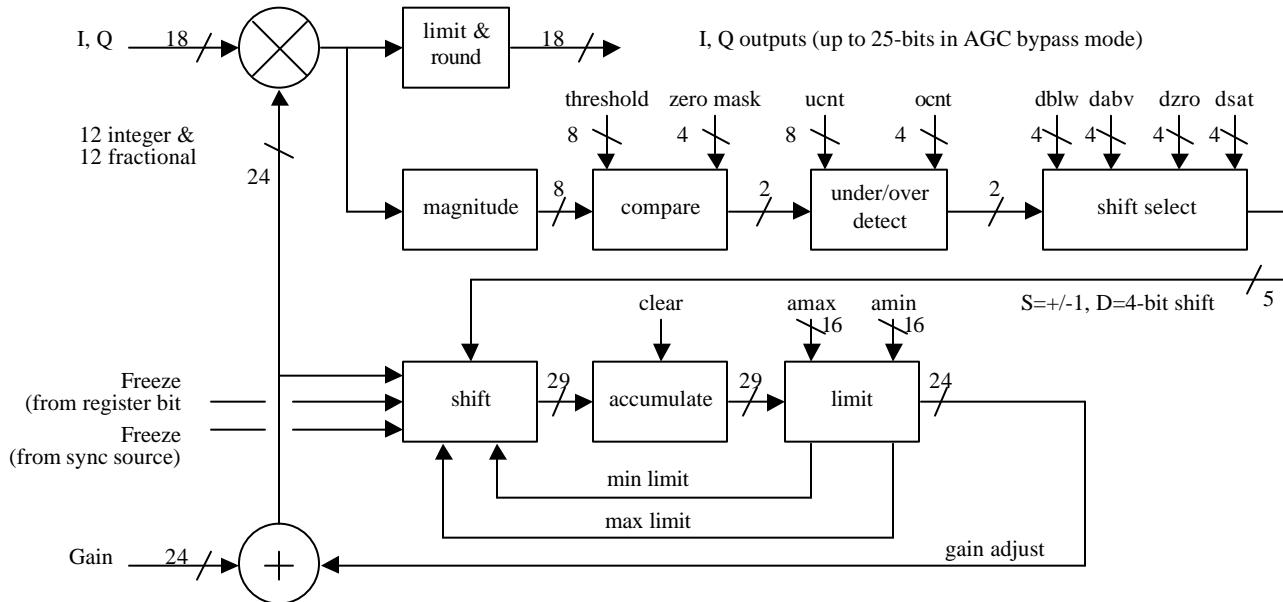
The power read is:

$$\text{power} = [ (I^2 + Q^2) * (X^4 + 1) ] \quad \text{where X is the integration count.}$$

### Programming

Variable	Description
pmeter_result_a(54:0)	55 bit UMTS or CDMA mode A channel power measurement result.
pmeter_result_b(54:0)	55 bit CDMA mode B channel power measurement result.
pmeter_sqr_sum_ddc(15:0)	Integration (square and sum) count in increments of four samples.
pmeter_sync_delay_ddc(7:0)	Sync delay count in samples.
pmeter_interval_ddc(7:0)	The measurement interval in increments of 2048 samples. This value must be greater than SQR_SUM.
ssel_pmeter(2:0)	Sync source selection.
pmeter_sync_disable	Turns off the sync to the channel power meter. This can be used to individually turn off syncs to a channels power meter while still having syncs to other power meters on the chip.

## 2.2.10 DDC AGC



The AFE8406 automatic gain control circuit is shown above. The basic operation of the circuit is to multiply the 18 bit input data from the PFIR by a 24-bit gain word that represents a gain or attenuation in the range of 0 to 4096. The gain format is mixed integer and fraction. The 12-bit integer allows the gain to be boosted by up to factor of 4096 (72 dB). The 12-bit fractional part allows the gain to be adjusted up or down in steps of one part in 4096, or approximately 0.002 dB. If the integer portion is zero, then the circuit attenuates the signal. The gain adjusted output data is saturated to full scale and then rounded to between 4 and 18 bits in steps of one bit.

The AGC portion of the circuit is used to automatically adjust the gain so that the "median" magnitude of the output data matches a target value, which is performed by comparing the magnitude of the output data with a target threshold. If the magnitude is greater than the threshold, then the gain is decreased, otherwise it is increased. The gain is adjusted as:  $G(t) = G + A(t)$ , where  $G$  is the default, user supplied gain value, and  $A(t)$  is the time varying adjustment.  $A(t)$  is updated as  $A(t) = A(t) + G(t)*S*2^D$ , where  $S=1$  if the magnitude is less than the threshold and is -1 if the magnitude exceeds the threshold, and where  $D$  sets the adjustment step size. Note that the adjustment is a fraction of the current gain. This is designed to set the AGC noise level to a known and acceptable level while keeping the AGC convergence and tracking rate constant, independent of the gain level. The AGC noise will be equal to  $\pm 2^D$  and the AGC attack and decay rate will be exponential, with a time constant equal to  $2^D$ . Hence, the AGC will increase or decrease by 0.63 times  $G(t)$  in  $2^D$  updates.

If one assumes the data is random with a Gaussian distribution, which is valid for UMTS if more than 12 users with different codes have been overlaid, then the relationship between the RMS level and the median is  $\text{MEDIAN} = 0.6745*\text{RMS}$ , hence the threshold should be set to 0.6745 times the desired RMS level.

The gain step size can be set using four different values of "D", each of which is a 4 bit integer. D can range from 3 to 18. The user can specify values of D for different situations, ie, when the signal magnitude

is below the user-specified threshold (Dblw), is above the threshold (Dabv), is consistently equal to zero (Dzro) or is consistently equal to maximum (Dsat). It is important to note that D represents a gain step size. Smaller values of D represent larger gain steps. The definition of “equal to zero” is any number when masked by zero\_mask is considered to be zero. This permits consistently very small amplitude signals to have their gain increased rapidly.

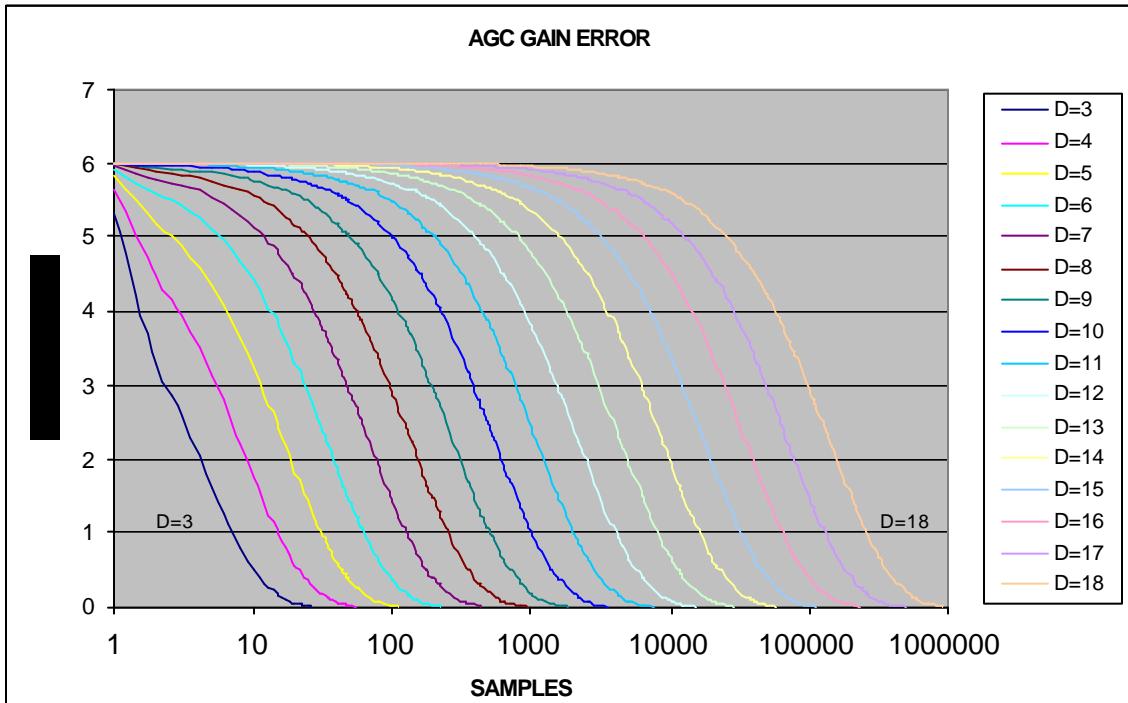
Separate programmable D values allow the user to set different attack and decay time constants, and to set shorter time constants for when the signal falls too low (equal to zero), or is too high (saturates). The magnitude is considered to be consistently equal to zero by using a 4-bit counter that counts up every time the 8-bit magnitude value is zero, and counts down otherwise. If the counter’s value exceeds a user specified threshold, then “Dabv” is used. Similarly the magnitude is considered too high by using a counter that counts up when the magnitude is maximum, and counts down otherwise. If this counter exceeds another user specified threshold, then “Dsat” is used.

As an example, if the AGC’s current gain at a particular moment in time is 5.123, and the magnitude of the signal is greater than zero, but less than the user-programmed threshold. Step size Dblw will be used to modify the gain for the next sample. This represents the AGC attack profile. If Dblw is set to a value of 5, then the gain for the next sample will be  $5.123 + 5.123 \times 2^5 = 5.123 + 0.160 = 5.283$ . If the signal’s magnitude is still less than the user-programmed threshold, then the gain for the next sample will be  $5.283 + 5.283 \times 2^5 = 5.283 + 0.165 = 5.448$ . This continues until the signal’s magnitude exceeds the user-programmed threshold. When the magnitude exceeds threshold (but is not saturated), then step size Dabv is automatically employed as a size rather than Dblw.

The AGC converges linearly in dB with a step size of  $40\log(1+2^D)$  when the error is greater than 12 dB (I.E. the gain is off by 12 dB or more). Within 6dB the behavior is approximately a exponential decay with a time constant of  $2^{D-0.5}$  samples.

The suggested value of D is 5 or 6 when the error is greater than 12dB (i.e., in the fast range detected by consistently zero or saturated data). This gives a step size of 0.5 or 0.25 dB per sample.

The suggested value when the gain is off by less than 12dB is D=10, giving a exponential time constant for delay of around 724 samples (63% decay every 724 samples).



The AGC noise once the AGC has converged is a random error of amplitude  $\pm 2^{-D}$  relative to the RMS signal level. This means that the error level is  $-6^*D$  dB below the signal RMS level. At D=10 (60dB) the error is negligible. The plot above shows the AGC response for values of D ranging from 3 to 18. "Error dB" represents the distance the signal level is from the desired target threshold.

The AGC is also subject to user specified upper and lower adjustment limits. The AGC stops incrementing the gain if the adjustment exceeds Amax. It stops decrementing the gain if the adjustment is less than Amin.

The input data is received with a valid flag that is high when a valid sample is received. For complex data the I and Q samples are on the same data input line and are not treated independently. An adjustment is made for the magnitude of the I sample, and then another adjustment is made for the Q sample.

The AGC operates on UMTS and CDMA data. When in UMTS mode the I and Q data are each used to produce the AGC level. There is no separate I path gain and Q path gain. When in CDMA mode there are separate gain levels for the Signal and Diversity I and Q data. The I and Q for A (or the Signal) pair is calculated and then the I' and Q' for the B (or Diversity) pair is calculated.

There is a freeze mode for holding the accumulator at its current level. This will put the AGC in a hold mode using the user-programmed gain along with the current gain\_adjust value. To only use the user programmed gain value as the gain, set the freeze bit and then clear the accumulator. When using the freeze bit the full 25 bit output is sent out of the AGC block to support transferring up to 25 bits when the AGC is disabled.

For TDD applications, freeze mode can be controlled using a sync source. This allows rxsync\_a/b/c/d to be assigned as a AGC hold signal to keep the AGC from responding during the transmit interval and run during the receive interval. The freeze register bit is logically Ored with the freeze sync source.

The current AGC gain and state can also be optionally output with the DDCs I and Q output data by setting the gain\_mon variable. When in this mode, the top 14 bits of the current AGC gain word are appended to the 8 bit AGC-modified I and Q output data.

Output	Bits(17:10)	Bits(9:4)	Bits(3:2)	Bits(1:0)
I	I output data		Gain(23:16)	"00"
Q	Q output data		Gain(15:10)	AGC State(1:0)

### Programming

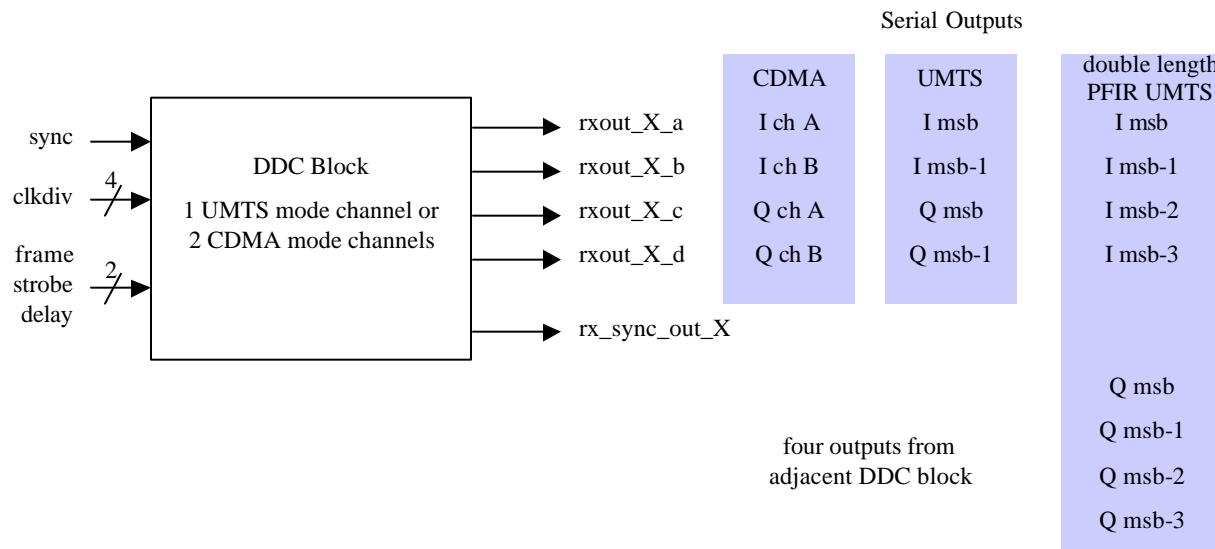
Variable	Description
agc_dblw(3:0)	<b>Below</b> threshold gain. Sets the value of gain step size Dblw (data * current gain below threshold). Ranges from 3 to 18, and maps to a 4 bit field. For example: 3 = "0000", 4= "0001", ... 18= "1111"
agc_dabv(3:0)	<b>Above</b> threshold gain. Sets the value of gain step size Dabv (data * current gain above threshold). Ranges from 3 to 18, and maps to a 4 bit field. For example: 3 = "0000", 4= "0001", ... 18= "1111"
agc_dzro(3:0)	<b>Zero</b> signal gain. Sets the value of gain step size Dzro (data * current gain consistently zero). Ranges from 3 to 18, and maps to a 4 bit field. For example: 3 = "0000", 4= "0001", ... 18= "1111"
agc_dsat (3:0)	<b>Saturated</b> signal gain. Sets the value of gain step size Dsat (data * current gain consistently saturated). Ranges from 3 to 18, and maps to a 4 bit field. For example: 3 = "0000", 4= "0001", ... 18= "1111"
agc_zero_msk(3:0)	Masks the lower 4 bits of signal data so as to be considered zeros.
agc_md(3:0)	AGC rounding. 0000= 18 bits out, 1111= 3 bits out.
agc_thresh(7:0)	AGC threshold. Compared with magnitude of 8 bits of input * gain.
agc_rnd_disable	AGC rounding is disabled when this bit is set.
agc_freeze	The AGC gain adjustment updates are disable when set.
agc_clear	The AGC gain adjustment accumulator is cleared when set
agc_gaina(23:0)	24 bit gain word for DDC A
agc_gainb(23:0)	24 bit gain word for DDC B (in CDMA mode)
agc_zero_cnt(3:0)	When the AGC output (input * gain) is zero value this number of times, the shift value is changed to agc_dzero.
agc_max_cnt(3:0)	When the AGC output (input * gain) is zero value this number of times, the shift value is changed to agc_dsat.
agc_amax(15:0)	The maximum value that gain can be adjusted up to. Top 12 bits are integer, bottom 4 bits are fractional.
agc_amin(15:0)	The minimum value that gain can be adjusted down to. Top 12 bits are integer, bottom 4 bits are fractional.
gain_mon	When set, combines current AGC gain with I and Q data. The 18 bit output format thus becomes:  I Portion: 8 bits of AGC'd I data - Gain(23:16) - 00 Q Portion: 8 bits of AGC'd Q data - Gain(15:10) - Status(1:0) - 00.  Note: Bit 0 of Status, when set, indicates the data is saturated. Bit 1 of Status, when set, indicates the data is zero.
ssel_agc_freeze(2:0)	Sync selection for freeze mode, 1 of 8 sources. This source is ORed with the freeze register bit
ssel_gain(2:0)	Sync selection for the double buffered agc_gaina and agc_gainb register.
ssel_ddc_agc(2:0)	Sync selection used to initialize the AGC, primarily for test purposes.

### 2.2.11 DDC Output Interface

The baseband I/Q sample interface can be configured as serial or parallel formatted data. The serial interface closely matches the GC5316 style interface. The parallel interface is provided to interface directly to the TMS320TCI110 when delayed antenna streams used to implement channel estimation buffering and/or transport format combination indicator (TFCI) buffering are not required.

The DDC output data is 2's complement format.

#### 2.2.11.1 Serial Output Interface



Each DDC block can be assigned four serial output data pins. These pins are used to transfer downconverted I/Q baseband data out of the AFE8406 for subsequent processing. The usage of these pins changes depending on how the DDC block is configured.

When the block is configured for two CDMA channels, a pair of serial data pins provides separate I and Q data output for the two DDC channels. Word size is selectable from 4 to 25 bits with the most significant bit first.

When the DDC block is configured for a single UMTS channel, even and odd I and Q data drive the four serial pins separately, most significant bit first.

Four serial pins each for I and Q data can be optionally employed (instead of two for I and two for Q) at half the output rate. This would most likely be used when two DDC channels ( $2k$  &  $2k + 1$ ,  $k = 0$  to  $3$ ) are combined to support double-length PFIR filtering (a channel is sacrificed). Formatting for I data is then: Imsb, Imsb-1, Imsb-2, Imsb-3. Q data formatting is: Qmsb, Qmsb-1, Qmsb-2, Qmsb-3.

The frame strobe signal provided on the rx\_sync\_out\_X pins can be programmed to arrive from 0 to 3 bit clocks early via a 2 bit control parameter. The frame interval can be programmed from 1 to 63 bits. A

programmable 4bit clock divider circuit is used to specify the serial bit rate. The clock divider circuit is synchronized using a sync block discussed later in this document.

Programming the serial port clock divider requires some thought and depends upon the channel's overall decimation ratio, frame sync interval, number of output bits, and CDMA-UMTS mode.

In general:

$$\text{the serial clock divide ratio} * \text{the frame sync interval} = \text{the total receive decimation}$$

The relationship between the number of serial bits output, clock divide ratio, and overall decimation ratio is:

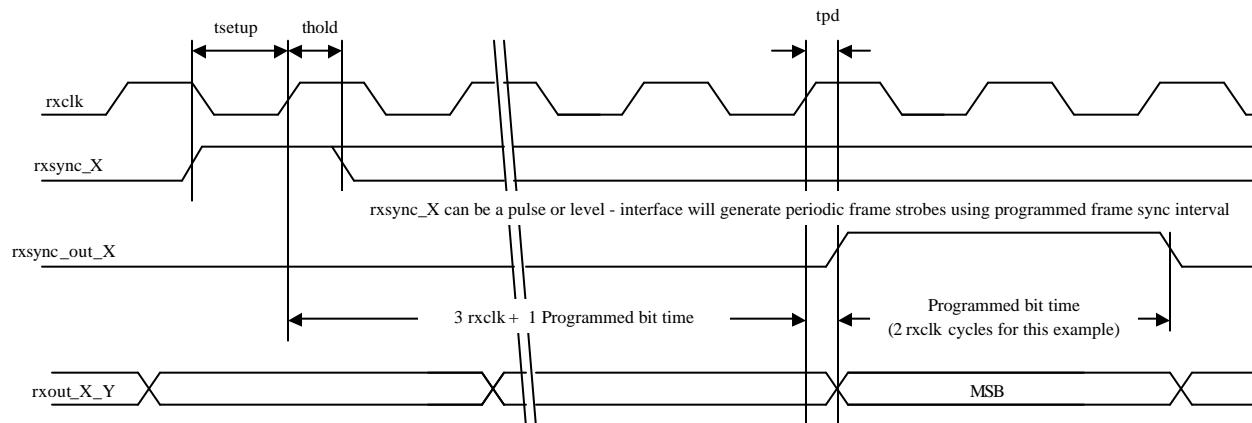
$$\text{CDMA: } [\text{overall decimation} * (\text{pser\_recv\_8pin} + 1)] / (\text{pser\_recv\_clkdiv} + 1) > \text{pser\_recv\_bits} + 1$$

$$\text{UMTS: } 2 * [\text{overall decimation} * (\text{pser\_recv\_8pin} + 1)] / (\text{pser\_recv\_clkdiv} + 1) > \text{pser\_recv\_bits} + 1$$

$$\text{where overall decimation} = \text{CIC decimation} * \text{CFIR decimation}$$

Decimation by 2 in the output interface can be achieved by setting the frame strobe interval and clock divider to 1/2 the PFIR output rate. The serial interface samples the PFIR output each time the transfer interval defined by these two settings has completed. The decimation moment can be controlled using the rxsync\_X input signal selected as the sync source for the serial interface.

The timing diagram below shows the DDC serial output timing.



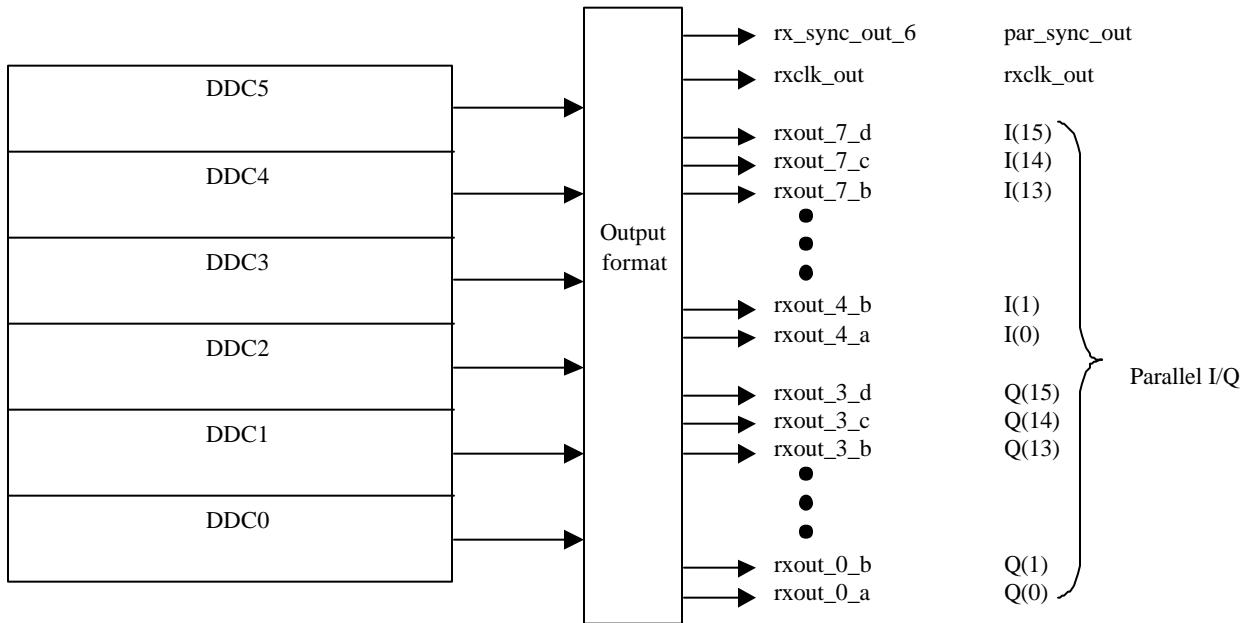
### Programming

Variable	Description
pser_recv_fsinvl(6:0)	Frame sync interval in bits
pser_recv_bits(4:0)	Number of data output bits - 1. ie: 10001= 18 bits
pser_recv_clkdiv(3:0)	Receive serial interface clock divider rate - 1. 0= rxclk, 15= rxclk/16
pser_recv_8pin	When set, configures the serial out pins for 4I and 4Q in UMTS mode. When clear, the mode is 2I and 2Q. Used in conjunction with pser_recv_alt.
pser_recv_alt	When set, outputs Q data from adjacent DDC channel.
pser_recv_fsdel(1:0)	Number of bit clocks the frame sync is output early with respect to serial data.
ssel_serial(2:0)	Sync source selection, 1 of 8.

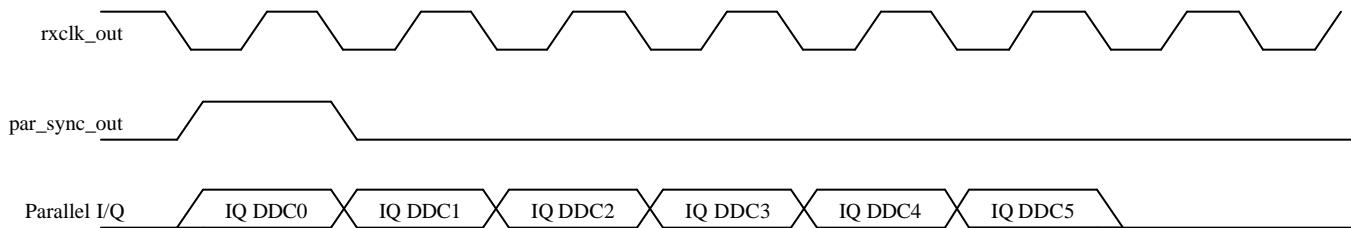
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tristate(6:3)	Tristate controls for the rx_sync_out_X and rxout_X_X pins. Pins are in tristate when the tristate register bits are set.
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### 2.2.11.2 Parallel Output Interface



When a parallel I/Q interface is required, a 32 bit time division multiplexed output mode can be selected using the rxout\_X\_X pins. This interface is provided for direct connection to the TMS320TCI110 Receive Chip Rate ASSP when delayed antenna streams are not required. The output sample rate, rxclk\_out clock polarity, par\_sync\_out position and number of channels to be output are all programmable.



The DDC channel serial interface synchronization source selections should all be programmed to the same value when using this parallel output interface (each DDC channel ssel\_serial(2:0) in the SYNC\_0 register should be programmed to the same rxsync\_A/B/C/D value).

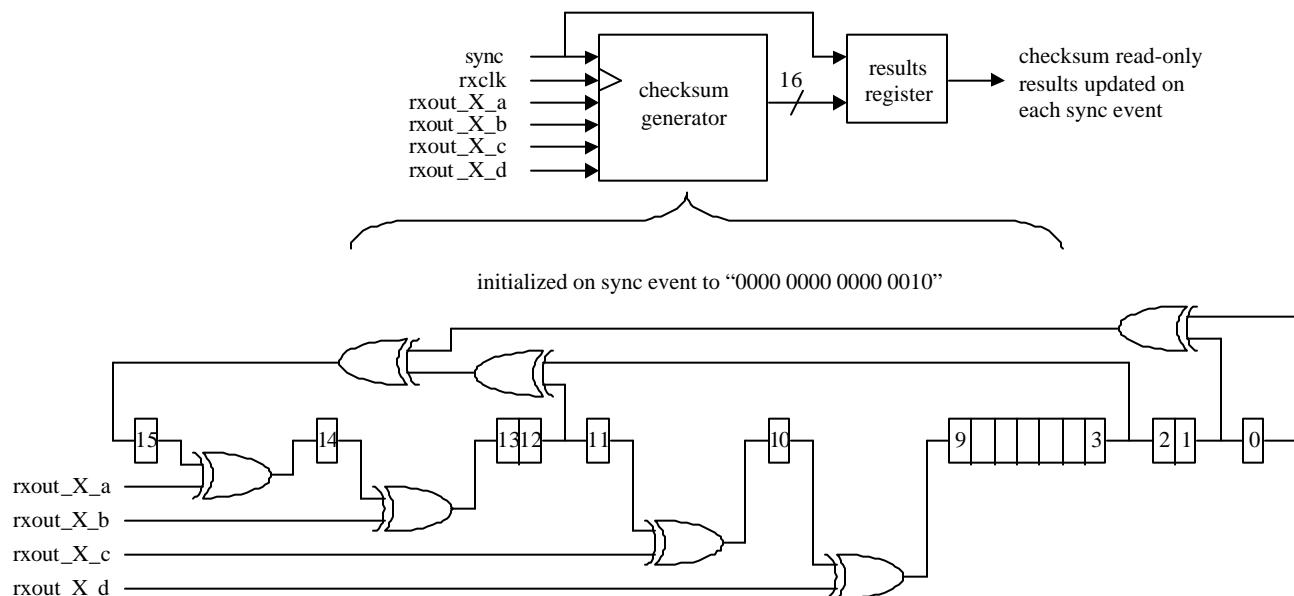
Decimation by 2 in the output interface can be achieved by setting the frame strobe interval and clock divider to 1/2 the PFIR output rate. The parallel interface samples the PFIR outputs each time the transfer interval defined by these two settings has completed.

**Programming**

Variable	Description
par_recv_fsinvl(6:0)	rx_sync_out (frame strobe) sync interval. 0 is 1 rxclk cycle and 127 is 128 rxclk cycles.
par_recv_clkdiv(6:0)	rxclk_out cycles per IQ channel sample; 1 is full rate, 2 is rxclk/2, etc.
par_recv_chan(3:0)	Number channels to be output. 0 is 1 channel, and 15 is 16 channels.
par_recv_sync_del(6:0)	delays the DDC0 pser sync source to establish the timing of IQ DDC0. Increasing the value delays the par_sync_out location.
par_recv_syncout_del(3:0)	delays the rx_sync_out position with respect to IQ DDC0. Setting to 0 moves the rx_sync_out pulse one rxclk_out cycle before the IQ DDC0 word, setting to 1 places it as shown above, lined up with IQ DDC0, etc.
par_recv_rxclk_pol	rxclk_out polarity. Outputs data on falling edges when cleared, rising edges when set.
par_recv_sync_pol	parallel interface par_sync_out polarity. 0 is active low, 1 for active high
par_recv_ena	Parallel TCI110 style interface enabled when set, serial interface enabled when cleared.
ssel_serial(2:0)	DDC channel serial interface sync source selection. <i>All DDCs should be programmed to the same sync source when using this parallel output interface.</i>
gain_mon	When set, the parallel output data includes 8b I at I(15:8), 8b Q at Q(15:8), 14b AGC gain at I(7:0) & Q(7:2) and 2b AGC state at Q(1:0).
tristate(6:3)	Tristate controls for the rx_sync_out_X and rxout_X_X pins. Pins are in tristate when the tristate register bits are set.

**2.2.12 DDC Checksum Generator**

The checksum generator is used in conjunction with the input test signal generator to implement a self test capability.



The sync for the checksum generator is internally connected to the ddc\_counter output.

**Programming**

Variable	Description
ddc_chk_sum(15:0)	Read only DDC channel checksum results

**3 AFE8406 General Control**

The AFE8406 is configured over a bi-directional 16 bit parallel data microprocessor control port. The control port permits access to the control registers which configure the chip. The control registers are organized using a paged-access scheme using 6 address lines. Half of the 64 addresses (Address 32 through Address 63) represent global registers. The other 32 (Address 0 through Address 31) are paged registers. This arrangement permits accessing a large number of control registers using relatively few address lines.

Global registers (Address 32 through Address 63) are used to read/write AFE8406 parameters that are global in nature and can benefit from single read/write operations. Examples include chip status, reset, sync options, checksum ramp parameters, interrupt sources, interrupt masks, tri-state controls and the page register.

Global Address 33 is the page register. Writing a 16 bit value to this register sets the page to which future write or read operations performed. These paged-registers contain the actual parameters that configure the chip and are accessed by writing/reading address 0 through address 31.

The global tristate register can be used to tristate the output drivers on the AFE8406, and also includes the capability of disabling the chip's internal rxclk.

**Programming**

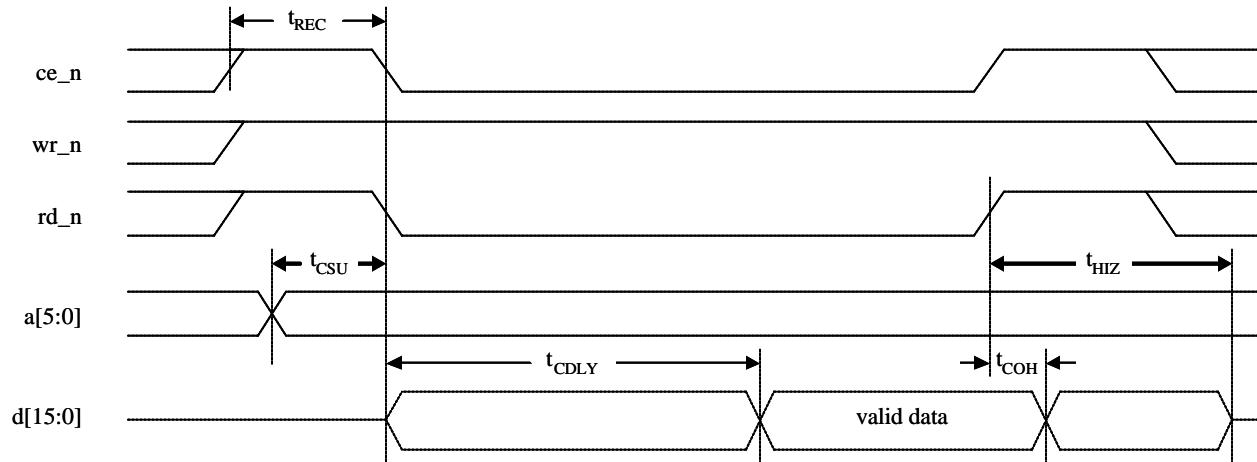
Variable	Description
rxclk_ena	Enables the internal rxclk when set. When cleared, the AFE8406 will ignore the rxclk input signal and hold the internal clock low.
tristate(10:0)	Various output pins are forced into tristate mode when these bits are asserted. See the GBL_TRISTATE register description for pin groups to bit assignments.
rst_func	When asserted, the internal datapath is held reset. The control register programming is not affected.

**3.1 Microprocessor Interface Control Data, Address, and Strobes**

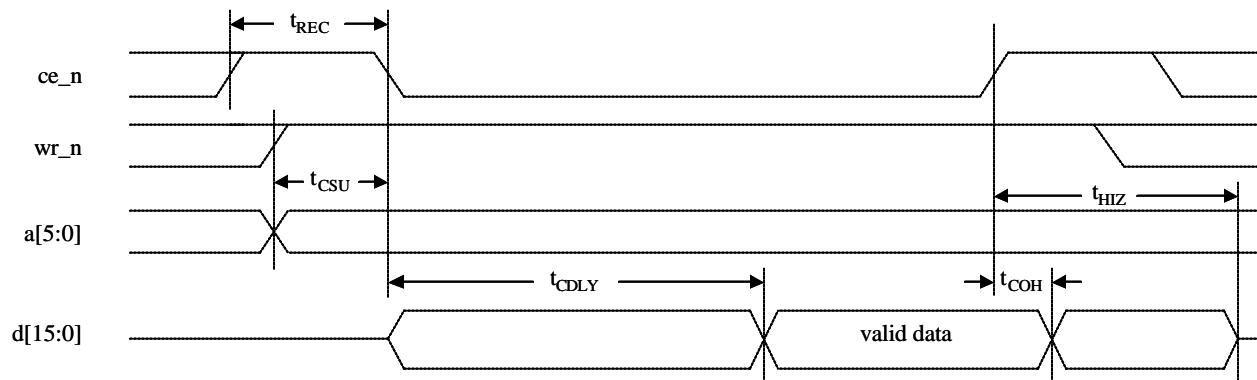
The microprocessor control bus consists of 16 bi-directional control data lines **d[15:0]**, 6 address lines **a[5:0]**, a read enable line **rd\_n**, a write enable line **wr\_n**, and a chip enable line **ce\_n**. These lines usually interface to a microprocessor or DSP chip and is intended to look like a block of memory.

The interface can be operated in a 3 pin control mode (using rd\_n, wr\_n and ce\_n) or 2 pin control mode (using wr\_n and ce\_n with rd\_n always low).

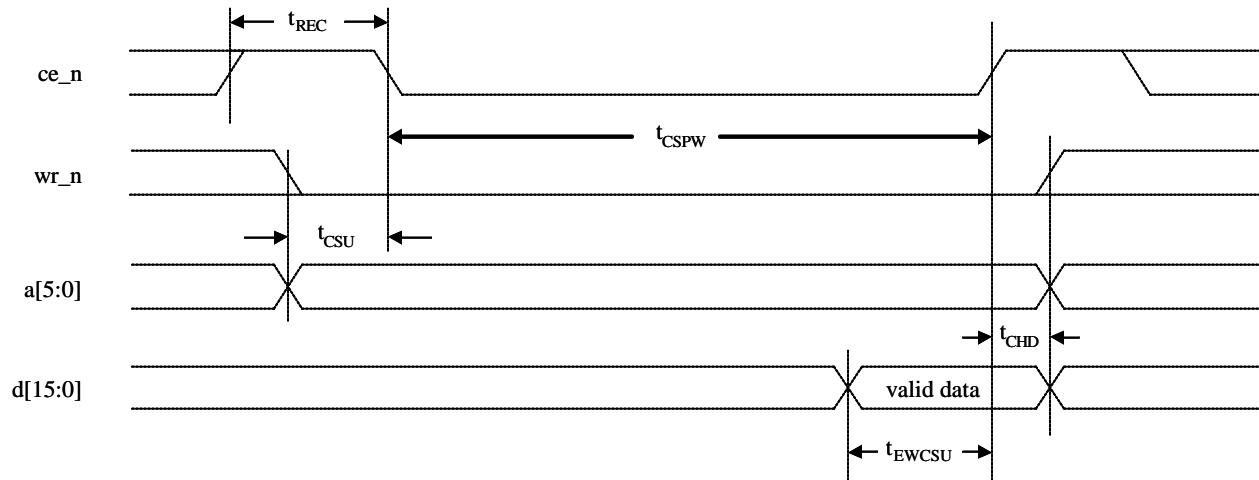
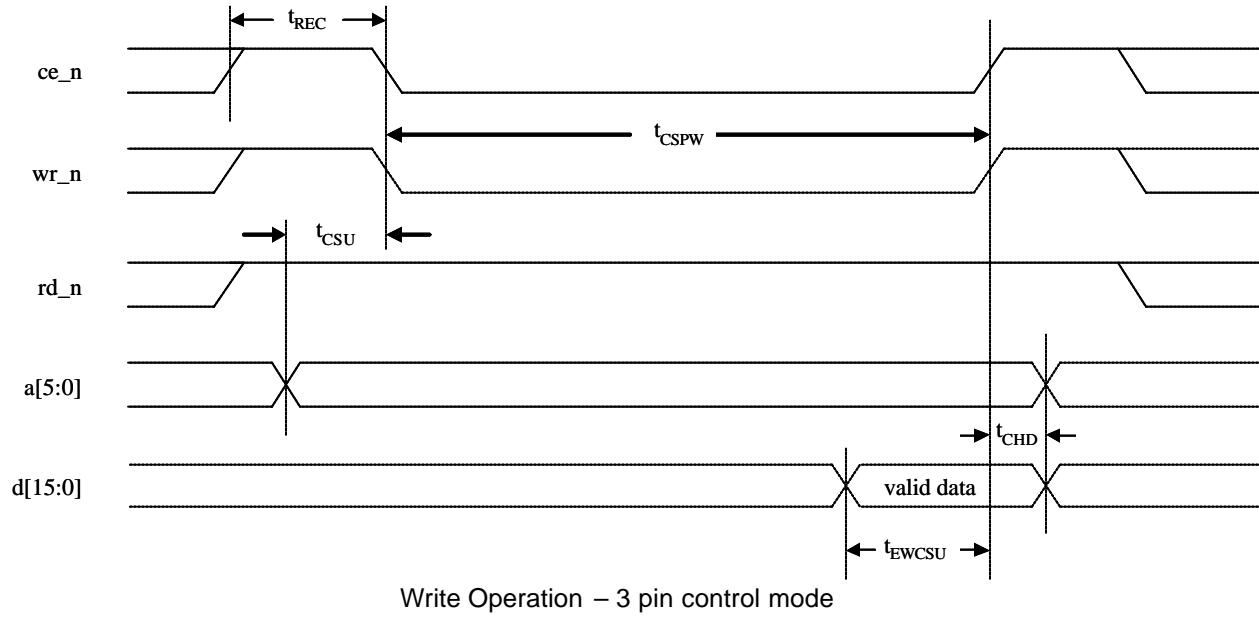
## 3.2 MPU Timing diagrams:



Read Operation – 3 pin control mode



Read Operation – 2 pin control mode (rd\_n tied low)



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### 3.3 Synchronization Signals

Various function blocks within the AFE8406 need to be synchronized in order to realize predictable results. The AFE8406 provides a flexible system where each function block that requires synchronization can be independently synchronized from either device pins or from a software “one-shot”. The one-shot option is setup and triggered through control registers. The four sync input pins, rxsync\_a, rxsync\_b, rxsync\_c and rxsync\_d are qualified on the rxclk rising clock edge.

The table below shows the different sync modes available:

Sync Select Code	Receive Sync Source
000	rxsync_a
001	rxsync_b
010	rxsync_c
011	rxsync_d
100	ddc sync counter terminal count
101	ddc sync triggered by s/w oneshot (register bit)
110	0 (always off)
111	1 (always on)

The tables below summarizes the blocks which have functions that can be synchronized using the above eight sync source options:

#### Receive Common Syncs

Sync Name	Purpose
sync_ddc_counter	Initializes the receive sync counter
sync_ddc	Initializes the receive ADC interface & clock generation circuits
sync_rxsync_out	selects sync signal to be output on the rx_sync_out pin.
sync_adc_fifo	Initializes the input and output pointers in the ADC fifo circuits.
sync_tst_decim	Initializes the testbus decimation counter.
sync_recv_pmeterX	Initializes the rxin power meters. {X = 0,1,2 or 3}
sync_ragc_interval_X	Initializes the rxin receive AGC timers. {X = 0,1,2 or 3}
sync_ragc_freeze_X	rxin receive AGC freeze mode control. {X = 0,1,2 or 3}
sync_ragc_clear_X	Initializes the receive AGC error accumulator. {X = 0,1,2 or 3}

#### DDC Channel Syncs

Sync Name	Purpose
sync_ddc_tadj	Selects zero stuff moment in the tadj fine adjustment section.
sync_ddc_tadj_reg	Updates the tadj output pointer register delay in the tadj coarse adjustment section.
sync_ddc_nco	Resets the NCO accumulator.
sync_ddc_freq	Updates the NCO freq registers.
sync_ddc_phase	Updates the NCO phase register.
sync_ddc_dither	Initializes the NCO dither circuits.
sync_ddc_cic	Selects the CIC decimation moment.
sync_ddc_pmeter	Initializes the receive channel power meters.
sync_ddc_gain	Updates the DDC channel AGC gain registers
sync_ddc_agc	Initializes the AGC accumulator.
sync_ddc_agc_freeze	AGC freeze mode control.
sync_ddc_serial	Initializes the receive serial interface.

A 32-bit general purpose timer is included in the synchronization function. The timer loads the user programmed terminal count on a sync event, and counts down to zero using rxclk. The width of the terminal count pulse can also be programmed up to rxclk cycles. The timers output can be used as a sync source for any other circuits requiring a sync if desired, and can also be routed to the rx\_sync\_out pin.

### Programming

Variable	Description
ddc_counter(31:0)	32-bit programmable terminal count
ddc_counter_width(7:0)	8-bit programmable terminal count pulse width
ssel_ddc_counter(2:0)	Sync source selection for the ddc counter
ssel_rxsync_out(2:0)	Sync source selection for the rx_sync_out pin
tristate(0)	When set, the interrupt and rx_sync_out pins are tristated.
rx_oneshot	Register bit used to generate the S/W oneshot signal for sync. This bit must be programmed from cleared to set in order to generate a rising edge sync signal.

### 3.4 Interrupt Handling

When a AFE8406 block sets an interrupt, the interrupt pin will go active if the interrupt source is not masked. The microprocessor should then read the interrupt register to determine the source of the interrupt. The microprocessor will then have to write the interrupt register to clear the interrupt pin and the interrupt source. The interrupt register and interrupt mask are located in the global registers section of the control registers.

The AFE8406 has 16 interrupt sources; power meters in each of the eight DDC blocks, power meters in the four receive input interface, and four rxin\_X\_ovr (adc overflow) input pins where X={a,b,c,d}.

### Programming

Variable	Description
pmeterX_im(7:0)	Channel pmeter interrupt mask bits. Interrupt source is masked when set.
recv_pmterX_im(3:0)	Receive input power meter interrupt masks.
rxin_X_ovr_im	ADC overflow input pin interrupt masks.
pmeterX(7:0)	Channel pmeter interrupt status.
recv_pmterX(3:0)	Receive input power meter interrupt status.
rxin_X_ovr	ADC overflow input pin interrupt status.
intr_clr	When asserted, holds all interrupt status bits cleared. The interrupt pin will be inactive (always low) when this bit is set. Intended for lab/debug use only
tristate(0)	When set, the interrupt and rx_sync_out pins are tristated.

### 3.5 AFE8406 Programming

The AFE8406 includes over 2000 internal configuration registers and therefore implements a paged addressing scheme. The register map includes a “global control variables” register address space that is accessed directly when the a5 signal is high. This “global control variables” address space includes the page register. All other registers are addressed using a combination of an address comprised of the internal page register contents and the 6-bit external address; a5, a4, a3, a2, a1 and a0.

The page register is accessed when the 6-bit address a5:a0 is 0x21 (or binary "100001").

Page Register Contents in Hex	Address pin a5	Registers Addressed with 5 bit address space, pins (a4:a0)
don't care	1	Global Control Variables 0x00 through 0x1F
0x0000	0	DDC0 PFIR taps 0 through 31 coefficient lsbs (1:0)
0x0020	0	DDC0 PFIR taps 32 through 63 coefficient lsbs (1:0)
0x0040	0	DDC0 PFIR taps 0 through 31 coefficient msbs (17:2)
0x0060	0	DDC0 PFIR taps 32 through 63 coefficient msbs (17:2)
0x0080	0	DDC0 CFIR taps 0 through 31 coefficient lsbs (1:0)
0x00A0	0	DDC0 CFIR taps 32 through 63 coefficient lsbs (1:0)
0x00C0	0	DDC0 CFIR taps 0 through 31 coefficient msbs (17:2)
0x00E0	0	DDC0 CFIR taps 32 through 63 coefficient msbs (17:2)
0x0100	0	DDC0 Control Registers 0x00 through 0x1F
0x0120	0	DDC0 Control Registers 0x20 through 0x3F
0x0200	0	DDC1 PFIR taps 0 through 31 coefficient lsbs (1:0)
0x0220	0	DDC1 PFIR taps 32 through 63 coefficient lsbs (1:0)
0x0240	0	DDC1 PFIR taps 0 through 31 coefficient msbs (17:2)
0x0260	0	DDC1 PFIR taps 32 through 63 coefficient msbs (17:2)
0x0280	0	DDC1 CFIR taps 0 through 31 coefficient lsbs (1:0)
0x02A0	0	DDC1 CFIR taps 32 through 63 coefficient lsbs (1:0)
0x02C0	0	DDC1 CFIR taps 0 through 31 coefficient msbs (17:2)
0x02E0	0	DDC1 CFIR taps 32 through 63 coefficient msbs (17:2)
0x0300	0	DDC1 Control Registers 0x00 through 0x1F
0x0320	0	DDC1 Control Registers 0x20 through 0x3F
0x0400	0	DDC2 PFIR taps 0 through 31 coefficient lsbs (1:0)
0x0420	0	DDC2 PFIR taps 32 through 63 coefficient lsbs (1:0)
0x0440	0	DDC2 PFIR taps 0 through 31 coefficient msbs (17:2)
0x0460	0	DDC2 PFIR taps 32 through 63 coefficient msbs (17:2)
0x0480	0	DDC2 CFIR taps 0 through 31 coefficient lsbs (1:0)
0x04A0	0	DDC2 CFIR taps 32 through 63 coefficient lsbs (1:0)
0x04C0	0	DDC2 CFIR taps 0 through 31 coefficient msbs (17:2)
0x04E0	0	DDC2 CFIR taps 32 through 63 coefficient msbs (17:2)
0x0500	0	DDC2 Control Registers 0x00 through 0x1F
0x0520	0	DDC2 Control Registers 0x20 through 0x3F
0x0600	0	DDC3 PFIR taps 0 through 31 coefficient lsbs (1:0)
0x0620	0	DDC3 PFIR taps 32 through 63 coefficient lsbs (1:0)
0x0640	0	DDC3 PFIR taps 0 through 31 coefficient msbs (17:2)
0x0660	0	DDC3 PFIR taps 32 through 63 coefficient msbs (17:2)
0x0680	0	DDC3 CFIR taps 0 through 31 coefficient lsbs (1:0)
0x06A0	0	DDC3 CFIR taps 32 through 63 coefficient lsbs (1:0)
0x06C0	0	DDC3 CFIR taps 0 through 31 coefficient msbs (17:2)
0x06E0	0	DDC3 CFIR taps 32 through 63 coefficient msbs (17:2)
0x0700	0	DDC3 Control Registers 0x00 through 0x1F
0x0720	0	DDC3 Control Registers 0x20 through 0x3F

Page Register Contents in Hex	Address pin a5	Registers Addressed with 5 bit address space, pins (a4:a0)
0x0800	0	DDC4 PFIR taps 0 through 31 coefficient lsbs (1:0)
0x0820	0	DDC4 PFIR taps 32 through 63 coefficient lsbs (1:0)
0x0840	0	DDC4 PFIR taps 0 through 31 coefficient msbs (17:2)
0x0860	0	DDC4 PFIR taps 32 through 63 coefficient msbs (17:2)
0x0880	0	DDC4 CFIR taps 0 through 31 coefficient lsbs (1:0)
0x08A0	0	DDC4 CFIR taps 32 through 63 coefficient lsbs (1:0)
0x08C0	0	DDC4 CFIR taps 0 through 31 coefficient msbs (17:2)
0x08E0	0	DDC4 CFIR taps 32 through 63 coefficient msbs (17:2)
0x0900	0	DDC4 Control Registers 0x00 through 0x1F
0x0920	0	DDC4 Control Registers 0x20 through 0x3F
0x0A00	0	DDC5 PFIR taps 0 through 31 coefficient lsbs (1:0)
0x0A20	0	DDC5 PFIR taps 32 through 63 coefficient lsbs (1:0)
0x0A40	0	DDC5 PFIR taps 0 through 31 coefficient msbs (17:2)
0x0A60	0	DDC5 PFIR taps 32 through 63 coefficient msbs (17:2)
0x0A80	0	DDC5 CFIR taps 0 through 31 coefficient lsbs (1:0)
0x0AA0	0	DDC5 CFIR taps 32 through 63 coefficient lsbs (1:0)
0x0AC0	0	DDC5 CFIR taps 0 through 31 coefficient msbs (17:2)
0x0AE0	0	DDC5 CFIR taps 32 through 63 coefficient msbs (17:2)
0x0B00	0	DDC5 Control Registers 0x00 through 0x1F
0x0B20	0	DDC5 Control Registers 0x20 through 0x3F
0x0C00	0	DDC6 PFIR taps 0 through 31 coefficient lsbs (1:0)
0x0C20	0	DDC6 PFIR taps 32 through 63 coefficient lsbs (1:0)
0x0C40	0	DDC6 PFIR taps 0 through 31 coefficient msbs (17:2)
0x0C60	0	DDC6 PFIR taps 32 through 63 coefficient msbs (17:2)
0x0C80	0	DDC6 CFIR taps 0 through 31 coefficient lsbs (1:0)
0x0CA0	0	DDC6 CFIR taps 32 through 63 coefficient lsbs (1:0)
0x0CC0	0	DDC6 CFIR taps 0 through 31 coefficient msbs (17:2)
0x0CE0	0	DDC6 CFIR taps 32 through 63 coefficient msbs (17:2)
0x0D00	0	DDC6 Control Registers 0x00 through 0x1F
0x0D20	0	DDC6 Control Registers 0x20 through 0x3F
0x0E00	0	DDC7 PFIR taps 0 through 31 coefficient lsbs (1:0)
0x0E20	0	DDC7 PFIR taps 32 through 63 coefficient lsbs (1:0)
0x0E40	0	DDC7 PFIR taps 0 through 31 coefficient msbs (17:2)
0x0E60	0	DDC7 PFIR taps 32 through 63 coefficient msbs (17:2)
0x0E80	0	DDC7 CFIR taps 0 through 31 coefficient lsbs (1:0)
0x0EA0	0	DDC7 CFIR taps 32 through 63 coefficient lsbs (1:0)
0x0EC0	0	DDC7 CFIR taps 0 through 31 coefficient msbs (17:2)
0x0EE0	0	DDC7 CFIR taps 32 through 63 coefficient msbs (17:2)
0x0F00	0	DDC7 Control Registers 0x00 through 0x1F
0x0F20	0	DDC7 Control Registers 0x20 through 0x3F
0x1000	0	Receive Input AGC0 Error RAM addresses 0 through 31
0x1020	0	Receive Input AGC0 Error RAM addresses 32 through 63
0x1040	0	Receive Input AGC0 DVGA RAM addresses 0 through 31
0x1080	0	Receive Input AGC0 Gain RAM addresses 0 through 31
0x10A0	0	Receive Input AGC0 Gain RAM addresses 32 through 63
0x1100	0	Receive Input AGC1 Error RAM addresses 0 through 31
0x1120	0	Receive Input AGC1 Error RAM addresses 32 through 63
0x1140	0	Receive Input AGC1 DVGA RAM addresses 0 through 31

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0x1180	0	Receive Input AGC1 Gain RAM addresses 0 through 31
0x11A0	0	Receive Input AGC1 Gain RAM addresses 32 through 63
0x1400	0	Receive Input AGC2 Error RAM addresses 0 through 31
0x1420	0	Receive Input AGC2 Error RAM addresses 32 through 63
0x1440	0	Receive Input AGC2 DVGA RAM addresses 0 through 31
0x1480	0	Receive Input AGC2 Gain RAM addresses 0 through 31
0x14A0	0	Receive Input AGC2 Gain RAM addresses 32 through 63
0x1500	0	Receive Input AGC3 Error RAM addresses 0 through 31
0x1520	0	Receive Input AGC3 Error RAM addresses 32 through 63
0x1540	0	Receive Input AGC3 DVGA RAM addresses 0 through 31
0x1580	0	Receive Input AGC3 Gain RAM addresses 0 through 31
0x15A0	0	Receive Input AGC3 Gain RAM addresses 32 through 63
0x1800	0	Receive Input Control Registers 0x00 through 0x1F
0x1820	0	Receive Input Control Registers 0x20 through 0x3F
0x1840	0	Receive Input AGC Control Registers 0x00 through 0x1F
0x1860	0	Receive Input AGC Control Registers 0x20 through 0x3F

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### 3.5.2 Global Control Variables

These registers are accessed directly without page address extension; when pin a5 is high during a read or write access, this block of 32 registers are accessed.

**Register name: VER**

**Address: 0x0**

**READ\_ONLY**

BIT15

BIT8

unused							
0	0	0	0	0	0	0	0

BIT7	BIT0						
unused	Unused	unused	unused	VER3	VER2	VER1	VER0
0	0	0	0	0	0	0	1

VER(3:0) : A hardwired read only register that returns the version of the chip.

**Register name: PAGE**

**Address: 0x1**

BIT15

BIT8

unused	Unused	unused	W(2:0)			X	Y(2)
0	0	0	0 0 0			0	0

BIT7	BIT0						
Y(1)	Y(0)	Zp	unused	unused	unused	unused	unused
0	0	0	0	0	0	0	0

W(2:0) : Selects which dual DDC block to address.

X : The DDC modules are configured as dual DDCs; an even numbered DDC and odd numbered DDC are contained in each dual DDC module, the X bit selects which DDC gets address. (DDC0/2/4/6=0, DDC1/3/5/7=1)

W(2:0)	X bit	Selected Block
000	0	DDC0
000	1	DDC1
001	0	DDC2
001	1	DDC3
010	0	DDC4
010	1	DDC5
011	0	DDC6
011	1	DDC7
100	0	Receive AGC0/1 RAMs
101	0	Receive AGC2/3 RAMs
110	0	Receive Input Interface

Y(2:0) : Within each major block, there are up to 8 different Zones that can be addressed using the Y bits.

Y(2:0)	DDC Zone	Receive Input Interface Zone	Receive AGC RAMs Zone
000	PFIR coefficient lower 2 bits	CHIPS control registers	RAGC0/2 ERRMAP
001	PFIR coefficient upper 16 bits	RAGC control registers	RAGC0/2 DVGAMAP
010	CFIR coefficient lower 2 bits	Not assigned	RAGC0/2 GAINMAP
011	CFIR coefficient upper 16 bits	Not assigned	Not assigned
100	Control registers	Not assigned	RAGC1/3 ERRMAP
101	Not assigned	Not assigned	RAGC1/3 DVGAMAP
110	Not assigned	Not assigned	RAGC1/3 GAINMAP
111	Not assigned	Not assigned	Not assigned

Zp : The Zp bit is the MSB of the address word sent to the registers and rams. This bit can be thought of as an upper/lower selector of the 64 word addressing.

## Register name: CONFIG

## Address: 0x2

BIT15

BIT8

slf_tst_ena	rduz_sens_ena	arst_func	tst_rate_sel(4:0)				
0	0	0	0	0	0	0	0

BIT7

BIT0

par_recv_ena	gbl_ddc_write	intr_clr	tst_select(3:0)				tst_on
0	0	0	1	1	1	0	0

slf\_tst\_ena : Turns on the checksum LFSR for the receivers. They are located in the RECEIVE INPUT INTERFACE and DDC blocks.

rduz\_sens\_ena : When enabled, adds noise to the LSB's of the ADC inputs.

arst\_func : When asserted, resets the functional portion of the circuits. The MPU registers do not get reset and retain their programmed value.

tst\_rate\_sel(4:0) : Sets the rate of the output test data and clock. The length of the clock cycle is the value in tst\_rate\_sel+1 multiplied by the RXCLK period. When the test bus source is set to 1000 (rxin\_a and rxin\_b FIFO outputs), tst\_rate\_sel(4:0) must be set to 0 for output. Therefore, will not output a clock at the decimated test bus rate.

par\_recv\_ena : When asserted, the rxout\_\*\_\* serial pins join to form a 32 bit parallel output using 32 pins as a data bus, one pin as a output clock and one pin as a sync. This is used to connect to the TCI110 Chip rate processor from TI.

gbl\_ddc\_write : *Factory use only.* When asserted, the mpu writes are global. This means that DDC0/2/4/6 or DDC1/3/5/7 can be programmed simultaneously with the same values. This is an effort to reduce the amount of time spent programming the device. A common setup can be used to program the DDC0/2/4/6, then all the DDC1/3/5/7. Afterwards, just individual writes to the registers which differ between DDCs can be done. To use this feature, this bit must be asserted and the DDC0/1 must be addressed. Any other DDC address will not work.

intr\_clr : When asserted, this bit forces all interrupts to be cleared. To allow the interrupts to be set again, this bit must be programmed to zero. This does not stop blocks from generating interrupts, but rather just keeps the interrupts from being reported.

tst\_select(3:0) : This selects which block the test output comes from:

tst_select(3:0)	Test data sent to test bus rxin_d(15:0), dvga_c(3:2), rxin_c(15:0), dvga_c(5:4)
0000	DDC 0
0001	DDC 1
0010	DDC 2
0011	DDC 3
0100	DDC 4
0101	DDC 5
0110	DDC 6
0111	DDC 7
1000	rxin_a(15:0), "00", rxin_b(15:0), "00" <i>from the fifo outputs</i>
others	none selected

tst\_on : When asserted, the testbus is active. The ADC input ports rxin\_c(15:0), rxin\_d(15:0), dvga\_c(5:0) and dvga\_d(5:0) become the testbus output ports. When this bit is set, the rxin\_c(15:0) and rxin\_d(15:0) ports become chip outputs. The dvga\_c(5:0) and dvga\_d(5:0) ports are enabled separately using the **GBL\_TRISTATE** register

**Register name: GBL\_PAR\_CONFIG0****Address: 0x3**

BIT15

par_recv_sync_del(6:0)							BIT8 tst_clk_pol
0	0	0	0	0	0	0	0

BIT7

par_recv_clkdiv(6:0)							BIT0 par_recv_rxclk_pol
0	0	0	0	0	0	0	0

par\_recv\_sync\_del(6:0) : Delays the sync source from the DDC0 AGC output by (par\_recv\_sync\_del+1) rxclk cycles.  
 tst\_clk\_pol : Selects the polarity of the test clock output at dvga\_c(1) when the test bus is enabled; 0 for rising edge in the center of valid data, 1 for falling edge in the center of valid data.  
*No effect when tst\_rate\_sel is "00000".*

par\_recv\_clkdiv(6:0) : Selects the parallel interface output clock rate.  
 par\_recv\_rxclk\_pol : Selects the polarity of the rxclk\_out clock output; 0 for rising edge in the center of valid data, 1 for falling edge in the center of valid data.

**Register name: GBL\_PAR\_CONFIG1****Address: 0x4**

BIT15

BIT8

par_recv_syncout_del(3:0)				par_recv_chan(3:0)			
0	0	0	0	0	0	0	0

par_recv_fsinvl(6:0)								par_recv_sync_pol
0	0	0	0	0	0	0	0	0

par\_recv\_syncout\_del(3:0): Changes the rx\_sync\_out position with respect to IQ DDC0. Setting to 0 causes rx\_sync\_out to lead IQ DDC0 by 1 output sample, setting to 1 causes rx\_sync\_out to line up with IQ DDC0, setting to 2 causes rx\_sync\_out to trail IQ DDC0 by 1 output sample, etc.

par\_recv\_chan(3:0) : Selects the number of channels to be output over the parallel interface, from 1 to 16 channels.

par\_recv\_fsinvl(6:0) : Selects the number of rxclk cycles per parallel interface frame, from 1 to 128 cycles.

par\_recv\_sync\_pol : Selects the polarity of the parallel interface sync pulse; 0 for active low, 1 for active high.

**Register name: GBL\_TRISTATE****Address: 0x5**

BIT15

BIT8

rxclk_ena	Unused	unused	unused	unused	tristate(10)	tristate(9)	tristate(8)
1	0	0	0	0	1	1	1

BIT7								BIT0
tristate(7)	tristate(6)	tristate(5)	tristate(4)	tristate(3)	tristate(2)	tristate(1)	tristate(0)	
1	1	1	1	1	1	1	1	

rxclk\_ena : *Master rxclk enable*. When set, the chip's rxclk is enabled, when cleared, rxclk is disabled.

**All tristates are ACTIVE LOW; '0' enables the output and '1' tristates it.**

tristate(10) : When cleared, enables the dvga\_d outputs.  
 tristate(9) : When cleared, enables the dvga\_c outputs.  
 tristate(8) : When cleared, enables the dvga\_b outputs.  
 tristate(7) : When cleared, enables the dvga\_a outputs.  
 tristate(6) : When cleared, enables the rx\_sync\_out\_6/7, and the rxout\_6/7\_a/b/c/d outputs (for parallel interface use only).  
 tristate(5) : When cleared, enables the rx\_sync\_out\_4/5, and the rxout\_4/5\_a/b/c/d outputs.  
 tristate(4) : When cleared, enables the rx\_sync\_out\_2/3, and the rxout\_2/3\_a/b/c/d outputs.  
 tristate(3) : When cleared, enables the rx\_sync\_out\_0/1, and the rxout\_0/1\_a/b/c/d outputs.  
 tristate(2) : TBD  
 tristate(1) : When cleared, enables the rxclk\_out output.  
 tristate(0) : When cleared, enables interrupt and rx\_sync\_out outputs.

**Register name: GBL\_ONESHOT****Address: 0x6**

BIT15

BIT8

| unused |
|--------|--------|--------|--------|--------|--------|--------|--------|
| 0      | 0      | 0      | 0      | 0      | 0      | 0      | 0      |

BIT7								BIT0
rx_oneshot	Unused							
0	0	0	0	0	0	0	0	

rx\_oneshot : When set, a one shot pulse is sent to the receive blocks for syncing. This only works if the blocks are programmed to use the oneshot as the sync source. To use the oneshot again, it must be programmed back to a '0' and then back to a '1'.

**Register name: GBL\_IMASK0****Address: 0x7**

BIT15

BIT8

unused	Unused	pmeter5_im	pmeter4_im	pmeter3_im	pmeter2_im	pmeter1_im	pmeter0_im
0	0	0	0	0	0	0	0

BIT7

BIT0

recv_pmeter0_im	recv_pmeter1_im	recv_pmeter2_im	recv_pmeter3_im	rxin_a_ovr_im	rxin_b_ovr_im	rxin_c_ovr_im	rxin_d_ovr_im
0	0	0	0	0	0	0	0

pmeterX\_im : When asserted, masks the interrupt for the particular DDC pmeter, X= {0,1,2,3,4,5,6,7}.  
 recv\_pmeterX\_im : When asserted, masks the interrupt for the particular receive input pmeter, X= {0,1,2,3 }.  
 rxin\_X\_ovr\_im : When asserted, masks the interrupt for the particular rxin overflow, X={a,b,c,d}.

**Register name: GBL\_INTERRUPT0****Address: 0x9**

BIT15

BIT8

unused	Unused	pmeter5	pmeter4	pmeter3	pmeter2	pmeter1	pmeter0
0	0	0	0	0	0	0	0

BIT7

BIT0

recv_pmeter0	recv_pmeter1	recv_pmeter2	recv_pmeter3	rxin_a_ovr	rxin_b_ovr	rcin_c_ovr	rxin_d_ovr
0	0	0	0	0	0	0	0

pmeterX : Asserted when an interrupt has been generated by this DDC pmeterX block, X={1,2,3,4,5,6,7}.  
 recv\_pmeterX : Asserted when an interrupt has been generated by this receive input pmeter, X= {0,1,2,3 }.  
 rxin\_X\_ovr : Asserted when a logic high input from the rxin\_X\_ovr pin occurs, X={a,b,c,d}.

## 3.5.3 Receive Input Interface Controls (Pages: 0x1800 and 0x1820)

Register name: SYNC\_DDC\_CNTR\_LSB

Page: 0x1800

Address: 0x0

BIT15

BIT8

ddc_counter(15:8)							
0	0	0	0	0	0	0	0

ddc_counter(7:0)							
0	0	0	0	0	0	0	0

Register name: SYNC\_DDC\_CNTR\_MSB

Page: 0x1800

Address: 0x1

BIT15

BIT8

ddc_counter(31:24)							
0	0	0	0	0	0	0	0

ddc_counter(23:16)							
0	0	0	0	0	0	0	0

ddc\_counter(32:0) : 32 bit interval timer common to all DDC sync inputs. This timer may be programmed to any interval count, and each DDC synchronization input can select this counter as a source. The value programmed into the counter is: (desired number -1). The counter increments on each RX clock rising edge.

Register name: SSEL\_DDC\_CNTR

Page: 0x1800

Address: 0x2

BIT15

BIT8

rxinab_mux	rxincd_mux	unused	unused	unused	ssel_ddc_counter(2:0)		
0	0	0	0	0	0	0	0

ddc_counter_width(7:0)							
0	0	0	0	0	0	0	0

rxinab\_mux : When asserted, the rxin\_a and rxin\_b inputs are internally driven by the rxin\_c and rxin\_d ports, respectively (Factory test use only).

rxincd\_mux : When asserted, the rxin\_c and rxin\_d inputs are internally driven by the rxin\_a and rxin\_b ports, respectively (Factory test use only).

ssel\_ddc\_counter(2:0) : Selects the sync source for the DDC sync counter.

ddc\_counter\_width(7:0) : Sets the width of the counter generated sync pulse in RX clock cycles, from 1 to 256.

Sync sources are contained in this and many of the following registers. For all sync source selections:

ssel_ddc_XXXXXX(2:0)	Selected sync source
000	rxsyncA
001	rxsyncB
010	rxsyncC
011	rxsyncD
100	DDC sync counter
101	one shot (register write triggered)

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110	always 0
111	always 1

**Register name: SSEL\_RX\_0****Page: 0x1800****Address: 0x3**

BIT15

unused	ssel_adc_fifo(2:0)			unused	ssel_tst_decim(2:0)		
0	0	0	0	0	0	0	0

BIT7

unused	ssel_rxsync_out(2:0)			unused	ssel_ddc(2:0)		
0	0	0	0	0	0	0	0

ssel\_adc\_fifo(2:0) : Selects the sync source for the adc FIFO blocks. Sync reinitializes the read and write pointers of the FIFO.

ssel\_tst\_decim(2:0) : Selects the sync source for the test bus decimator block.

ssel\_rxsync\_out(2:0) : Selects the sync source for the RXSYNC\_OUT pin.

ssel\_ddc(2:0) : Selects the sync source for the DDC data input mux and mixer. *Controls clock generation in each DDC block (before the CIC input) which must match because the FIFO output clock is common for all DDC blocks.*

**Register name: RECV\_CONFIG0****Page: 0x1800**

**Address: 0x4**

BIT15

BIT8

rate_sel(1:0)	adc_fifo_strap_ab	adc_fifo_strap_cd	self_test_const_ena	adc_fifo_bypass	ragc_mpu_ram_read	tst_decim17
0	0	0	0	0	0	0
BIT7						
	tst_decim_delay(3:0)		pmeter3_iq	pmeter2_iq	pmeter1_iq	pmeter0_iq
0	0	0	0	0	0	0

rate\_sel(1:0)

: Tells the RECV\_CDRV the input rate. This is the rxin\_a/b/c/d input rate and the rate that the RECEIVE INPUT INTERFACE block sends data to the DDCs.

rate_sel	Input clock rate
00	rxclk
01	rxclk/2
10	rxclk/4
11	rxclk/8

adc\_fifo\_strap\_ab

: When asserted, the input pointers of the rxin\_a FIFO and rxin\_b FIFO are hooked together in lock step configuration. This is used for maintaining FIFO delay consistency when complex inputs are driven on rxin\_a(l) and rxin\_b(Q). rxin\_a is the Master.

adc\_fifo\_strap\_cd

: When asserted, the input pointers of the rxin\_c FIFO and rxin\_d FIFO are hooked together in lock step configuration. This is used for maintaining FIFO delay consistency when complex inputs are driven on rxin\_c(l) and rxin\_d(Q). rxin\_c is the Master.

self\_test\_const\_ena

: When asserted, (with slf\_tst\_ena also asserted), a constant value is output by the test and noise generator instead of the pseudo random sequence. The constant value is programmable.

adc\_fifo\_bypass

: When asserted, the ADC FIFO circuits are bypassed. Input data is then clocked in directly using the rxclk input. *The ssel\_ddc selection value will control the location of the internally generated sample clock when this bit is asserted where rate\_sel is rxclk/2, rxclk/4 or rxclk/8.*

ragc\_mpu\_ram\_read

: When asserted, the RAMs in the RAGC blocks can be read. This bit should only be set when reading the RAGC map rams via the mpu interface and must be cleared for proper RAGC operation.

tst\_decim17

: Factory use only. Will have no effect for user on production part.

tst\_decim\_delay(3:0)

: These bits set the delay from the sync occurring until the decimator samples. In other words, the moment of the decimator is set by this delay value.

pmeter3\_iq

: When asserted, the pmeter3 block takes input from both rxin\_c and rxin\_d as a complex sample pair. When de-asserted, only input from rxin\_d is used for the power measurement.

pmeter2\_iq

: When asserted, the pmeter2 block takes input from both rxin\_c and rxin\_d as a complex sample pair. When de-asserted, only input from rxin\_c is used for the power measurement.

pmeter1\_iq

: When asserted, the pmeter1 block takes input from both rxin\_a and rxin\_b as a complex sample pair. When de-asserted, only input from rxin\_b is used for the power measurement.

pmeter0\_iq

: When asserted, the pmeter0 block takes input from both rxin\_a and rxin\_b as a complex sample pair. When de-asserted, only input from rxin\_a is used for the power measurement.

**Register name: RECV\_CONFIG1**

Page: 0x1800

**Address: 0x5**

BIT15				BIT8			
msb_pos_d(2:0)		offset_bin_d		msb_pos_c(2:0)		offset_bin_c	
0	0	0	0	0	0	0	0
BIT7				BIT0			
msb_pos_b(2:0)		offset_bin_b		msb_pos_a(2:0)		offset_bin_a	
0	0	0	0	0	0	0	0

msb\_pos\_X(2:0) : Places the MSB of the input word from the ADC. The value programmed into the 3 bits is the number of bit positions to the left of bit16 in the input word, that the MSB is located. For example, if a 14bit input word is driving rxin\_a input and is aligned with rxin\_a\_0, then msb\_pos\_a is programmed to "010" meaning 2 bits shifted down from bit 16 is the MSB. X={a,b,c,d}

offset\_bin\_X : rxin\_X input data is in offset binary and not 2's complement. If set, the input value will be converted to 2s complement using the MSB from the corresponding msb\_pos\_X value. X={a,b,c,d} **Note that the internal ADCs use 2's complement format, so offset\_bin\_A and offset\_bin\_B must be set.**

**Register name: NZ\_PWR\_MASK****Page: 0x1800****Address: 0x6**

BIT15								BIT8	
nz_pwr_mask (15:8)								BIT0	
nz_pwr_mask (7:0)								BIT0	
0	0	0	0	0	0	0	0	0	0

nz\_pwr\_mask(15:0) : Used with the rduz\_sens\_ena and selects the noise bits to be added to the ADC input sample when asserted.

**Register name: RECV\_PMETER\_SYNC****Page: 0x1800****Address: 0x7**

BIT15				BIT8			
recv_pmet_ena	ssel_recv_pmeter0(2:0)			recv_pmet_ena	ssel_recv_pmeter1(2:0)		
0	0	0	0	0	0	0	0
BIT7				BIT0			
recv_pmet_ena	ssel_recv_pmeter2(2:0)			recv_pmet_ena	ssel_recv_pmeter3(2:0)		
0	0	0	0	0	0	0	0

recv\_pmeter0\_ena : Enables the Receive Input Interface pmeter0 block when set  
 recv\_pmeter1\_ena : Enables the Receive Input Interface pmeter1 block when set  
 recv\_pmeter2\_ena : Enables the Receive Input Interface pmeter2 block when set  
 recv\_pmeter3\_ena : Enables the Receive Input Interface pmeter3 block when set  
 ssel\_recv\_pmeter0(2:0) : Selects the sync source for the Receive Input Interface pmeter0 block  
 ssel\_recv\_pmeter1(2:0) : Selects the sync source for the Receive Input Interface pmeter1 block  
 ssel\_recv\_pmeter2(2:0) : Selects the sync source for the Receive Input Interface pmeter2 block  
 ssel\_recv\_pmeter3(2:0) : Selects the sync source for the Receive Input Interface pmeter3 block

**Register name: RECV\_PMETER0\_SQR\_SUM\_LSB****Page: 0x1800****Address: 0x8**

BIT15

BIT8

recv\_pmeter0\_sqr\_sum (15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

recv\_pmeter0\_sqr\_sum (7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

**recv\_pmeter0\_sqr\_sum(15:0)** : The sqr\_sum register controls the number of samples to accumulate for a power measurement. Ia is (or Ia & Qa if complex mode is selected are) squared and accumulated. Eight Ia samples (or eight sample pairs of Ia and Qa samples) equal to one sqr\_sum count. The accumulation interval is initiated when the sync is asserted and the programmed (8\*sync\_delay+2) samples has expired or when the interval start time is reached. When the (8\*sqr\_sum+1) sample time is reached, the accumulated powers are made available for MPU access and an interrupt is generated.

**Register name: RECV\_PMETER0\_STRT\_INTVL\_LSB****Page: 0x1800****Address: 0x9**

BIT15

BIT8

recv\_pmeter0\_strt\_intrvl (15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

recv\_pmeter0\_strt\_intrvl (7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

**recv\_pmeter0\_strt\_intrvl(15:0)** : The start interval timer is the interval over which the sqr\_sum is restarted. The timer value is (8\*strt\_intrvl + 1) samples and must be larger than (8\*sqr\_sum+1) samples. The interval start counter and RMS power accumulation is started at the sync pulse after the programmed delay and every time the STRT\_INTRVL counter reaches its limit.

**Register name: RECV\_PMETER0\_SYNC\_DLY****Page: 0x1800****Address: 0xA**

BIT15

BIT8

delay\_line\_0(5:0)

delay_line_0(5:0)						unused	recv_pmeter0_sync_delay(8)
0	0	0	0	0	0	0	0

BIT7

BIT0

recv\_pmeter0\_sync\_delay (7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

**delay\_line\_0(5:0)** : Pointer offset for the rxin\_a path variable delay line. Larger values result in larger pointer offsets and therefore more path delay.

**recv\_pmeter0\_sync\_delay(8:0)** : Programmable start delay from sync, in eight sample units. The actual value is (8\*sync\_delay + 2) samples.

**Register name: RECV\_PMETER0\_CONFIG****Page: 0x1800**

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**Address: 0xB**

recv_pmeter0_sqr_sum(20:16)					recv_pmeter0 strt_intrvl(20:18)		
0	0	0	0	0	0	0	0
BIT7	recv_pmeter0 strt_intrvl(17:16)					ssel_delay_line_0(2:0)	
0	0	0	0	0	0	0	0
BIT0							

recv\_pmeter0\_sqr\_sum(20:16) : MSBs of sqr\_sum value, in 8 sample units.

recv\_pmeter0 strt\_intrvl(20:16) : MSBs of start interval value, in 8 sample units.

ssel\_delay\_line\_0(2:0) : Sync source selection for the 64 sample delay line pointer value update

**Register name: RECV\_PMETER1\_SQR\_SUM\_LSB****Page: 0x1800****Address: 0xC**

recv_pmeter1_sqr_sum (15:8)								
0	0	0	0	0	0	0	0	
BIT7	recv_pmeter1_sqr_sum (7:0)							
0	0	0	0	0	0	0	0	
BIT0								

recv\_pmeter1\_sqr\_sum(15:0) : Lower 16bits of the sqr\_sum interval timer, in 8 sample units.

**Register name: RECV\_PMETER1\_STRT\_INTVL\_LSB****Page: 0x1800****Address: 0xD**

recv_pmeter1 strt_intrvl (15:8)								
0	0	0	0	0	0	0	0	
BIT7	recv_pmeter1 strt_intrvl (7:0)							
0	0	0	0	0	0	0	0	
BIT0								

recv\_pmeter1 strt\_intrvl(15:0) : Lower 16bits of the interval timer, in 8 sample units.

**Register name: RECV\_PMETER1\_SYNC\_DLY****Page: 0x1800****Address: 0xE**

delay_line_1(5:0)						unused	recv_pmeter1_sync_delay(8)
0	0	0	0	0	0	0	0
BIT7	recv_pmeter1 sync_delay (7:0)						BIT0
0	0	0	0	0	0	0	0

delay\_line\_1(5:0) : Pointer offset for the rxin\_b path variable delay line. Larger values result in larger pointer offsets and therefore more path delay.

recv\_pmeter1 sync\_delay(8:0) : Programmable start delay from sync, in 8 sample units.

**Register name: RECV\_PMETER1\_CONFIG****Page: 0x1800****Address: 0xF**

BIT15

BIT8

recv_pmeter1_sqr_sum(20:16)					recv_pmeter1 strt_intrvl(20:18)		
0	0	0	0	0	0	0	0

recv_pmeter1 strt_intrvl(17:16)							
ssel_delay_line_1(2:0)							
0	0	0	0	0	0	0	0

recv\_pmeter1\_sqr\_sum(20:16) : MSBs of sqr\_sum value, in 8 sample units.

recv\_pmeter1 strt\_intrvl(20:16) : MSBs of start interval value, in 8 sample units.

ssel\_delay\_line\_1(2:0) : Sync source selection for the 64 sample delay line pointer value update

**Register name: RECV\_PMETER2\_SQR\_SUM\_LSB****Page: 0x1800****Address: 0x10**

BIT15

BIT8

recv_pmeter2_sqr_sum (15:8)							
0	0	0	0	0	0	0	0

recv_pmeter2_sqr_sum (7:0)							
0	0	0	0	0	0	0	0

recv\_pmeter2\_sqr\_sum(15:0) : Lower 16bits of the sqr\_sum interval timer, in 8 sample units.

**Register name: RECV\_PMETER2\_STRT\_INTVL\_LSB****Page: 0x1800****Address: 0x11**

BIT15

BIT8

recv_pmeter2 strt_intrvl (15:8)							
0	0	0	0	0	0	0	0

recv_pmeter2 strt_intrvl (7:0)							
0	0	0	0	0	0	0	0

recv\_pmeter2 strt\_intrvl(15:0) : Lower 16bits of the interval timer, in 8 sample units.

**Register name: RECV\_PMETER2\_SYNC\_DLY****Page: 0x1800****Address: 0x12**

BIT15

BIT8

delay_line_2(5:0)						unused	recv_pmeter2_sync_delay(8)
0	0	0	0	0	0	0	0

recv_pmeter2_sync_delay (7:0)							
0	0	0	0	0	0	0	0

delay\_line\_2(5:0) : Pointer offset for the rxin\_c path variable delay line. Larger values result in larger pointer offsets and therefore more path delay.

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recv\_pmeter2\_sync\_delay (8:0) : Programmable start delay from sync, in 8 sample units.

**Register name: RECV\_PMETER2\_CONFIG**

**Page: 0x1800**

**Address: 0x13**

BIT15

recv_pmeter2_sqr_sum(20:16)					recv_pmeter2 strt_intrvl(20:18)		
0	0	0	0	0	0	0	0

BIT7

BIT8

recv_pmeter2 strt_intrvl(17:16)	unused	unused	unused	ssel_delay_line_2(2:0)			
0	0	0	0	0	0	0	0

recv\_pmeter2\_sqr\_sum(20:16) : MSBs of sqr\_sum value, in 8 sample units.

recv\_pmeter2 strt\_intrvl(20:16) : MSBs of start interval value, in 8 sample units.

ssel\_delay\_line\_2(2:0) : Sync source selection for the 64 sample delay line pointer value update

**Register name: RECV\_PMETER3\_SQR\_SUM\_LSB**

**Page: 0x1800**

**Address: 0x14**

BIT15

BIT8

recv_pmeter3_sqr_sum (15:8)							
0	0	0	0	0	0	0	0

BIT7

recv_pmeter3_sqr_sum (7:0)							
0	0	0	0	0	0	0	0

recv\_pmeter3\_sqr\_sum(15:0) : Lower 16bits of the sqr\_sum interval timer, in 8 sample units.

**Register name: RECV\_PMETER3\_STRT\_INTVL\_LSB**

**Page: 0x1800**

**Address: 0x15**

BIT15

BIT8

recv_pmeter3 strt_intrvl (15:8)							
0	0	0	0	0	0	0	0

BIT7

recv_pmeter3 strt_intrvl (7:0)							
0	0	0	0	0	0	0	0

recv\_pmeter3 strt\_intrvl(15:0) : Lower 16bits of the interval timer, in 8 sample units.

**Register name: RECV\_PMETER3\_SYNC\_DLY**

**Page: 0x1800**

**Address: 0x16**

BIT15

delay_line_3(5:0)						unused	recv_pmeter3_sync_delay(8)	BIT8
0	0	0	0	0	0	0	0	

BIT7

recv_pmeter3_sync_delay(7:0)								BIT0
0	0	0	0	0	0	0	0	

delay\_line\_3(5:0) : Pointer offset for the rxin\_d path variable delay line. Larger values result in larger pointer offsets and therefore more path delay.

recv\_pmeter3\_sync\_delay(8:0) : Programmable start delay from sync, in 8 sample units.

**Register name: RECV\_PMETER3\_CONFIG****Page: 0x1800****Address: 0x17**

BIT15

recv_pmeter3_sqr_sum(20:16)					recv_pmeter3 strt_intrvl(20:18)			BIT8
0	0	0	0	0	0	0	0	

BIT7

recv_pmeter3 strt_intrvl(17:16)	unused	unused	unused	ssel_delay_line_3(2:0)				BIT0
0	0	0	0	0	0	0	0	

recv\_pmeter3\_sqr\_sum(20:16) : MSBs of sqr\_sum value, in 8 sample units

recv\_pmeter3 strt\_intrvl(20:16) : MSBs of start interval value, in 8 sample units

ssel\_delay\_line\_3(2:0) : Sync source selection for the 64 sample delay line pointer value update

**Register name: RECV\_SLF\_TST\_VALUE****Page: 0x1800****Address: 0x18**

BIT15

self_test_constant(15:8)								BIT8
0	0	0	0	0	0	0	0	

BIT7

self_test_constant(7:0)								BIT0
0	0	0	0	0	0	0	0	

self\_test\_constant(15:0) : 16 bit constant presented at the test and noise generator output when enabled. Used for test and debug purposes.

**Register name: RECV\_PMETER0\_LSB****Page: 0x1820**

**Address: 0x20****READ ONLY**

BIT15

BIT8

recv\_pmeter0(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter0(15:0) : Lower bits of the power meter 0 measurement

**Register name: RECV\_PMETER0\_MID****Page: 0x1820****Address: 0x21****READ ONLY**

BIT15

BIT8

recv\_pmeter0(31:24)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter0(31:16) : Mid bits of the power meter 0 measurement

**Register name: RECV\_PMETER0\_LMSB****Page: 0x1820****Address: 0x22****READ ONLY**

BIT15

BIT8

recv\_pmeter0(47:40)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter0(47:32) : Lower MSB bits of the power meter 0 measurement

**Register name: RECV\_PMETER0\_UMSB****Page: 0x1820****Address: 0x23****READ ONLY**

BIT15

BIT8

recv\_pmeter0(57:56)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter0(57:48) : Upper MSB bits of the power meter 0 measurement

**Register name: RECV\_PMETER1\_LSB****Page: 0x1820**

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**Address: 0x24****READ ONLY**

BIT15

BIT8

recv\_pmeter1(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter1(15:0) : Lower bits of the power meter 1 measurement

**Register name: RECV\_PMETER1\_MID****Page: 0x1820****Address: 0x25****READ ONLY**

BIT15

BIT8

recv\_pmeter1(31:24)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter1(31:16) : Mid bits of the power meter 1 measurement

**Register name: RECV\_PMETER1\_LMSB****Page: 0x1820****Address: 0x26****READ ONLY**

BIT15

BIT8

recv\_pmeter1(47:40)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter1(47:32) : Lower MSB bits of the power meter 1 measurement

**Register name: RECV\_PMETER1\_UMSB****Page: 0x1820****Address: 0x27****READ ONLY**

BIT15

BIT8

unused unused unused unused unused unused recv\_pmeter1(57:56)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter1(57:48) : Upper MSB bits of the power meter 1 measurement

**Register name: RECV\_PMETER2\_LSB****Page: 0x1820**

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**Address: 0x28****READ ONLY**

BIT15

BIT8

recv\_pmeter2(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

recv\_pmeter2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

recv\_pmeter2(15:0) : Lower bits of the power meter 2 measurement

**Register name: RECV\_PMETER2\_MID****Page: 0x1820****Address: 0x29****READ ONLY**

BIT15

BIT8

recv\_pmeter2(31:24)

0	0	0	0	0	0	0	0
BIT7							BIT0

recv\_pmeter2(23:16)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

recv\_pmeter2(31:16) : Mid bits of the power meter 2 measurement

**Register name: RECV\_PMETER2\_LMSB****Page: 0x1820****Address: 0x2A****READ ONLY**

BIT15

BIT8

recv\_pmeter2(47:40)

0	0	0	0	0	0	0	0
BIT7							BIT0

recv\_pmeter2(39:32)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

recv\_pmeter2(47:32) : Lower MSB bits of the power meter 2 measurement

**Register name: RECV\_PMETER2\_UMSB****Page: 0x1820****Address: 0x2B****READ ONLY**

BIT15

BIT8

unused unused unused unused unused unused recv\_pmeter2(57:56)

0	0	0	0	0	0	0	0
BIT7							BIT0

recv\_pmeter2(55:48)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

recv\_pmeter2(57:48) : Upper MSB bits of the power meter 2 measurement

**Register name: RECV\_PMETER3 LSB****Page: 0x1820**

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**Address: 0x2C****READ ONLY**

BIT15

BIT8

recv\_pmeter3(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter3(15:0) : Lower bits of the power meter 3 measurement

**Register name: RECV\_PMETER3\_MID****Page: 0x1820****Address: 0x2D****READ ONLY**

BIT15

BIT8

recv\_pmeter3(31:24)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter3(31:16) : Mid bits of the power meter 3 measurement

**Register name: RECV\_PMETER3\_LMSB****Page: 0x1820****Address: 0x2E****READ\_ONLY**

BIT15

BIT8

recv\_pmeter3(47:40)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter3(47:32) : Lower MSB bits of the power meter 3 measurement

**Register name: RECV\_PMETER3\_UMSB****Page: 0x1820****Address: 0x2F****READ\_ONLY**

BIT15

BIT8

unused unused unused unused unused unused recv\_pmeter3(57:56)

0	0	0	0	0	0	0	0
BIT7							BIT0
0	0	0	0	0	0	0	0

recv\_pmeter3(55:48)

recv\_pmeter3(57:48) : Upper MSB bits of the power meter 3 measurement

## 3.5.4 Receive AGC Controls(Pages 0x1840 and 0x1860)

## Register name: RAGC\_CONFIG0

Page: 0x1840

Address: 0x0

BIT15								BIT8
hp_ena_0	Hp_ena_1	hp_ena_2	hp_ena_3	sd_ena_0	sd_ena_1	sd_ena_2	sd_ena_3	0
0	0	0	0	0	0	0	0	BIT0
BIT7								BIT0
ragc_bypass_0	ragc_bypass_1	ragc_bypass_2	ragc_bypass_3	unused	unused	unused	unused	1
1	1	1	1	0	0	0	0	0

hp\_ena\_X : Enables the high pass filter in receive AGC X when set.  
 sd\_ena\_X : Enables the Signal Detect block in receive AGC X when set.  
 ragc\_bypass\_X : Bypasses the receive AGC X block when set.

## Register name: RAGC\_CONFIG1

Page: 0x1840

Address: 0x1

BIT15								BIT8
ragc_freeze_0	ragc_freeze_1	ragc_freeze_2	ragc_freeze_3	ragc_clear_0	ragc_clear_1	ragc_clear_2	ragc_clear_3	0
0	0	0	0	0	0	0	0	BIT0
BIT7								BIT0
complex01	complex23	ssel_ragc_interval_0(2:0)			ssel_ragc_interval_1(2:0)			0
0	0	0	0	0	0	0	0	0

ragc\_freeze\_X : Freezes the receive AGC block when set.  
 ragc\_clear\_X : Clears the loop error accumulator when set.  
 complex01 : When set, receive AGC 0 uses complex input with the second sample stream coming from receive AGC 1. The clip detect, high pass, and squarer from receive AGC 1 are used to generate inputs for receive AGC 0.  
 complex23 : When set, receive AGC 2 uses complex input with the second sample stream coming from receive AGC 3. The clip detect, high pass, and squarer from receive AGC 3 are used to generate inputs for receive AGC 2.  
 ssel\_ragc\_interval\_0(2:0) : Selects the sync source for receive AGC 0. After a programmed delay from sync, the interval update timer is started.  
 ssel\_ragc\_interval\_1(2:0) : Selects the sync source for receive AGC 1. After a programmed delay from sync, the interval update timer is started.

## Register name: RAGC\_CONFIG2

Page: 0x1840

**Address: 0x2**

BIT15

BIT8

ssel_ragc_freeze_0(2:0)			ssel_ragc_freeze_1(2:0)			ssel_ragc_freeze_2(2:1)	
0	0	0	0	0	0	0	0
ssel_ragc_freeze_2(0)			ssel_ragc_freeze_3(2:0)			ssel_ragc_interval_2(2:0)	
0	0	0	0	0	0	0	0

ssel\_ragc\_freeze\_X(2:0) : Selects the sync source that will freeze the receive AGC loop when asserted.

ssel\_ragc\_interval\_2(2:0) : Selects the sync source for receive AGC 2. After a programmed delay from sync, the interval update timer is started.

**Register name: RAGC\_CONFIG3****Page: 0x1840****Address: 0x3**

BIT15

BIT8

ssel_ragc_clear_0(2:0)			ssel_ragc_clear_1(2:0)			ssel_ragc_clear_2(2:1)	
0	0	0	0	0	0	0	0
ssel_ragc_clear_2(0)			ssel_ragc_clear_3(2:0)			ssel_ragc_interval_3(2:0)	
0	0	0	0	0	0	0	0

ssel\_agc\_clear\_X(2:0) : Controls the selection of the sync that will clear the receive AGC error accumulator.

ssel\_agc\_interval\_3(2:0) : Selects the sync source for receive AGC 3. After a programmed delay from sync, the interval update timer is started.

**Register name: RAGC0\_INTEGRINVL\_LSB****Page: 0x1840****Address: 0x4**

BIT15

BIT8

integ_interval_0(15:8)							
0	0	0	0	0	0	0	0
BIT7							
integ_interval_0(7:0)							
0	0	0	0	0	0	0	0

integ\_interval\_0(15:0) : The 16 LSBs of the integration time for receive AGC 0

**Register name: RAGC0\_INTEGRINVL\_MSB****Page: 0x1840****Address: 0x5**

BIT15

BIT8

ragc\_update\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

integ\_interval\_0(23:16)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

ragc\_update\_0(7:0) : Sets the number of receive AGC updates per sync event (0x00 is infinite).

integ\_interval\_0(23:16) : The eight MSBs of the integration time for receive AGC 0

**Register name: RAGC0\_CONFIG0****Page: 0x1840****Address: 0x6**

BIT15

BIT8

ragc\_sync\_delay\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

hp\_corner\_0(2:0)

acc\_shift\_0(4:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

ragc\_sync\_delay\_0(7:0) : The input sync to the receive AGC block is delayed by this number of samples.

hp\_corner\_0(2:0) : Sets the corner frequency of the high pass filter. Larger values result in higher corner frequencies

acc\_shift\_0(4:0) : Selects the integrated power measurements result bits to be used as the error lookup table address. A larger number means fewer samples will have to be integrated to achieve the same result.

**Register name: RAGC0\_CONFIG1****Page: 0x1840****Address: 0x7**

BIT15

BIT8

acc\_offset\_0(5:0)

err\_shift\_0(4:3)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

err\_shift\_0(2:0)

delay\_adj\_0(4:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

acc\_offset\_0(5:0) : Constant subtracted from the integrated power measurement result before the error lookup table.

err\_shift\_0(4:0) : Adjusts the loop gain by controlling the amount of shifting applied to the error lookup table output. Larger values result in higher gain.

delay\_adj\_0(4:0) : Sets the delay difference, in samples, between the DVGA outputs and the value applied to the sample multiplier.

**Register name: RAGC0\_SD\_THRESH****Page: 0x1840****Address: 0x8**

BIT15

BIT8

sd\_thresh\_0(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

sd\_thresh\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

sd\_thresh\_0(15:0) : This is the threshold used by the Signal Detect block to determine if there is signal on the inputs. The comparison is done to the output of the squarer block, which is a 32 bit word. Because of this, these bits are aligned with bits 24 down to 8 of the 32 bit squared value.

#### Register name: RAGC0\_SD\_TIMER

Page: 0x1840

Address: 0x9

BIT15

BIT8

sd\_timer\_0(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

sd\_timer\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

sd\_timer\_0(15:0) : Qualification window timer for loss of input signal.

#### Register name: RAGC0\_SD\_SAMPLES

Page: 0x1840

Address: 0xA

BIT15

BIT8

sd\_samples\_0(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

sd\_samples\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

sd\_samples\_0(15:0) : Number of samples that must be below the sd\_thresh\_X within the sd\_timer\_X timer value for the loss of signal condition to occur.

#### Register name: RAGC0\_CLIP\_HITHRESH

Page: 0x1840

Address: 0xB

BIT15

BIT8

clip\_hi\_thresh\_0(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_hi\_thresh\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_thresh\_0(15:0) : The high threshold value for clip detection.

#### Register name: RAGC0\_CLIP\_LOTHRESH

Page: 0x1840

Address: 0xC

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BIT15

BIT8

clip\_lo\_thresh\_0(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_thresh\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_lo\_thresh\_0(15:0) : The low threshold value for clip detection.

**Register name: RAGC0\_CLIP\_HITIMER****Page: 0x1840****Address: 0xD**

BIT15

BIT8

clip\_hi\_timer\_0(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_hi\_timer\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_timer\_0(15:0) : The high timer value in Samples

**Register name: RAGC0\_CLIP\_LOTIMER****Page: 0x1840****Address: 0xE**

BIT15

BIT8

clip\_lo\_timer\_0(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_timer\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_lo\_timer\_0(15:0) : The low timer value in Samples.

**Register name: RAGC0\_CLIP\_SAMPLES****Page: 0x1840****Address: 0xF**

BIT15

BIT8

clip\_hi\_samples\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_samples\_0(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_samples\_0(7:0) : Number of samples above the high threshold within the clip high time to enable the clip event.

clip\_lo\_samples\_0(7:0) : Number of samples below the low threshold within the clip low time to disable the clip event.

**Register name: RAGC0\_CLIP\_ERROR****Page: 0x1840**

**Address: 0x10**

clip_error_0(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT7
clip_error_0(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

clip\_error\_0(15:0) : This is the error value that is added into the loop accumulator when a clip is detected.

**Register name: RAGC1\_INTEGRINV1\_LSB****Page: 0x1840****Address: 0x11**

integ_interval_1(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT7
integ_interval_1(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

integ\_interval\_1(15:0) : The LSBs of the integration time for receive AGC 1

**Register name: RAGC1\_INTEGRINV1\_MSB****Page: 0x1840****Address: 0x12**

ragc_update_1(7:0)								BIT8
0	0	0	0	0	0	0	0	BIT7
integ_interval_1(23:16)								BIT0
0	0	0	0	0	0	0	0	BIT0

ragc\_update\_1(7:0) : Sets the number of receive AGC updates per sync event (0x00 is infinite).

integ\_interval\_1(23:16) : The MSBs of the integration time for receive AGC 1

**Register name: RAGC1\_CONFIG0****Page: 0x1840****Address: 0x13**

ragc_sync_delay_1(7:0)								BIT8
0	0	0	0	0	0	0	0	BIT7
hp_corner_1(2:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

ragc\_sync\_delay\_1(7:0) : The input sync to the receive AGC block is delayed by this value of samples.

hp\_corner\_1(2:0) : This sets the corner frequency of the High Pass filter. Larger values result in higher corner frequencies.

acc\_shift\_1(4:0) : Selects the integrated power measurements result bits to be used as the error lookup table address. A larger number means fewer samples will have to be integrated to achieve the same result.

**Register name: RAGC1\_CONFIG1****Page: 0x1840****Address: 0x14**

BIT15

acc_offset_1(5:0)						err_shift_1(4:3)	
0	0	0	0	0	0	0	0
err_shift_1(2:0)						delay_adj_1(4:0)	
0	0	0	0	0	0	0	0

acc\_offset\_1(5:0) : Constant subtracted from the integrated power measurement result before the error lookup table.  
 err\_shift\_1(4:0) : Controls the loop gain by left shifting the error output. Larger values result in higher gain.  
 delay\_adj\_1(4:0) : Sets the delay difference, in samples, between the DVGA outputs and the value applied to the sample multiplier.

**Register name: RAGC1\_SD\_THRESH****Page: 0x1840****Address: 0x15**

BIT15

sd_thresh_1(15:8)							
0	0	0	0	0	0	0	0
sd_thresh_1(7:0)							
0	0	0	0	0	0	0	0

sd\_thresh\_1(15:0) : This is the threshold used by the Signal Detect block to determine if there is signal on the inputs. The comparison is done to the output of the squarer block, which is a 32 bit word. Because of this, these bits are aligned with bits 24 down to 8 of the 32 bit squared value.

**Register name: RAGC1\_SD\_TIMER****Page: 0x1840****Address: 0x16**

BIT15

sd_timer_1(15:8)							
0	0	0	0	0	0	0	0
sd_timer_1(7:0)							
0	0	0	0	0	0	0	0

sd\_timer\_1(15:0) : After the first no signal sample occurs, this is the amount of samples that control the length of time to determine the loss of signal condition.

**Register name: RAGC1\_SD\_SAMPLES****Page: 0x1840****Address: 0x17**

BIT15

BIT8

sd\_samples\_1(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

sd\_samples\_1(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

sd\_samples\_1(15:0) : Number of samples that must be below the sd\_thresh\_X threshold within the sd\_timer\_X timer value for the loss of signal condition to occur.

#### Register name: RAGC1\_CLIP\_HITHRESH

Page: 0x1840

Address: 0x18

BIT15

BIT8

clip\_hi\_thresh\_1(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_hi\_thresh\_1(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_thresh\_1(15:0) : The high threshold value for clip detection.

#### Register name: RAGC1\_CLIP\_LOTHRESH

Page: 0x1840

Address: 0x19

BIT15

BIT8

clip\_lo\_thresh\_1(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_thresh\_1(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_lo\_thresh\_1(15:0) : The low threshold value for clip detection.

#### Register name: RAGC1\_CLIP\_HITIMER

Page: 0x1840

Address: 0x1A

BIT15

BIT8

clip\_hi\_timer\_1(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_hi\_timer\_1(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_timer\_1(15:0) : The high timer value in samples.

#### Register name: RAGC1\_CLIP\_LOTIMER

Page: 0x1840

Address: 0x1B

BIT15

BIT8

clip\_lo\_timer\_1(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_timer\_1(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_lo\_timer\_1(15:0) : The low timer value in samples.

**Register name: RAGC1\_CLIP\_SAMPLES****Page: 0x1840****Address: 0x1C**

BIT15

BIT8

clip\_hi\_samples\_1(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_samples\_1(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_samples\_1(7:0) : Number of samples above the high threshold within the clip high time to enable the clip event.  
clip\_lo\_samples\_1(7:0) : Number of samples below the low threshold within the clip low time to disable the clip event.**Register name: RAGC1\_CLIP\_ERROR****Page: 0x1840****Address: 0x1D**

BIT15

BIT8

clip\_error\_1(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_error\_1(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_error\_1(15:0) : This is the error value that is added into the loop accumulator when a clip is detected.

**Register name: RAGC2\_INTEGINVL\_LSB****Page: 0x1840****Address: 0x1E**

BIT15

BIT8

integ\_interval\_2(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

integ\_interval\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

integ\_interval\_2(15:0) : The LSBs of the integration time for receive AGC 2

**Register name: RAGC2\_INTEGINVL\_MSB****Page: 0x1840**

**Address: 0x1F**

BIT15

BIT8

## ragc\_update\_2(7:0)

0	0	0	0	0	0	0	0
BIT7							BIT0

## integ\_interval\_2(23:16)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

ragc\_update\_2(7:0) : Sets the number of receive AGC updates per sync event (0x00 is infinite).

integ\_interval\_2(23:16) : The MSBs of the integration time for receive AGC 2

**Register name: RAGC2\_CONFIG0****Page: 0x1860****Address: 0x20**

BIT15

BIT8

## ragc\_sync\_delay\_2(7:0)

0	0	0	0	0	0	0	0
BIT7							BIT0

## hp\_corner\_2(2:0)

## acc\_shift\_2(4:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

ragc\_sync\_delay\_2(7:0) : The input sync to the receive AGC block is delayed by this value of samples.

hp\_corner\_2(2:0) : This sets the corner frequency of the High Pass filter. Larger values result in higher corner frequencies.

acc\_shift\_2(4:0) : Selects the integrated power measurements result bits to be used as the error lookup table address. A larger number means fewer samples will have to be integrated to achieve the same result.

**Register name: RAGC2\_CONFIG1****Page: 0x1860****Address: 0x21**

BIT15

BIT8

## acc\_offset\_2(5:0)

## err\_shift\_2(4:3)

0	0	0	0	0	0	0	0
BIT7							BIT0

## err\_shift\_2(2:0)

## delay\_adj\_2(4:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

acc\_offset\_2(5:0) : Constant subtracted from the integrated power measurement result before the error lookup table.

err\_shift\_2(4:0) : Controls the loop gain by left shifting the error output. Larger values result in higher gain..

delay\_adj\_2(4:0) : Sets the delay difference, in samples, between the DVGA outputs and the value applied to the sample multiplier.

**Register name: RAGC2\_SD\_THRESH****Page: 0x1860****Address: 0x22**

BIT15

BIT8

sd\_thresh\_2(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

sd\_thresh\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

sd\_thresh\_2(15:0) : This is the threshold used by the Signal Detect block to determine if there is signal on the inputs. The comparison is done to the output of the squarer block, which is a 32 bit word. Because of this, these bits are aligned with bits 24 down to 8 of the 32 bit squared value.

**Register name: RAGC2\_SD\_TIMER****Page: 0x1860****Address: 0x23**

BIT15

BIT8

sd\_timer\_2(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

sd\_timer\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

sd\_timer\_2(15:0) : After the first no signal sample occurs, this is the amount of samples that control the length of time to determine the loss of signal condition.

**Register name: RAGC2\_SD\_SAMPLES****Page: 0x1860****Address: 0x24**

BIT15

BIT8

sd\_samples\_2(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

sd\_samples\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

sd\_samples\_2(15:0) : Number of samples that must be below the sd\_thresh\_X threshold within the sd\_timer\_X timer value for the loss of signal condition to occur.

**Register name: RAGC2\_CLIP\_HITHRESH****Page: 0x1860****Address: 0x25**

BIT15

BIT8

clip\_hi\_thresh\_2(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_hi\_thresh\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_thresh\_2(15:0) : The high threshold value for clip detection.

**Register name: RAGC2\_CLIP\_LOTHRESH****Page: 0x1860****Address: 0x26**

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BIT15

BIT8

clip\_lo\_thresh\_2(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_thresh\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_lo\_thresh\_2(15:0) : The low threshold value for clip detection.

**Register name: RAGC2\_CLIP\_HITIMER****Page: 0x1860****Address: 0x27**

BIT15

BIT8

clip\_hi\_timer\_2(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_hi\_timer\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_timer\_2(15:0) : The high timer value in samples

**Register name: RAGC2\_CLIP\_LOTIMER****Page: 0x1860****Address: 0x28**

BIT15

BIT8

clip\_lo\_timer\_2(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_timer\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_lo\_timer\_2(15:0) : The low timer value in samples.

**Register name: RAGC2\_CLIP\_SAMPLES****Page: 0x1860****Address: 0x29**

BIT15

BIT8

clip\_hi\_samples\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

clip\_lo\_samples\_2(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_samples\_2(7:0) : Number of samples above the high threshold within the clip high time to enable the clip event.

clip\_lo\_samples\_2(7:0) : Number of samples below the low threshold within the clip low time to disable the clip event.

**Register name: RAGC2\_CLIP\_ERROR****Page: 0x1860**

**Address: 0x2A**

clip_error_2(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT7
clip_error_2(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

clip\_error\_2(15:0) : This is the error value that is added into the loop accumulator when a clip is detected.

**Register name: RAGC3\_INTEGRINVL\_LSB****Page: 0x1860****Address: 0x2B**

integ_interval_3(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT7
integ_interval_3(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

integ\_interval\_3(15:0) : The LSBs of the integration time for receive AGC 3

**Register name: RAGC3\_INTEGRINVL\_MSB****Page: 0x1860****Address: 0x2C**

ragc_update_3(7:0)								BIT8
0	0	0	0	0	0	0	0	BIT7
integ_interval_3(23:16)								BIT0
0	0	0	0	0	0	0	0	BIT0

ragc\_update\_3(7:0) : Sets the number of receive AGC updates per sync event (0x00 is infinite).

integ\_interval\_3(23:16) : The MSBs of the integration time for receive AGC 3

**Register name: RAGC3\_CONFIG0****Page: 0x1860****Address: 0x2D**

ragc_sync_delay_3(7:0)								BIT8
0	0	0	0	0	0	0	0	BIT7
hp_corner_3(2:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

ragc\_sync\_delay\_3(7:0) : The input sync to the receive AGC block is delayed by this value of samples.

hp\_corner\_3(2:0) : This sets the corner frequency of the High Pass filter. Larger values result in higher corner frequencies.

acc\_shift\_3(4:0) : Selects the integrated power measurements result bits to be used as the error lookup table address. A larger number means fewer samples will have to be integrated to achieve the same result.

**Register name: RAGC3\_CONFIG1****Page: 0x1860****Address: 0x2E**

BIT15

acc_offset_3(5:0)						err_shift_3(4:3)	
0	0	0	0	0	0	0	0
err_shift_3(2:0)						delay_adj_3(4:0)	
0	0	0	0	0	0	0	0

acc\_offset\_3(5:0) : Constant subtracted from the integrated power measurement result before the error lookup table.  
 err\_shift\_3(4:0) : Controls the loop gain by left shifting the error output. Larger values result in higher gain.  
 delay\_adj\_3(4:0) : Sets the delay difference, in samples, between the DVGA outputs and the value applied to the sample multiplier.

**Register name: RAGC3\_SD\_THRESH****Page: 0x1860****Address: 0x2F**

BIT15

sd_thresh_3(15:8)							
0	0	0	0	0	0	0	0
sd_thresh_3(7:0)							
0	0	0	0	0	0	0	0

sd\_thresh\_3(15:0) : This is the threshold used by the Signal Detect block to determine if there is signal on the inputs. The comparison is done to the output of the squarer block, which is a 32 bit word. Because of this, these bits are aligned with bits 24 down to 8 of the 32 bit squared value.

**Register name: RAGC3\_SD\_TIMER****Page: 0x1860****Address: 0x30**

BIT15

sd_timer_3(15:8)							
0	0	0	0	0	0	0	0
sd_timer_3(7:0)							
0	0	0	0	0	0	0	0

sd\_timer\_3(15:0) : After the first no signal sample occurs, this is the amount of samples that control the length of time to determine the loss of signal condition.

**Register name: RAGC3\_SD\_SAMPLES****Page: 0x1860**

**Address: 0x31**

BIT15

BIT8

## sd\_samples\_3(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

## sd\_samples\_3(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

sd\_samples\_3(15:0) : Number of samples that must be below the sd\_thresh\_X threshold within the sd\_timer\_X timer value for the loss of signal condition to occur.

**Register name: RAGC3\_CLIP\_HITHRESH****Page: 0x1860****Address: 0x32**

BIT15

BIT8

## clip\_hi\_thresh\_3(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

## clip\_hi\_thresh\_3(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_thresh\_3(15:0) : The high threshold value for clip detection.

**Register name: RAGC3\_CLIP\_LOTHRESH****Page: 0x1860****Address: 0x33**

BIT15

BIT8

## clip\_lo\_thresh\_3(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

## clip\_lo\_thresh\_3(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_lo\_thresh\_3(15:0) : The low threshold value for clip detection.

**Register name: RAGC3\_CLIP\_HITIMER****Page: 0x1860****Address: 0x34**

BIT15

BIT8

## clip\_hi\_timer\_3(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

## clip\_hi\_timer\_3(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_timer\_3(15:0) : The clip high timer value in samples

**Register name: RAGC3\_CLIP\_LOTIMER****Page: 0x1860**

**Address: 0x35**

BIT15

BIT8

## clip\_lo\_timer\_3(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

## clip\_lo\_timer\_3(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_lo\_timer\_3(15:0) : The clip low timer value in samples.

**Register name: RAGC3\_CLIP\_SAMPLES****Page: 0x1860****Address: 0x36**

BIT15

BIT8

## clip\_hi\_samples\_3(7:0)

0	0	0	0	0	0	0	0
BIT7							BIT0

## clip\_lo\_samples\_3(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_hi\_samples\_3(7:0) : Number of samples above the high threshold within the clip high time to enable a clip event.  
clip\_lo\_samples\_3(7:0) : Number of samples below the low threshold within the clip low time to disable a clip event.**Register name: RAGC3\_CLIP\_ERROR****Page: 0x1860****Address: 0x37**

BIT15

BIT8

## clip\_error\_3(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

## clip\_error\_3(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

clip\_error\_3(15:0) : Error value that is added into the loop accumulator when a clip is detected.

**Register name: RAGC0\_ACCUM\_LSB****Page: 0x1860****Address: 0x38****READ ONLY**

BIT15

BIT8

## ragc0\_accum(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

## ragc0\_accum (7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

ragc0\_accum(15:0) : lower 16 bits of the ragc0 error accumulator.

**Register name: RAGC0\_ACCUM\_MSB****Page: 0x1860**

**Address: 0x39****READ ONLY**

BIT15

BIT8

ragc0\_accum(31:24)

0	0	0	0	0	0	0	0
BIT7							BIT0

ragc0\_accum(23:16)

0	0	0	0	0	0	0	0

ragc0\_accum(31:16) : upper 16 bits of the ragc0 error accumulator.

**Register name: RAGC1\_ACCUM\_LSB****Page: 0x1860****Address: 0x3A****READ ONLY**

BIT15

BIT8

ragc1\_accum(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

ragc1\_accum(7:0)

0	0	0	0	0	0	0	0

ragc1\_accum(15:0) : lower 16 bits of the ragc1 error accumulator.

**Register name: RAGC1\_ACCUM\_MSB****Page: 0x1860****Address: 0x3B****READ ONLY**

BIT15

BIT8

ragc1\_accum(31:24)

0	0	0	0	0	0	0	0
BIT7							BIT0

ragc1\_accum(23:16)

0	0	0	0	0	0	0	0

ragc1\_accum(31:16) : upper 16 bits of the ragc1 error accumulator.

**Register name: RAGC2\_ACCUM\_LSB****Page: 0x1860****Address: 0x3C****READ ONLY**

BIT15

BIT8

ragc2\_accum(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

ragc2\_accum(7:0)

0	0	0	0	0	0	0	0

ragc2\_accum(15:0) : lower 16 bits of the ragc2 error accumulator.

**Register name: RAGC2\_ACCUM\_MSB****Page: 0x1860**

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**Address: 0x3D****READ ONLY**

BIT15

BIT8

ragc2\_accum(31:24)

0	0	0	0	0	0	0	0
BIT7							BIT0

ragc2\_accum (23:16)

0	0	0	0	0	0	0	0

ragc2\_accum(31:16) : upper 16 bits of the ragc2 error accumulator.

**Register name: RAGC3\_ACCUM\_LSB****Page: 0x1860****Address: 0x3E****READ ONLY**

BIT15

BIT8

ragc3\_accum(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

ragc3\_accum (7:0)

0	0	0	0	0	0	0	0

ragc3\_accum(15:0) : lower 16 bits of the ragc3 error accumulator.

**Register name: RAGC3\_ACCUM\_MSB****Page: 0x1860****Address: 0x3F****READ ONLY**

BIT15

BIT8

ragc3\_accum(31:24)

0	0	0	0	0	0	0	0
BIT7							BIT0

ragc3\_accum (23:16)

0	0	0	0	0	0	0	0

ragc3\_accum(31:16) : upper 16 bits of the ragc3 error accumulator.

## 3.5.5 DDC Channel Controls (Pages 0x0%00 and 0x0%20, where % = 1 to F is the 2\*(DDC channel #)+1)

## Register name: FIR\_MODE

Page: 0x0%00, where % = 2\*(DDC channel #)+1

Address: 0x0

cdma_mode	unused	unused	crastarttap_pfir(4:0)				BIT8	
0	0	0	0	0	0	0	0	
BIT7								
crastarttap_cfir(4:0)					unused	unused	unused	
0	0	0	0	0	0	0	0	

cdma\_mode : When asserted the DDC block is in CDMA mode (2 streams per DDC block).

crastarttap\_pfir : These bits define the number of taps that PFIR will use for the filtering.

crastarttap\_cfir : These bits define the number of taps that CFIR will use for the filtering.

Formulas for the number of taps, in the different FIR's, using the crastarttap word.

DDC PFIR:  $4 * (\text{crastarttap\_pfir} + 1)$ DDC PFIR long mode:  $8 * (\text{crastarttap\_pfir} + 1)$ DDC CFIR:  $2 * (\text{crastarttap\_cfir} + 1)$ 

## Register name: FIR\_GAIN

Page: 0x0%00, where % = 2\*(DDC channel #)+1

Address: 0x1

pfir_gain(2:0)	unused	unused	unused	unused	BIT8
0	0	0	0	0	0
BIT7					
unused	unused	cfir_gain	unused	unused	unused
0	0	0	0	0	0

pfir\_gain(2:0) : PFIR gain, from 2e-19 to 2e-12 for the receive PFIR. ("000" = 2e-19 and "111" = 2e-12)

cfir\_gain : When '0' then the gain of the CFIR is 2e-19, otherwise when set to '1' the gain is 2e-18.

## Register name: SQR\_SUM

Page: 0x0%00, where % = 2\*(DDC channel #)+1

Address: 0x2

pmeter_sqr_sum_ddc(15:8)	BIT8
0	0
BIT7	
pmeter_sqr_sum_ddc(7:0)	BIT0
0	0

pmeter\_sqr\_sum\_ddc(15:0): The sqr\_sum register is the number of 4 sample sets to accumulate for a power measurement.

In CDMA mode, one sample set is the I & Q of the signal and diversity. Ia & Qa (signal) are each squared and accumulated and Ib & Qb (diversity) are squared and accumulated. In UMTS mode, each I and Q pair are squared and accumulated. 4 samples is equal to one SQR\_SUM count. The count is initiated when the sync is asserted or when the interval start time is reached. When the SQR\_NUM number is reached, the accumulated powers are made available for MPU access and an interrupt is generated.

**Register name: STRT\_INTRVL****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x3**

BIT15	pmeter_sync_delay_ddc(7:0)								BIT8
0	0	0	0	0	0	0	0	0	
BIT7	pmeter_interval_ddc(7:0)								BIT0
0	0	0	0	0	0	0	0	0	

**pmeter\_sync\_delay\_ddc(7:0):** The delay from selected sync source to when the power calculation starts. The actual value is *sync\_delay* + 1.

**pmeter\_interval\_ddc(7:0) :** The start interval timer is the interval over which the SQR\_SUM is restarted and must be greater than the SQR\_SUM. **The actual interval is *interval* + 1, and must be greater than the *sqr\_sum* interval.** The interval start counter and RMS power accumulation is started at the sync pulse after the programmed delay and every time the interval counter reaches its limit. This value is in 1024 sample units.

**Register name: CIC\_MODE1****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x4**

BIT15	cic_scale_a(4:0)					cic_scale_b(4:2)			BIT8
0	0	0	0	0	0	0	0	0	
BIT7	cic_scale_b(1:0)					cic_decim(4:0)			
0	0	0	0	0	0	0	0	0	

**cic\_scale\_a(4:0) :** This sets the gain shift at the output of the A channel CIC. 0x00 is no shift, each increment by 1 increases the signal amplitude by 2X.

**cic\_scale\_b(4:0) :** This sets the gain shift at the output of the B channel CIC. 0x00 is no shift, each increment by 1 increases the signal amplitude by 2X.

**cic\_gain\_ddc :** Adds a fixed gain of 12dB at the CIC output when asserted.

**cic\_decim(4:0) :** Sets the CIC decimation rate, where decimation is *cic\_decim* + 1.

**Register name: CIC\_MODE2****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x5**

BIT15	cic_m2_ena_a(5:0)						cic_m2_ena_b(5:4)		BIT8
0	0	0	0	0	0	0	0	0	
BIT7	cic_m2_ena_b(3:0)						unused	unused	unused
0	0	0	0	0	0	0	0	0	

**cic\_m2\_ena\_a(5:0) :** Programs the A channel CIC fir sections M value to 2 when set, 1 when cleared. cic\_m2\_ena\_a(0) controls the M value for the first comb section and cic\_m2\_ena\_a(5) controls the M value for the last comb section.

**cic\_m2\_ena\_b(5:0) :** Programs the B channel CIC fir sections M value to 2 when set, 1 when cleared. cic\_m2\_ena\_b(0) controls the M value for the first comb section and cic\_m2\_ena\_b(5) controls the M value for the last comb section.

**Register name: TADJC****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x6****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

BIT15							BIT8
unused	unused	unused	tadj_offset_coarse_a(2:0)	unused	unused	unused	unused
0	0	0	0	0	0	0	0
BIT7							BIT0
unused	tadj_offset_coarse_b(2:0)		unused	unused	unused	unused	unused
0	0	0	0	0	0	0	0

**tadj\_offset\_coarse\_a(2:0)** : This is the coarse time adjustment offset and acts as an offset from the write address in the delay ram. This value affects the A data in the path if CDMA mode is being used. Each LSB is one more offset between input to the coarse delay block and the output of the coarse block.

**tadj\_offset\_coarse\_b(2:0)** : Effects the B channel in CDMA, just as the above effects the A channel.

**Register name: TADJF****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x7****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

BIT15							BIT8
tadj_offset_fine_a(2:0)			tadj_offset_fine_b(2:0)			tadj_interp(2:1)	
0	0	0	0	0	0	0	0
BIT7							BIT0
tadj_interp(0)	unused	unused	unused	unused	unused	unused	unused
0	0	0	0	0	0	0	0

**tadj\_offset\_fine\_a(2:0)** : This is the fine adjust (zero stuff offset) value. It adjusts the time delay at the rxclk rate. This value affects the A channel data in the path if CDMA mode is being used.

**tadj\_offset\_fine\_b(2:0)** : Same as above except this value affects the B channel data in CDMA mode.

**tadj\_interp(2:0)** : This is the interpolation (zero stuff) value for the fine time adjust block. Interpolation can be from 1 to 8 (tadj\_interp + 1). This value affects the A and B data in the path if CDMA mode is being used.

**Register name: PHASEADD0A****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x8****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

BIT15	phase_add_a(15:8)								BIT8
0	0	0	0	0	0	0	0	0	
BIT7	phase_add_a(7:0)								BIT0
0	0	0	0	0	0	0	0	0	

**phase\_add\_a(15:0)** : This 32 bit word is used to control the frequency of the NCO. This value is added to the frequency accumulator every clock cycle (*UMTS mode and Main channel in CDMA mode*).

**Register name: PHASEADD1A****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x9****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

BIT15	phase_add_a(31:24)								BIT8
0	0	0	0	0	0	0	0	0	
BIT7	phase_add_a(23:16)								BIT0
0	0	0	0	0	0	0	0	0	

**phase\_add\_a(31:16)** : This 32 bit word is used to control the frequency of the NCO. This value is added to the frequency accumulator every clock cycle (*UMTS mode and A channel in CDMA mode*).

**Register name: PHASEADD0B****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0xA****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

BIT15	phase_add_b(15:8)								BIT8
0	0	0	0	0	0	0	0	0	
BIT7	phase_add_b(7:0)								BIT0
0	0	0	0	0	0	0	0	0	

**phase\_add\_b(15:0)** : This 32 bit word is used to control the frequency of the NCO. This value is added to the frequency accumulator every clock cycle (*B channel in CDMA mode*).

**Register name: PHASEADD1B****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0xB****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

phase_add_b(31:24)								BIT8
0	0	0	0	0	0	0	0	BIT0
<b>BIT7</b>								
phase_add_b(23:16)								BIT0
0	0	0	0	0	0	0	0	BIT0

**phase\_add\_b(31:16)** : This 32 bit word is used to control the frequency of the NCO. This value is added to the frequency accumulator every clock cycle (*B channel in CDMA mode*).

**Register name: PHASE\_OFFSETA****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0xC****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

phase_offset_a(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT0
<b>BIT7</b>								
phase_offset_a(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

**phase\_offset\_a(15:0)** : This is the fixed phase offset added to the output of the frequency accumulator for sinusoid generation in the NCO. (*UMTS mode and A channel in CDMA mode*)

**Register name: PHASE\_OFFSETB****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0xD****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

phase_offset_b(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT0
<b>BIT7</b>								
phase_offset_b(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

**phase\_offset\_b(15:0)** : This is the fixed phase offset added to the output of the frequency accumulator for sinusoid generation in the NCO. (*B channel in CDMA mode*)

## Register name: CONFIG1

Page: 0x0%00, where % = 2\*(DDC channel #)+1

Address: 0xE

BIT15

dither_ena	dither_mask(1:0)	pmeter_sync_disable	ddc_ena	mixed_data	mixer_gain	mpu_ram_read	BIT8
0	0	0	0	0	0	1	0

BIT7

unused	unused	unused	unused	unused	zero_qsample	mux_pos	mux_factor	BIT0
0	0	0	0	0	0	0	0	0

dither\_ena : This bit controls whether dither is turned on(1) or off(0).

dither\_mask(1) : This bit controls the MASKing of the dither word's MSB. (1= MASKed, 0=used in dither word)

dither\_mask(0) : This bit controls the MASKing of the dither word's MSB-1. (1= MASKed, 0=used in dither word)

pmeter\_sync\_disable : Turns off the sync to the channel power meter. This can be used to individually turn off syncs to a channels power meter while still having syncs to other power meters available.

ddc\_ena : When set this turns on the DDC. When cleared, the clocks to this block are turned off. For the DDC blocks used as the second half in the long PFIR configuration, this bit should be cleared.

mixed\_data : When asserted the DDC mux block assumes that multiple channels are muxed together on one input data stream. *For factory use only.*  
For a 2X muxed stream it would look like: Sa0, Sb0, Sa1, Sb1, Sa2, Sb2 .... etc...

mixer\_gain : Adds a fixed 6 dB of gain to the mixer output(before round and limiting) when asserted.

mpu\_ram\_read : **(TESTING PURPOSES)** Allows the coefficient RAMs in the PFIR/CFIR to be read out the mpu data bus. Unfortunately, this cannot be done during normal operation and must be done when the state of the output data is not important. **THIS BIT MUST ONLY BE SET DURING THE MPU READ OPERATION AND MUST BE CLEARED FOR NORMAL DDC OPERATION.**

zero\_qsample : When asserted, the Q sample into the mixer is held to zero. For UMTS mode at any input rate, and CDMA mode with input rates of rxclk/2 or lower, this bit must be set for real only input data mode (also for muxed input data stream modes). For real only inputs at the full rxclk rate in CDMA mode, the remix\_only bit must be set in the DDCCONFIG1 register.

mux\_pos : These bits set the position for selection in the muxed data stream. This value must be less than or equal to the mux\_factor bits.

mux\_factor : These two bits set the number of channels in the data stream. 0=1 stream, 1=2 streams. The ch\_rate\_sel bits for the DDC should be programmed to rxclk/2 for the 2 streams mode.

## Register name: CONFIG2

Page: 0x0%00, where % = 2\*(DDC channel #)+1

Address: 0xF

BIT15

BIT8

unused							
0	0	0	0	0	0	0	0

BIT7	BIT0
unused	unused

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

ddc\_tst\_sel(5:0) : This is the selection of which signal comes out the test bus. When a constant '0' is selected this also reduces power by preventing the data at the input of the tst\_blk from changing. It does not stop the clock however. The 36bits for the testbus are routed to the rxin\_c, rxin\_d, dvga\_c and dvga\_d pins on the chip.

SYNC on dvga_c(0) AFLAG on dvga_d(5)	ddc_tst_sel(5:0)	Data selected for output (36 bits total) rxin_d(15:0), dvga_c(3:2), rxin_c(15:0), dvga_c(5:4)
N	000000	constant 0
Y	000001	pfir output - (35:18) I and (17:0) Q
Y	000010	cfir output - (35:18) I and (17:0) Q
N	000011	tadj A output - (35:18) I and (17:0) Q
N	000100	tadj B output - (35:18) I and (17:0) Q
N	000101	nco SINE output - (35:20) zeroed (19:0) SINE
N	000110	nco COSINE output - (35:20) zeroed (19:0) COSINE
Y	000111	cic output - (35:18) I and (17:0) Q
Y	001000	agc output - (35:11) I and (10:0) Q {full 25b I result and upper 11b Q result}
N	001001	mix A output - (35:18) i*cos-q*sin and (17:0) i*sin+q*cos
N	001010	mix B output - (35:18) i*cos-q*sin and (17:0) i*sin+q*cos
N	001011	DDC MUX A output (35:18) I and (17:0) Q
N	001100	DDC MUX B output (35:18) I and (17:0) Q

## Register name: AGC\_CONFIG1

Page: 0x0%00, where % = 2\*(DDC channel #)+1

Address: 0x10

BIT15

BIT8

agc_dblw(3:0)	agc_dabv(3:0)
0 0 0 0	0 0 0 0

BIT7	BIT0
agc_dzro(3:0)	agc_dsat(3:0)

0 0 0 0	0 0 0 0
---------	---------

agc\_dblw(3:0) : The value to shift the gain that is then added to the accumulator when the value of the incoming data \* current gain value is **below** the Threshold.

agc\_dabv(3:0) : The value to shift the gain that is then subtracted from the accumulator when the value of the incoming data \* the current gain value is **above** the Threshold.

agc\_dzro(3:0) : The value to shift the gain that is then added to the accumulator when the value of the incoming data \* current gain values **consistently equal to zero**. (Usually a smaller number than agc\_dblw).

agc\_dsat(3:0) : The value to shift the gain that is then subtracted from the accumulator when the value of the incoming data \* the current gain value is **consistently equal to maximum (saturation)**.

Note: The larger the number in the above words, the smaller the step size. The above values control the AGC gain shifting (range is from 3 to 18).

**Register name: AGC\_CONFIG2****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x11**

BIT15

BIT8

zero_msk(3:0)				agc_rnd(3:0)			
0	0	0	0	0	0	0	0

agc_thresh(7:0)							
0	0	0	0	0	0	0	0

zero\_msk(3:0) : Masks the lower 4 bits of the magnitude of the input signal so that they are counted as zeros.  
 agc\_rnd(3:0) : Determines where to round the output of the AGC; the number of bits output is (18 – agc\_rnd). For example, 0000 is 18 bits.  
 agc\_thresh(7:0) : Threshold for (input \* gain) comparison. This value is compared to the magnitude of the upper eight bits of the agc output.

**Register name: AGC\_CONFIG3****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x12**

BIT15

BIT8

				agc_max_cnt(3:0)			
0	0	0	0	0	0	0	0

				agc_zero_cnt(3:0)			
0	0	0	0	0	0	0	0

agc\_freeze : Freezes the agc when set. This should be asserted when the AGC algorithm is bypassed or held constant.  
 agc\_max\_cnt(3:0) : When the agc\_output (input \* gain) is at full scale for this number of samples, then the gain shift value is changed to agc\_dsat.  
 agc\_clear : Clears the AGC accumulator when set. Assert this when the AGC is in bypass mode.  
 agc\_zero\_cnt(3:0) : when the agc\_output (input \* gain) is zero value for this number of samples, then the gain shift value is changed to agc\_dzro.

**Register name: AGC\_GAINMSB****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x13****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

BIT15

BIT8

agc_gaina(23:16)							
0	0	0	0	0	0	0	0

agc_gainb(23:16)							
0	0	0	0	0	0	0	0

agc\_gaina(23:16) : MSBs of the agc\_gaina word.  
 agc\_gainb(23:16) : MSBs of the agc\_gainb word.

**Register name: AGC\_GAINA****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x14****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

agc_gaina(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT0
agc_gaina(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

## agc\_gaina(15:0)

: This is the lower 16 bits of the total 24 bits of programmable gain. The gain value is always positive with the upper 12 bits being the integer value and the lower 12 bits being the fractional. This gain value is used for all UMTS operations and for A channel data when in CDMA mode. A 24-bit value of 00000000001.000000000000 is unity gain.

**Register name: AGC\_GAINB****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x15****DOUBLE BUFFERED, REQUIRES SYNC FOR LOADING**

agc_gainb(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT0
agc_gainb(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

## agc\_gainb(15:0)

: This is the lower 16 of the total of 24 bit of programmable gain. The gain value is always positive with the upper 12 bits being the integer value and the lower 12 bits being the fractional. This gain value is used for B channel data when in CDMA. A 24-bit value of 00000000001.000000000000 is unity gain.

**Register name: AGC\_AMAX****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x16**

agc_amax(15:8)								BIT8
0	0	0	0	0	0	0	0	BIT0
agc_amax(7:0)								BIT0
0	0	0	0	0	0	0	0	BIT0

## agc\_amax(15:0)

: This is the maximum gaina or gainb can be adjusted up. The value programmed is a positive value that is used to generate the most positive AGC gain adjust. For example, if 512 is programmed, the maximum gain will be the programmed gain (AGC\_GAINA/B) + 512.

**Register name: AGC\_AMIN****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x17**

BIT15

BIT8

agc\_amin(15:8)

0	0	0	0	0	0	0	0
BIT7							BIT0

agc\_amin(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

agc\_amin(15:0) : This is the minimum gaina or gainb can be adjusted down. The value programmed is a positive value that is inverted internally to generate the most negative AGC gain adjust. For example, if 512 is programmed, the minimum gain will be the programmed gain (AGC\_GAINA/B) – 512.

**Register name: PSER\_CONFIG1****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x18**

BIT15

BIT8

pser\_recv\_fsinvl(6:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pser\_recv\_bits(4:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pser\_recv\_fsinvl(6:0) : Receive serial interface frame sync interval in bit clocks.

pser\_recv\_bits(4:0) : Number of output bits per sample-1; for 18 bits, this is set to {10001}.

**Register name: PSER\_CONFIG2****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x19**

BIT15

BIT8

pser\_recv\_clkdiv(3:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pser\_recv\_8pin

pser\_recv\_fsdel(1:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pser\_recv\_clkdiv(3:0) : Receive serial interface clock divider rate-1; 0 is full rate and 15 divides the clock by 16. For example, to run the receive serial interface at 1/4 the AFE8406 clock, set pser\_recv\_clkdiv(3:0) = 0011.

pser\_recv\_8pin : When set, 4 pins are used for I and 4 pins for Q in UMTS mode. When cleared, 2 pins are used for I and 2 pins for Q. This is used in combination with the pser\_recv\_alt bit. When this bit is set, it would be set in 2 adjacent DDC channels; one would also set the pser\_recv\_alt bit in the adjacent DDC. This will cause the I channel to be serialized on 4 pins and the Q channel to be serialized on the adjacent channels 4 pins.

pser\_recv\_alt : When set, this channel's receive serial interface will output the Q data from the adjacent DDC channel.

pser\_recv\_fsdel(1:0) : Delay between the receive frame sync output and the MSB of serial data {3,2,1,0}. This number is in serial output bit times, not rxclk periods.

**Register name: DDCCONFIG1****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x1A**

BIT15

ddcmux_sel_a (3:0)				agc_rnd_disable	gain_mon	ch_rate_sel(1:0)		BIT8
0	0	0	0	0	0	0	0	

BIT7

ddcmux_sel_b(3:0)				remix_only	cic_bypass	double_tap(1:0)		BIT0
0	0	0	0	0	0	0	0	

ddcmux\_sel\_X(3:0) : Controls which samples go to the mixer for I/Q. Since in CDMA mode there are two streams, an A and B stream, two mux select values are used.

Select Value	I data from X input	Q data from X input
0000	RXINA	RXINA
0001	RXINB	RXINB
0010	RXINC	RXINC
0011	RXIND	RXIND
0100	RXINA	RXINB
0101	RXINA	RXINC
0110	RXINA	RXIND
0111	RXINB	RXINA
1000	RXINB	RXINC
1001	RXINB	RXIND
1010	RXINC	RXINA
1011	RXINC	RXINB
1100	RXINC	RXIND
1101	RXIND	RXINA
1110	RXIND	RXINB
1111	RXIND	RXINC

RXINA = internal A-side ADC, RXINB = internal B-side ADC, RXINC = external input C, RXIND = external input D

agc\_rnd\_disable : When set, the agc\_rnd bits have no effect. The whole 29 bits are used in the rounding and the round bit is bit4.

gain\_mon : Combines the gain with the I/Q output signals when asserted.

OUTPUT	Bits(17:10)	Bits(9:4)	Bits(3:2)	Bits(1:0)
I	Gained I value	Gain(18:11)		"00"
Q	Gained Q value	Gain(10:5)	Shift status(1:0)	"00"

ch\_rate\_sel(1:0) : Sets the DDC channel input data rate. The value set here should match the value in the Receive Input Interface rate select bits (rate\_sel). MUST BE SET THE SAME AS REGISTER rate\_sel(1:0).

ch_rate_sel	Input data rate
00	rxclk
01	rxclk/2
10	rxclk/4
11	rxclk/8

*When muxed\_data is set (Factory Use Only) rate\_sel should be set to rxclk "00" and ch\_rate\_sel should be set to rxclk/2 "01".*

remix\_only : Assert this when real only, full rxclk rate input data is used in CDMA mode. The signal on the Q bus selected by the ddcmux\_sel\_X(3:0) bits above is ignored (functions as if the Q data is 0).

cic\_bypass : *Factory Use Only.* If asserted then the data from the rxin\_a(15:0) and rxin\_b(15:0) are fed directly into the cfir input as I and Q respectively. rxin\_a(0) also functions as the "sync\_cfir" signal and should rise at the beginning of input data.

**ONLY DDC0, DDC2 and DDC4 can be the UMTS double tap (64 to 128 tap) PFIR Mode. DDC1, DDC3 and DDC5 PFIRs are used to lengthen the DDC0, DDC2 and DDC4 PFIRs.**

double\_tap(1) : When set, the DDC is in double length PFIR mode which sends the data out of the last PFIR sample ram in this DDC (DDC0, DDC2, DDC4) to the adjacent secondary DDC (DDC1, DDC3, DDC5) PFIR forming a 128-tap delay line. Output data received from the adjacent secondary DDC PFIR summer is added into the Main DDC's PFIR sum to form the final output.

double\_tap(0) : When set, the PFIR input comes from the adjacent(Main) PFIR. When cleared, PFIR input is from the CFIR connected directly to this PFIR. **Only valid in DDC1, DDC3 and DDC5. The ddc\_ena bit in the CONFIG1 register should be cleared for the DDC1, DDC3 and DDC5 when double\_tap(0) is set.**

Note: to put 2 DDCs in to 128 tap mode:

Program DDC0/DDC2/DDC4 double\_tap(1:0) to "10" and ddc\_ena to "1".  
Program DDC1/DDC3/DDC5 double\_tap(1:0) to "01" and ddc\_ena to "0".

**Register name: SYNC\_0**

**Page: 0x0%00, where % = 2\*(DDC channel #)+1**

**Address: 0x1B**

BIT15								BIT8
unused	ssel_cic(2:0)			unused	ssel_pmeter(2:0)			
0	0	0	0	0	0	0	0	
BIT7								
unused	ssel_agc_freeze(2:0)			unused	ssel_serial(2:0)			
0	1	1	0	0	0	0	0	

ssel\_cic(2:0) : Selects the sync source for the DDC CIC filter, thus setting the decimation moment.

ssel\_pmeter(2:0) : Selects the sync source for the channel power meter.

ssel\_agc\_freeze(2:0) : Selects the sync that is used to hold the AGC in freeze mode. With this functionality the user can program the AGC freeze control to look at the state of an input sync, or the one shots. It defaults to being off or not looking at any syncs and not driving the freeze control. This way, upon startup, the chip looks at the MPU register bit for AGC freezing and not the syncs.

ssel\_serial(2:0) : Selects the sync source for the DDC serial interface state machines.

Sync sources are contained in this and many of the following registers. For all sync source selections:

ssel_XXXX(2:0)	Selected sync source for DDC
000	rxsyncA
001	rxsyncB
010	rxsyncC
011	rxsyncD
100	DDC sync counter
101	one shot (register write triggered)
110	always 0
111	always 1

**Register name: SYNC\_1****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x1C**

BIT15									
unused	ssel_tadj_fine(2:0)				unused	ssel_tadj_reg(2:0)			
0	0	0	0	0	0	0	0	0	
BIT7									
unused	ssel_gain(2:0)				unused	ssel_ddc_agc(2:0)			
0	0	0	0	0	0	0	0	0	

ssel\_tadj\_fine(2:0) : Selects the sync source for the fine time adjust zero stuff moment.  
 ssel\_tadj\_reg(2:0) : Selects the sync source for the fine and coarse time adjust register updates.  
 ssel\_gain(2:0) : Selects the sync source for the DDC AGC gain register.  
 ssel\_ddc\_agc(2:0) : Selects the sync source to initialize the AGC, primarily for test purposes.

**Register name: SYNC\_2****Page: 0x0%00, where % = 2\*(DDC channel #)+1****Address: 0x1D**

BIT15									
unused	ssel_nco(2:0)				unused	ssel_dither(2:0)			
0	0	0	0	0	0	0	0	0	
BIT7									
unused	ssel_freq(2:0)				unused	ssel_phase (2:0)			
0	0	0	0	0	0	0	0	0	

ssel\_nco : Selects the sync source for the NCO accumulator reset.  
 ssel\_dither : Selects the sync source for the NCO phase dither generator reset.  
 ssel\_freq : Selects the sync source for the NCO frequency register.  
 ssel\_phase : Selects the sync source for the NCO phase offset register.

**Register name: DDC\_CHK\_SUM****Page: 0x0%20, where % = 2\*(DDC channel #)+1****Address: 0x00****READ ONLY**

BIT15								
0	0	0	0	0	0	0	0	0
BIT7								
0	0	0	0	0	0	0	0	0
ddc_chk_sum								

ddc\_chk\_sum : The DDC self test checksum value

**Register name: PMETER\_RESULT\_A\_LSB****Page: 0x0%20, where % = 2\*(DDC channel #)+1****Address: 0x01**

**READ ONLY**

BIT15

BIT8

pmeter\_result\_a(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pmeter\_result\_a(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pmeter\_result\_a(15:0) : Lower 16 bits of the UMTS mode or CDMA mode A channel power measurement.

**Register name: PMETER\_RESULT\_A\_MID****Page: 0x0%20, where % = 2\*(DDC channel #)+1****Address: 0x02****READ ONLY**

BIT15

BIT8

pmeter\_result\_a(31:24)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pmeter\_result\_a(23:16)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pmeter\_result\_a(31:16) : Mid 16 bits of the UMTS mode or CDMA mode A channel power measurement.

**Register name: PMETER\_RESULT\_A\_MSB****Page: 0x0%20, where % = 2\*(DDC channel #)+1****Address: 0x03****READ ONLY**

BIT15

BIT8

pmeter\_result\_a(47:40)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pmeter\_result\_a(39:32)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pmeter\_result\_a(47:32) : Upper mid 16 bits of the UMTS mode or CDMA mode A channel power measurement.

**Register name: PMETER\_RESULT\_B\_LSB****Page: 0x0%20, where % = 2\*(DDC channel #)+1****Address: 0x04**

**READ ONLY**

BIT15

BIT8

pmeter\_result\_b(15:8)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pmeter\_result\_b(7:0)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pmeter\_result\_b(15:0) : Lower 16 bits of the CDMA mode B channel power measurement.

**Register name: PMETER\_RESULT\_B\_MID****Page: 0x0%20, where % = 2\*(DDC channel #)+1****Address: 0x05****READ ONLY**

BIT15

BIT8

pmeter\_result\_b(31:24)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pmeter\_result\_b(23:16)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pmeter\_result\_b(31:16) : Mid 16 bits of the CDMA mode B channel power measurement.

**Register name: PMETER\_RESULT\_B\_MSB****Page: 0x0%20, where % = 2\*(DDC channel #)+1****Address: 0x06****READ ONLY**

BIT15

BIT8

pmeter\_result\_b(47:40)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pmeter\_result\_b(39:32)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pmeter\_result\_b(47:32) : Upper mid 16 bits of the CDMA mode B channel power measurement.

**Register name: PMETER\_RESULT\_AB\_UMSB****Page: 0x0%20, where % = 2\*(DDC channel #)+1****Address: 0x07****READ ONLY**

BIT15

BIT8

pmeter\_result\_a(54:48)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

BIT7

BIT0

pmeter\_result\_b(54:48)

0	0	0	0	0	0	0	0
---	---	---	---	---	---	---	---

pmeter\_result\_a(54:48) : Most Significant 7 bits of the 55-bit UMTS or CDMA mode A channel power measurement.

pmeter\_result\_b(54:48) : Most Significant 7 bits of the 55-bit CDMA mode B channel power measurement.



## 4 AFE8406 Pins

## 4.1 Analog Section Signals

Signal Name	Ball	Type	Description
inpa	F3	input	ADCA analog positive input
inma	F4	input	ADCA analog negative input
inpб	V4	input	ADCB analog positive input
inmb	V3	input	ADCB analog negative input
clkpa	H1	input	ADCA clock positive input
clkma	J1	input	ADCA clock negative input
clkpb	R1	input	ADCB clock positive input
clkmb	T1	input	ADCB clock negative input
refpa	L3	input	ADCA positive reference input. connect 0.1uF to AVSS.
refma	K3	input	ADCA negative reference input; connect 0.1uF to AVSS.
refpb	P3	input	ADCB positive reference input; connect 0.1uF to AVSS.
refmb	N3	input	ADCB negative reference input; connect 0.1uF to AVSS.
cma	H3	output	ADCA common mode output reference
cmb	T3	output	ADCB common mode output reference
iref	M3	input	Current set; connect 56KΩ to AVSS.
oea	L9	input	<i>connect to AVDD</i> ADCA output enable; AVDD=enable, AVSS=disabled
oeb	N9	input	<i>connect to AVDD</i> ADCB output enable; AVDD=enable, AVSS=disabled
ovra	G6	output	ADCA over range indicator bit
ovrb	N8	output	ADCB over range indicator bit
da(13:0)	N/A	output	ADCA output data; internally connected to rxin_a_15:2
db(13:0)	N/A	output	ADCB output data; internally connected to rxin_b_15:2
clkouta	N/A	output	ADCA output clock; internally connected to adcclka
clkoutb	N/A	output	ADCB output clock; internally connected to adcclkb
fuse_sel	H5	input	<i>connect to AVSS</i> ; fuse trim enable - factory use only
pin_configure	T5	input	<i>connect to AVDD</i> Set mode of the following 3 pins
<b>when pin_configure = AVSS (factory use only, customers should always tie to AVDD)</b>			
sdata	N10	input	serial interface data - factory use only
sclk	M9	input	serial interface clock - factory use only
sen	M10	input	serial interface enable - factory use only
<b>when pin_configure = AVDD (normal operating mode)</b>			
dll_disable	N10	input	<i>connect to AVDD</i> AVDD=disables DLL, AVSS=enables DLL
pwdn	M9	Input	<i>connect to AVSS</i> AVDD=powered down, AVSS=powered up
ext_ref	M10	input	<i>connect to AVSS</i> AVDD=External reference, AVSS=internal reference.

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## 4.2 Digital Receive Section Signals

Signal Name	Ball	Type	Description
rxclk	R22	input	receive digital section clock input
adcclk_a	N/A	input	<i>rxin_a_x</i> input clock; connected to ADCA output clock
adcclk_b	N/A	input	<i>rxin_b_x</i> input clock; connected to ADCB output clock
adcclk_c	AA11	input	<i>rxin_c_x</i> input clock
adcclk_d	AB11	input	<i>rxin_d_x</i> input clock
rxin_a_ovr	G6	input/output	adc overflow/overrange bit for <i>rxin_a</i> ; driven by ADC A
rxin_b_ovr	N8	input/output	adc overflow/overrange bit for <i>rxin_b</i> ; driven by ADC B
rxin_c_ovr	AB6	input	adc overflow/overrange bit for <i>rxin_c</i>
rxin_d_ovr	V12	input	adc overflow/overrange bit for <i>rxin_d</i>
dvga_a_5	D7	output	Digital VGA control output for ADC0 MSB
dvga_a_4	D8	output	Digital VGA control output for ADC0
dvga_a_3	C7	output	Digital VGA control output for ADC0
dvga_a_2	B7	output	Digital VGA control output for ADC0
dvga_a_1	A7	output	Digital VGA control output for ADC0
dvga_a_0	C8	output	Digital VGA control output for ADC0 LSB
dvga_b_5	B8	output	Digital VGA control output for ADC1 MSB
dvga_b_4	A8	output	Digital VGA control output for ADC1
dvga_b_3	D9	output	Digital VGA control output for ADC1
dvga_b_2	D10	output	Digital VGA control output for ADC1
dvga_b_1	C9	output	Digital VGA control output for ADC1
dvga_b_0	B9	output	Digital VGA control output for ADC1 LSB
dvga_c_5	AA15	output	Digital VGA control output for <i>rxin_c</i> MSB, test bus bit 1
dvga_c_4	AB15	output	Digital VGA control output for <i>rxin_c</i> , test bus bit 0
dvga_c_3	V16	output	Digital VGA control output for <i>rxin_c</i> , test bus bit 19
dvga_c_2	W16	output	Digital VGA control output for <i>rxin_c</i> , test bus bit 18
dvga_c_1	Y16	output	Digital VGA control output for <i>rxin_c</i> , test bus CLK
dvga_c_0	AA16	output	Digital VGA control output for <i>rxin_c</i> LSB, test bus SYNC
dvga_d_5	AB16	output	Digital VGA control output for <i>rxin_d</i> MSB, test bus AFLAG
dvga_d_4	V17	output	Digital VGA control output for <i>rxin_d</i>
dvga_d_3	W17	output	Digital VGA control output for <i>rxin_d</i>
dvga_d_2	AA17	output	Digital VGA control output for <i>rxin_d</i>
dvga_d_1	AB17	output	Digital VGA control output for <i>rxin_d</i>
dvga_d_0	V18	output	Digital VGA control output for <i>rxin_d</i> LSB

<i>rxin_a_15</i>	N/A	<i>input</i>	<i>receive input data bus a bit 15 (MSB); connected to ADC A d(13)</i>
<i>rxin_a_14</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_13</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_12</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_11</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_10</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_9</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_8</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_7</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_6</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_5</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_4</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_3</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_2</i>	N/A	<i>input</i>	<i>receive input data bus a; connected to ADC A d(0)</i>
<i>rxin_a_1</i>	N/A	<i>input</i>	<i>receive input data bus a</i>
<i>rxin_a_0</i>	N/A	<i>input</i>	<i>receive input data bus a bit 0 (LSB)</i>
<i>rxin_b_15</i>	N/A	<i>input</i>	<i>receive input data bus b bit 15 (MSB); connected to ADC B d(13)</i>
<i>rxin_b_14</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_13</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_12</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_11</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_10</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_9</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_8</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_7</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_6</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_5</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_4</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_3</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_2</i>	N/A	<i>input</i>	<i>receive input data bus b; connected to ADC B d(0)</i>
<i>rxin_b_1</i>	N/A	<i>input</i>	<i>receive input data bus b</i>
<i>rxin_b_0</i>	N/A	<i>input</i>	<i>receive input data bus b bit 0 (LSB)</i>
<i>rxin_c_15</i>	Y7	<i>input/output</i>	<i>receive input data bus c bit 15 (MSB), test bus bit 17</i>
<i>rxin_c_14</i>	AA7	<i>input/output</i>	<i>receive input data bus c bit 14, test bus bit 16</i>
<i>rxin_c_13</i>	AB7	<i>input/output</i>	<i>receive input data bus c bit 13, test bus bit 15</i>
<i>rxin_c_12</i>	Y8	<i>input/output</i>	<i>receive input data bus c bit 12, test bus bit 14</i>
<i>rxin_c_11</i>	V10	<i>input/output</i>	<i>receive input data bus c bit 11, test bus bit 13</i>
<i>rxin_c_10</i>	AA8	<i>input/output</i>	<i>receive input data bus c bit 10, test bus bit 12</i>
<i>rxin_c_9</i>	AB8	<i>input/output</i>	<i>receive input data bus c bit 9, test bus bit 11</i>
<i>rxin_c_8</i>	W9	<i>input/output</i>	<i>receive input data bus c bit 8, test bus bit 10</i>
<i>rxin_c_7</i>	Y9	<i>input/output</i>	<i>receive input data bus c bit 7, test bus bit 9</i>
<i>rxin_c_6</i>	AA9	<i>input/output</i>	<i>receive input data bus c bit 6, test bus bit 8</i>
<i>rxin_c_5</i>	AB9	<i>input/output</i>	<i>receive input data bus c bit 5, test bus bit 7</i>
<i>rxin_c_4</i>	W10	<i>input/output</i>	<i>receive input data bus c bit 4, test bus bit 6</i>
<i>rxin_c_3</i>	Y10	<i>input/output</i>	<i>receive input data bus c bit 3, test bus bit 5</i>
<i>rxin_c_2</i>	AA10	<i>input/output</i>	<i>receive input data bus c bit 2, test bus bit 4</i>
<i>rxin_c_1</i>	AB10	<i>input/output</i>	<i>receive input data bus c bit 1, test bus bit 3</i>

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rxin_c_0	W11	input/output	receive input data bus c bit 0 (LSB), test bus bit 2
rxin_d_15	W12	input/output	receive input data bus d bit 15 (MSB), test bus bit 35
rxin_d_14	Y12	input/output	receive input data bus d bit 14, test bus bit 34
rxin_d_13	AA12	input/output	receive input data bus d bit 13, test bus bit 33
rxin_d_12	AB12	input/output	receive input data bus d bit 12, test bus bit 32
rxin_d_11	V13	input/output	receive input data bus d bit 11, test bus bit 31
rxin_d_10	W13	input/output	receive input data bus d bit 10, test bus bit 30
rxin_d_9	Y13	input/output	receive input data bus d bit 9, test bus bit 29
rxin_d_8	AA13	input/output	receive input data bus d bit 8, test bus bit 28
rxin_d_7	AB13	input/output	receive input data bus d bit 7, test bus bit 27
rxin_d_6	V14	input/output	receive input data bus d bit 6, test bus bit 26
rxin_d_5	W14	input/output	receive input data bus d bit 5, test bus bit 25
rxin_d_4	AA14	input/output	receive input data bus d bit 4, test bus bit 24
rxin_d_3	AB14	input/output	receive input data bus d bit 3, test bus bit 23
rxin_d_2	V15	input/output	receive input data bus d bit 2, test bus bit 22
rxin_d_1	W15	input/output	receive input data bus d bit 1, test bus bit 21
rxin_d_0	Y15	input/output	receive input data bus d bit 0 (LSB), test bus bit 20
rx_synca	P21	input	receive sync input
rx_syncb	P22	input	receive sync input
rx_syncc	N20	input	receive sync input
rx_syncd	N21	input	receive sync input
rx_sync_out	E22	output	receive general purpose output sync
rxclk_out	E21	output	receive clock output
rx_sync_out_7	A20	output	receive serial interface frame strobe for rxout_7_x, output clock (rxout_clk) for parallel interface.
rx_sync_out_6	C19	output	receive serial interface frame strobe for rxout_6_x, frame strobe (rx_sync_out) for parallel interface.
rx_sync_out_5	C17	output	receive serial interface frame strobe for rxout_5_x
rx_sync_out_4	C16	output	receive serial interface frame strobe for rxout_4_x
rx_sync_out_3	D15	output	receive serial interface frame strobe for rxout_3_x
rx_sync_out_2	B13	output	receive serial interface frame strobe for rxout_2_x
rx_sync_out_1	C12	output	receive serial interface frame strobe for rxout_1_x
rx_sync_out_0	A10	output	receive serial interface frame strobe for rxout_0_x

rxout_7_a	D20	output	DDC 7 serial out data. CDMA A: I data DDC Parallel Interface I(12)	UMTS: I <sub>msb</sub>
rxout_7_b	C21	output	DDC 7 serial out data. CDMA B: I data DDC Parallel Interface I(13)	UMTS: I <sub>msb - 1</sub>
rxout_7_c	B20	output	DDC 7 serial out data. CDMA A: Q data DDC Parallel Interface I(14)	UMTS: Q <sub>msb</sub>
rxout_7_d	C20	output	DDC 7 serial out data. CDMA B: Q data DDC Parallel Interface I(15)	UMTS: Q <sub>msb - 1</sub>
rxout_6_a	A19	output	DDC 6 serial out data. CDMA A: I data DDC Parallel Interface I(8)	UMTS: I <sub>msb</sub>
rxout_6_b	B19	output	DDC 6 serial out data. CDMA B: I data DDC Parallel Interface I(9)	UMTS: I <sub>msb - 1</sub>
rxout_6_c	A18	output	DDC 6 serial out data. CDMA A: Q data DDC Parallel Interface I(10)	UMTS: Q <sub>msb</sub>
rxout_6_d	B18	output	DDC 6 serial out data. CDMA B: Q data DDC Parallel Interface I(11)	UMTS: Q <sub>msb - 1</sub>
rxout_5_a	D18	output	DDC 5 serial out data. CDMA A: I data Parallel Interface I(4)	UMTS: I <sub>msb</sub>
rxout_5_b	B17	output	DDC 5 serial out data. CDMA B: I data Parallel Interface I(5)	UMTS: I <sub>msb - 1</sub>
rxout_5_c	D17	output	DDC 5 serial out data. CDMA A: Q data Parallel Interface I(6)	UMTS: Q <sub>msb</sub>
rxout_5_d	A17	output	DDC 5 serial out data. CDMA B: Q data Parallel Interface I(7)	UMTS: Q <sub>msb - 1</sub>
rxout_4_a	A16	output	DDC 4 serial out data. CDMA A: I data Parallel Interface I(0)	UMTS: I <sub>msb</sub>
rxout_4_b	B16	output	DDC 4 serial out data. CDMA B: I data Parallel Interface I(1)	UMTS: I <sub>msb - 1</sub>
rxout_4_c	D16	output	DDC 4 serial out data. CDMA A: Q data Parallel Interface I(2)	UMTS: Q <sub>msb</sub>
rxout_4_d	A15	output	DDC 4 serial out data. CDMA B: Q data Parallel Interface I(3)	UMTS: Q <sub>msb - 1</sub>
rxout_3_a	B15	output	DDC 3 serial out data. CDMA A: I data Parallel Interface Q(12)	UMTS: I <sub>msb</sub>
rxout_3_b	C15	output	DDC 3 serial out data. CDMA B: I data Parallel Interface Q(13)	UMTS: I <sub>msb - 1</sub>
rxout_3_c	A14	output	DDC 3 serial out data. CDMA A: Q data Parallel Interface Q(14)	UMTS: Q <sub>msb</sub>
rxout_3_d	B14	output	DDC 3 serial out data. CDMA B: Q data Parallel Interface Q(15)	UMTS: Q <sub>msb - 1</sub>
rxout_2_a	D14	output	DDC 2 serial out data. CDMA A: I data Parallel Interface Q(8)	UMTS: I <sub>msb</sub>
rxout_2_b	A13	output	DDC 2 serial out data. CDMA B: I data Parallel Interface Q(9)	UMTS: I <sub>msb - 1</sub>
rxout_2_c	C13	output	DDC 2 serial out data. CDMA A: Q data Parallel Interface Q(10)	UMTS: Q <sub>msb</sub>
rxout_2_d	D13	output	DDC 2 serial out data. CDMA B: Q data Parallel Interface Q(11)	UMTS: Q <sub>msb - 1</sub>

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rxout_1_a	A12	output	DDC 1 serial out data. CDMA A: I data Parallel Interface Q(4)	UMTS: I <sub>msb</sub>
rxout_1_b	B12	output	DDC 1 serial out data. CDMA B: I data Parallel Interface Q(5)	UMTS: I <sub>msb - 1</sub>
rxout_1_c	D12	output	DDC 1 serial out data. CDMA A: Q data Parallel Interface Q(6)	UMTS: Q <sub>msb</sub>
rxout_1_d	A11	output	DDC 1 serial out data. CDMA B: Q data Parallel Interface Q(7)	UMTS: Q <sub>msb - 1</sub>
rxout_0_a	B11	output	DDC 0 serial out data. CDMA A: I data Parallel Interface Q(0)	UMTS: I <sub>msb</sub>
rxout_0_b	C11	output	DDC 0 serial out data. CDMA B: I data Parallel Interface Q(1)	UMTS: I <sub>msb - 1</sub>
rxout_0_c	B10	output	DDC 0 serial out data. CDMA A: Q data Parallel Interface Q(2)	UMTS: Q <sub>msb</sub>
rxout_0_d	A9	output	DDC 0 serial out data. CDMA B: Q data Parallel Interface Q(3)	UMTS: Q <sub>msb - 1</sub>

## 4.3 Microprocessor Signals

Signal Name	Ball	Type	Description
d0	Y22	input/output	MPU register interface data bus bit 0 (LSB)
d1	Y21	input/output	MPU register interface data bus
d2	AB20	input/output	MPU register interface data bus
d3	AA20	input/output	MPU register interface data bus
d4	Y20	input/output	MPU register interface data bus
d5	W20	input/output	MPU register interface data bus
d6	V20	input/output	MPU register interface data bus
d7	AB19	input/output	MPU register interface data bus
d8	AA19	input/output	MPU register interface data bus
d9	Y19	input/output	MPU register interface data bus
d10	W19	input/output	MPU register interface data bus
d11	V19	input/output	MPU register interface data bus
d12	AB18	input/output	MPU register interface data bus
d13	AA18	input/output	MPU register interface data bus
d14	Y18	input/output	MPU register interface data bus
d15	W18	input/output	MPU register interface data bus bit 15 (MSB)
a0	T20	input	MPU register interface address bus bit 0 (LSB)
a1	U22	input	MPU register interface address bus
a2	U21	input	MPU register interface address bus
a3	W22	input	MPU register interface address bus
a4	V21	input	MPU register interface address bus
a5	W21	input	MPU register interface address bus bit 5 (MSB)
rd_n	T22	input	MPU register interface read – active low
wr_n	R20	input	MPU register interface write – active low
ce_n	T21	input	MPU register interface chip enable – active low
reset_n	R21	input	chip reset – active low
interrupt	M21	output	chip interrupt

#### 4.4 JTAG Signals

Signal Name	Ball	Type	Description
tdi	K22	input	JTAG test data in
tms	K21	input	JTAG test mode select
trst_n	J22	input	JTAG test reset (same as trst; the “_n” is for consistency - being active low) <i>Note: the trst_n pin should be asserted low after power up to insure the JTAG logic is properly initialized.</i>
tck	L20	input	JTAG test clock
tdo	L21	output	JTAG test data out

#### 4.5 Factory Test and No Connect Signals

Signal Name	Ball	Type	Note
testmode0	G21	input	Do not connect; internal pull down
testmode1	G22	input	Do not connect; internal pull down
scangen	H21	input	Do not connect; internal pull down
fa002_scan	J20	input	Do not connect; internal pull down
fa002_clk	H22	input	Do not connect; internal pull down
fa002_out	J21	output	Do not connect
zero	H20	input	Do not connect; internal pull down
fuse_out	F20	output	Do not connect
fuse_ena	D21	input	Do not connect; internal pull down
fuse_bias	F21	input	Do not connect; internal pull down

#### 4.6 Power and Ground Signals

Signal Name	Ball	Description
AVDD	H4, J3, L1, L2, M2, N1, N2, R3, T4	Analog Power (3.3V)
DRVDD	H6, H7, J8, K8, L8, P8, R8, T6, T7	Analog I/O Power (3.3V)
FUSE_AVDD	M1	Analog Power (3.3V)
AVSS	A1, A2, A3, A4, A5, B1, B2, B3, B4, B5, C1, C2, C3, C4, C5, D1, D2, D3, D4, D5, E1, E2, E3, E4, E5, F1, F2, F5, F6, F7, F8, F9, G1, G2, G3, G4, G5, G7, G8, G9, H2, J2, J4, J5, J6, K1, K2, K4, K5, K6, L4, L5, L6, L7, M4, M5, M6, M7, N4, N5, N6, N7, P1, P2, P4, P5, P6, R2, R4, R5, R6, T2, U1, U2, U3, U4, U5, U6, U7, U8, U9, V1, V2, V5, V6, V7, V8, W1, W2, W3, W4, W5, Y1, Y2, Y3, Y4, AA1, AA2, AA3, AA4, AB1, AB2, AB3, AB4	Analog Ground
DRVSS	H8, H9, J7, J9, K7, K9, M8, P7, P9, R7, R9, T8, T9	Analog I/O Ground
VDDS	B6, B21, D6, D11, D19, E10, E11, E12, E13, E14, E15, E16, E17, E18, E19, K20, M20, P20, U11, U12, U13, U14, U15, U16, U17, U18, U19, V11, W7, AA6, AA21	Digital I/O Power (3.3V) Also called Vpad
VDDS_VFUSE	D22	Digital I/O Power (3.3V)
DVDD	F22, G10, G19, H10, H19, J10, J19, K10, K19, L10, L19, M19, N19, P10, P19, R10, R19, V22	Digital Core Power (1.5V) Also called Vcore
DVSS	A6, A21, A22, B22, C6, C10, C14, C18, C22, E6, E7, E8, E9, E20, F10, F11, F12, F13, F14, F15, F16, F17, F18, F19, G11, G12, G13, G14, G15, G16, G17, G18, G20, H11, H12, H13, H14, H15, H16, H17, H18, J11, J12, J13, J14, J15, J16, J17, J18, K11, K12, K13, K14, K15, K16, K17, K18, L11, L12, L13, L14, L15, L16, L17, L18, M11, M12, M13, M14, M15, M16, M17, M18, N11, N12, N13, N14, N15, N16, N17, N18, N22, P11, P12, P13, P14, P15, P16, P17, P18, R11, R12, R13, R14, R15, R16, R17, R18, T10, T11, T12, T13, T14, T15, T16, T17, T18, T19, U10, U20, V9, W6, W8, Y5, Y6, Y11, Y14, Y17, AA5, AA22, AB5, AB21, AB22	Digital Ground

#### 4.7 Digital Supply Monitoring

Signal Name	Ball	Description
dvddmon	L22	It is recommended that this pin be brought to a probe point for monitoring and debugging purposes.
dvssmon	M22	It is recommended that this pin be brought to a probe point for monitoring and debugging purposes.

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#### 4.8 JTAG

The JTAG standard for boundary scan testing will be implemented for board testing purposes. Internal scan test will not be supported. Five device pins are dedicated for JTAG support: tdi, tdo, tms, tck, and trst\_n. The JTAG bsd1 configuration file will be available from TI at a later time.

*Note: the trst\_n pin should be asserted LOW after power up to insure the JTAG logic is properly initialized.*

#### 5 Specifications

NOTE: These numbers are engineering estimates prior to first silicon. They will change after we have characterized the parts.

##### 5.1 Absolute Maximum Ratings

**Table 1. Absolute Maximum Ratings**

PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
Analog Chip, Analog Supply Voltage	AVDD	-0.3	3.7	V	
Analog Chip, I/O Ring Supply Voltage	DRVDD	-0.3	3.7	V	
Analog Chip, Ground Difference DRVSS to AVSS		-0.1	0.1	V	
Digital Chip, Pad Ring Supply Voltage	VDDS	-0.3	3.7	V	
Digital Chip, Core Supply Voltage	DVDD	-0.3	1.8	V	
Analog Chip, Analog Input Voltage		-0.15	2.5	V	
Analog Chip, Digital Input Voltage		-0.3	DRVDD+0.3	V	
Digital Chip, Digital Input Voltage		-0.3	VDDS+0.3	V	
Clamp current for an input or output		-20	+20	mA	
Storage Temperature	T <sub>STG</sub>	-65	140	°C	
Junction Temperature	T <sub>J</sub>		105	°C	
Theta Junction to Ambient (0 LFPM)	θ <sub>JA</sub>			°C	
Theta Junction to Ambient (100 LFPM)				°C	
Theta Junction to Ambient (250 LFPM)				°C	
Theta Junction to Ambient (500 LFPM)				°C	
Theta Junction to Case				°C	
Lead Soldering Temperature (10 seconds)			300	°C	
ESD Classification	Class 2				
Moisture Sensitivity	Class 2				

CAUTION: Exceeding the absolute maximum ratings (min or max) may cause permanent damage to the part. These are stress only ratings and are not intended for operation.

## 5.2 Recommended Operating Conditions

**Table 2. Recommended Operating Conditions**

PARAMETER	SYMBOL	MIN	NOM	MAX	UNITS	NOTES
Analog Chip, Analog Supply Voltage	AVDD	3.0	3.3	3.6	V	
Analog Chip, I/O Ring Supply Voltage	DRVDD	3.0	3.3	3.6	V	
Analog Chip, Differential Input Range			2.3		V	
Analog Chip, Input Common Mode	VCM	1.5		1.6	V	
Analog Chip, Differential Clock Inputs			3		V <sub>pp</sub>	
Analog Chip, Clock Input Duty Cycle			50		%	
Digital Chip, I/O Ring Supply Voltage	VDDS	3		3.6	V	
Digital Chip, Core Supply Voltage	DVDD	1.425		1.575	V	
Digital Chip, Supply Voltage Difference, VDDS – DVDD				2.0	V	
Temperature Ambient, no air flow	T <sub>A</sub>	-40		+85	°C	1
Junction Temperature	T <sub>J</sub>			105	°C	2

1. Chips specifications in Tables 6.4 and 6.5 are production tested to 100°C case temperature. QA tests are performed at 85°C.

2. Thermal management will be required for full rate operation. See table below and Section 5.4. The circuit is designed for junction temperatures up to 125°C. Sustained operation at elevated temperatures will reduce long-term reliability. Lifetime calculations based on maximum junction temperature of 105°C. Thermal management mechanisms such as air flow, heat sinks or lower ambient temperature may need to be employed to maintain a maximum junction temperature of 105°C.

## 5.3 Thermal Characteristics

THERMAL CONDUCTIVITY	SYMBOL	TYP	UNITS
Theta Junction to Ambient (0 LFPM)	$\theta_{JA}$	14	°C/W
Theta Junction to Ambient (100 LFPM)		13	°C/W
Theta Junction to Ambient (250 LFPM)		12.2	°C/W
Theta Junction to Ambient (500 LFPM)		11.6	°C/W
Theta Junction to Case	$\theta_{JC}$	2.8	°C/W

Note: Air flow will reduce  $\theta_{JA}$  and is highly recommended.

## 5.4 Power Consumption

The maximum power consumption is largely a function of the operating mode of the chip. The Dual ADC chip power dissipation is fairly constant over clock rate due to the constant biasing in the analog circuits. The following equation estimates the typical power supply current for the digital chip. The AC Characteristics table provides maximum current in a maximum configuration used in production test.

$IVDSS = \text{proportional to filter lengths, supply, frequency, and number of channels active; separate equations for CDMA and UMTS modes to be included after characterization.}$

Current consumption on the pad supply is primarily due to the external loads and follows  $C*V*F$ . Internal loads are estimated at 2pF per pin. Data outputs have a transition density of going from a zero to a one once per four clocks, while clock outputs transition every cycle. The rx\_sync\_out\_X frame strobes consume negligible power due to the low transition frequency. In general,

$$IVDSS = \sum \text{DataPad}/4*C*F*V + \sum \text{ClockPad}*C*F*V$$

### 5.5 Analog Electrical Characteristics

Typ, min, and max values at TA = +25°C, full temperature range is TMIN = -40°C to TMAX = +85°C, sampling rate = 80MSPS, 50% clock duty cycle, AVDD = DRVDD = 3.3V, DLL OFF, -1dBFS differential input, internal reference, and 3VPP differential clock, unless otherwise noted.

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Resolution		14 tested			Bits
<b>Analog Inputs</b>					
Differential input range		2.3			Vpp
Differential input impedance					k?
Differential input capacitance					
Total analog input common-mode current	2mA per input, 4mA total	4			mA
Analog input bandwidth	Source impedance = 50?	750			MHz
<b>Conversion Characteristics</b>					
ADC clock rate, fadc (fclkpa=fclkma=fclkpb=fclkmb=fadc)	f <sub>rxclk</sub> = 1xf <sub>adc</sub> ch_rate_sel = rate_sel = 00			85	MSPS
	f <sub>rxclk</sub> = 2xf <sub>adc</sub> ch_rate_sel = rate_sel = 01			80	
	f <sub>rxclk</sub> = 4xf <sub>adc</sub> ch_rate_sel = rate_sel = 10			40	
	f <sub>rxclk</sub> = 8xf <sub>adc</sub> ch_rate_sel = rate_sel = 11			20	
Data Latency – ADC input to FIFO input		16.5			Clock Cycles
<b>Internal Reference Voltages</b>					
Lower Reference Voltages, REFMA & REFMB		0.97			V
Upper Reference Voltages, REFPA & REFPB		2.11			V
Reference Error					%
Common Mode Voltage Outputs, CMA & CMB		1.55 +/- 0.05			V
<b>Dynamic DC Characteristics and Accuracy</b>					
No missing codes		tested			
Differential Linearity Error, DNL	Fin = 10MHz				LSBs
Integral Linearity Error, INL	Fin = 10MHz				LSBs
Offset Error					mV
Offset Temperature Coefficient					%/°C
Gain Error					%FS
Gain Temperature Coefficient					Δ%/°C
<b>Dynamic AC Characteristics</b>					
Signal to Noise Ratio, SNR	Fin = 10MHz, 25 °C	TBD			dBFS
	Fin = 10MHz, -40 to 85 °C	TBD			dBFS
	Fin = 30MHz		TBD		dBFS
	Fin = 55MHz		73.5		dBFS
	Fin = 70MHz, 25 °C	TBD			dBFS
	Fin = 70MHz, -40 to 85 °C	TBD			dBFS
	Fin = 110MHz		TBD		dBFS
	Fin = 150MHz		TBD		dBFS
	Fin = 225MHz		TBD		dBFS
RMS Output Noise	INPA & INMA tied to CMA INPB & INMB tied to CMB	1.1			LSBs

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.

Spurious free dynamic range, SFDR	Fin = 10MHz, 25 °C	TBD			dBc
	Fin = 10MHz, -40 to 85 °C	TBD			dBc
	Fin = 30MHz		TBD		dBc
	Fin = 55MHz		84		dBc
	Fin = 70MHz, 25 °C	TBD			dBc
	Fin = 70MHz, -40 to 85 °C	TBD			dBc
	Fin = 110MHz		TBD		dBc
	Fin = 150MHz		TBD		dBc
	Fin = 225MHz		TBD		dBc

**Analog Electrical Characteristics (Continued)**

Typ, min, and max values at TA = +25°C, full temperature range is TMIN = -40°C to TMAX = +85°C, sampling rate = 65MSPS, 50% clock duty cycle, AVDD = DRVDD = 3.3V, DLL OFF, -1dBFS differential input, internal reference, and 3VPP differential clock, unless otherwise noted.

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Second Harmonic, HD2	Fin = 10MHz, 25 °C	TBD			dBc
	Fin = 10MHz, -40 to 85 °C	TBD			dBc
	Fin = 30MHz		TBD		dBc
	Fin = 55MHz		TBD		dBc
	Fin = 70MHz, 25 °C	TBD			dBc
	Fin = 70MHz, -40 to 85 °C	TBD			dBc
	Fin = 110MHz		TBD		dBc
	Fin = 150MHz		TBD		dBc
	Fin = 225MHz		TBD		dBc
Third Harmonic, HD3	Fin = 10MHz, 25 °C	TBD			dBc
	Fin = 10MHz, -40 to 85 °C	TBD			dBc
	Fin = 30MHz		TBD		dBc
	Fin = 55MHz		TBD		dBc
	Fin = 70MHz, 25 °C	TBD			dBc
	Fin = 70MHz, -40 to 85 °C	TBD			dBc
	Fin = 110MHz		TBD		dBc
	Fin = 150MHz		TBD		dBc
	Fin = 225MHz		TBD		dBc
Worst harmonic/spur other than HD2 or HD3	Fin = 10MHz, 25 °C		TBD		dBc
	Fin = 70MHz, 25 °C		TBD		dBc
Signal to Noise plus Distortion	Fin = 10MHz, 25 °C		TBD		dBc
	Fin = 10MHz, -40 to 85 °C		TBD		dBc
	Fin = 30MHz		TBD		dBc
	Fin = 55MHz		TBD		dBc
	Fin = 70MHz, 25 °C		TBD		dBc
	Fin = 70MHz, -40 to 85 °C		TBD		dBc
	Fin = 110MHz		TBD		dBc
	Fin = 150MHz		TBD		dBc
	Fin = 225MHz		TBD		dBc
Total Harmonic Distortion, THD	Fin = 10MHz, 25 °C		TBD		dBc
	Fin = 10MHz, -40 to 85 °C		TBD		dBc
	Fin = 30MHz		TBD		dBc
	Fin = 55MHz		TBD		dBc
	Fin = 70MHz, 25 °C		TBD		dBc
	Fin = 70MHz, -40 to 85 °C		TBD		dBc
	Fin = 110MHz		TBD		dBc
	Fin = 150MHz		TBD		dBc
	Fin = 225MHz		TBD		dBc
Channel to channel crosstalk	Fin = 225MHz		90		dBc

## 5.6 Digital Chip DC Characteristics

Table 3. DC Operating Conditions (-40 to 85°C case unless noted)

PARAMETER	SYMBOL	VDDS=3 to 3.6V		UNITS	NOTES
		MIN	MAX		
Voltage input low	V <sub>IL</sub>		0.8	V	1
Voltage input high	V <sub>IH</sub>	2.0		V	1
Voltage output low (I <sub>OL</sub> = 2mA)	V <sub>OL</sub>		0.5	V	1
Voltage output high (I <sub>OH</sub> = -2mA)	V <sub>OH</sub>	2.4	VDDS	V	1
Pullup current (V <sub>IN</sub> = 0V) (tdi, tms, trst_n, ce_n, wr_n, rd_n, reset_n) (nominal 20uA)	I <sub>PU</sub>	5	35	uA	1
Pulldown current (V <sub>IN</sub> = VDDS) (all other inputs and bidirs) (nominal 20uA)	I <sub>PD</sub>	5	35	uA	1
Leakage current (V <sub>IN</sub> = 0V or VDDS) Outputs in tristate condition	I <sub>IN</sub>		20	uA	1
Quiescent supply current, IDVDD or IVDDS (Vin = 0 for pads with pulldowns, Vin=VDDS for inputs with pullups)	I <sub>CCQ</sub>		8	mA	1
Capacitance for inputs	C <sub>IN</sub>	Typical 5		pF	2
Capacitance for bidirectionals	C <sub>BI</sub>	Typical 5		pF	2

## Notes:

General: Voltages are measured at low speed. Output voltages are measured with the indicated current load.

General: Currents are measured at nominal voltages, high temperature (TBD°C for production test, 85°C for QA).

1. Each part is tested at TBD°C case temperature for the given specification. Lots are sample tested at -40°C.

2. Controlled by design and process and not directly tested.

## 5.7 Digital Chip AC Timing Characteristics

**Table 4. AC Characteristics  
(-40 TO +85°C Case, Supplies across recommended range unless noted)**

PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
Clock Frequency ( <b>adcclk_c/d, rxclk</b> )	$F_{CK}$		160	MHz	1
Clock low period (Below $V_{IL}$ ) ( <b>adcclk_c/d, rxclk</b> )	$t_{CKL}$	2		ns	1
Clock high period (Above $V_{IH}$ ) ( <b>adcclk_c/d, rxclk</b> )	$t_{CKH}$	2		ns	1
Clock rise and fall times ( $V_{IL}$ to $V_{IH}$ ) ( <b>adcclk_c/d, rxclk</b> )	$t_{RF}$		2	ns	3
Input setup ( <b>rxsync_a/b/c/d</b> ) before <b>rxclk</b> rises	$t_{SU}$	2		ns	1
Input setup ( <b>rxin_c/d [0-15]</b> ) before <b>rxclk</b> rises (adc fifo blocks bypassed)	$t_{SU}$	2		ns	1
Input setup ( <b>rxin_c/d [0-15]</b> ) before <b>adcclk_c/d</b> rises (adc fifo blocks enabled)	$t_{SU}$	2		ns	1
Input hold ( <b>rxsync_a/b/c/d</b> ) after <b>rxclk</b> rises	$t_{HD}$	1		ns	1
Input hold ( <b>rxin_c/d [0-15]</b> ) after <b>rxclk</b> rises (adc fifo blocks bypassed)	$t_{HD}$	2		ns	1
Input hold ( <b>rxin_c/d [0-15]</b> ) after <b>adcclk_c/d</b> rises (adc fifo blocks enabled)	$t_{HD}$	1		ns	1
Data output delay ( <b>rx_sync_out [0-7], rxout [0-7]_a/b/c/d, rxclk_out, rx_sync_out, dvga [a-d] [5-0]</b> ) after <b>rxclk</b> rises.	$t_{DLY}$		6.5	ns	1
Data output hold ( <b>rx_sync_out [0-7], rxout [0-7]_a/b/c/d, rxclk_out, rx_sync_out, dvga [a-d] [5-0]</b> ) after <b>rxclk</b> rises.	$t_{OHD}$	0.5		ns	1
JTAG Clock Frequency ( <b>tck</b> )	$F_{JCK}$		40	MHz	1
JTAG Clock low period (Below $V_{IL}$ ) ( <b>tck</b> )	$t_{JCKL}$	10		ns	1
JTAG Clock high period (Above $V_{IH}$ ) ( <b>tck</b> )	$t_{JCKH}$	10		ns	1
JTAG Input ( <b>tdi</b> or <b>tms</b> ) setup before <b>tck</b> goes high	$t_{JSU}$	1		ns	1
JTAG Input ( <b>tdi</b> or <b>tms</b> ) hold time after <b>tck</b> goes high	$t_{JHD}$	10		ns	1
JTAG output ( <b>tdo</b> ) delay from falling edge of <b>tck</b> .	$t_{JDLY}$		10	ns	1
Control setup during reads or writes	$t_{CSU}$	6		ns	1
3 pin mode: <b>a[5:0]</b> valid before <b>rd_n</b> , <b>wr_n</b> or <b>ce_n</b> falling edge					
2 pin mode: <b>a[5:0]</b> and <b>wr_n</b> valid before <b>ce_n</b> falling edge					
Control setup during writes	$t_{EWCSU}$	10		ns	1
3 pin mode: <b>d[15:0]</b> valid before <b>wr_n</b> and <b>ce_n</b> rising edge					
2 pin mode: <b>d[15:0]</b> valid before <b>ce_n</b> rising edge					
Control hold during writes.	$t_{CHD}$	6		ns	1
3 pin mode: <b>a[5:0]</b> and <b>d[15:0]</b> valid after <b>wr_n</b> and <b>ce_n</b> rise					
2 pin mode: <b>a[5:0]</b> , <b>d[15:0]</b> and <b>wr_n</b> valid after <b>ce_n</b> rise					
Control strobe ( <b>ce_n</b> and <b>wr_n</b> low) pulse width during write.	$t_{CSPW}$	15		ns	1
Control output delay <b>ce_n</b> and <b>rd_n</b> low and <b>a[5:0]</b> stable to <b>d[15:0]</b> during read.	$t_{CDLY}$		25	ns	1
Control recovery time between reads or writes.	$t_{REC}$		6	ns	1
Control end of read to Hi-Z.	$t_{HIZ}$		10	ns	1
<b>rd_n</b> and <b>ce_n</b> rise to <b>d[15:0]</b> tristate					
Control read <b>d[15:0]</b> output hold time	$t_{COH}$	3		ns	1
Core dynamic supply current ,nominal voltages, 160 MHz, (specific conditions, typical app with chip busy within capability of the tester, high temperature.)	$I_{CDYN}$	TBD	TBD	mA	1

Notes:

General: Timing is measured from the respective clock at VDDS/2 to input or output at VDDS/2. Output loading is a 50 Ohm transmission line whose delay is calibrated out.

1. Each part is tested at TBD°C case temperature for the given specification. Lots are sample tested at -40°C.

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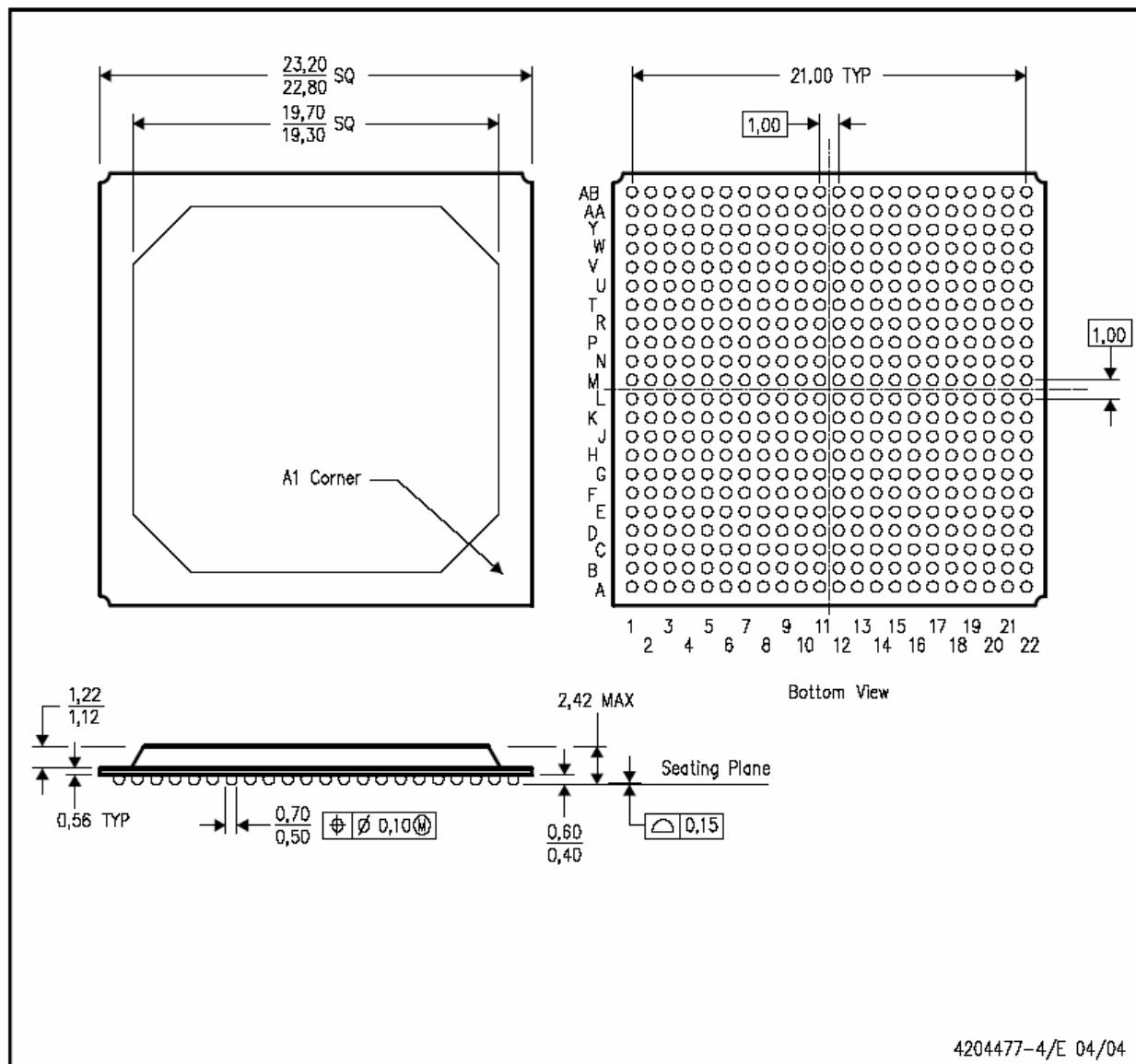
- 2. Controlled by design and process and not directly tested. Verified on initial part evaluation.
- 3. Recommended practice.
- 4. reset\_n and interrupt have no timing specifications since they are asynchronous signals

## 6 Package/Ordering Information

PRODUCT	PACKAGE-LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	PACKAGE MARKING	ORDERING NUMBER	TRANSPORT MEDIA, QUANTITY
AFE8406	Plastic BGA - 484	GDQ	-40°C to +85°C	TBD	TBD	Tray, TBD

## GDQ (S-PBGA-N484)

## PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.  
 B. This drawing is subject to change without notice.  
 C. Falls within JEDEC MO-151

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